

## General Description

The epc660 is a fully integrated 3D-TOF imager with a resolution of 320 x 240 pixels (QVGA). It is a highly integrated system-on-chip camera system. Apart from the actual CCD pixel field, it includes the complete control logic to operate the device. Data communication is done through a high-speed digital 12-bit parallel video interface.

Even for mobile devices, only a few additional components are needed to integrate 3D camera capability. Depending on the system design, a resolution in the millimeter range for measurements up to 100 meters is feasible. 65 full frame TOF images are delivered in maximal configuration. By using the advanced operation modes, this can be boosted up to more than 1000 TOF images per second! The high degree of integration lays base for straight-forward camera system design with minimal part count. The extremely high sensitivity of the optical front end allows for a reduced illumination subsystem and reduces the power consumption of the overall system significantly.

An evaluation kit with hard- and software examples and a comprehensive manual helps the system designer to speed up system integration.

## Applications

- People detection and counting
- Mobile postal parcel size measurement
- Machine safety
- Helicopter near terrain flight assistance
- Car collision avoidance systems
- Pedestrian detection and breaking systems
- Man-Machine interface
- Gesture control
- Body size measurement
- General volumetric mapping

## Block Diagram

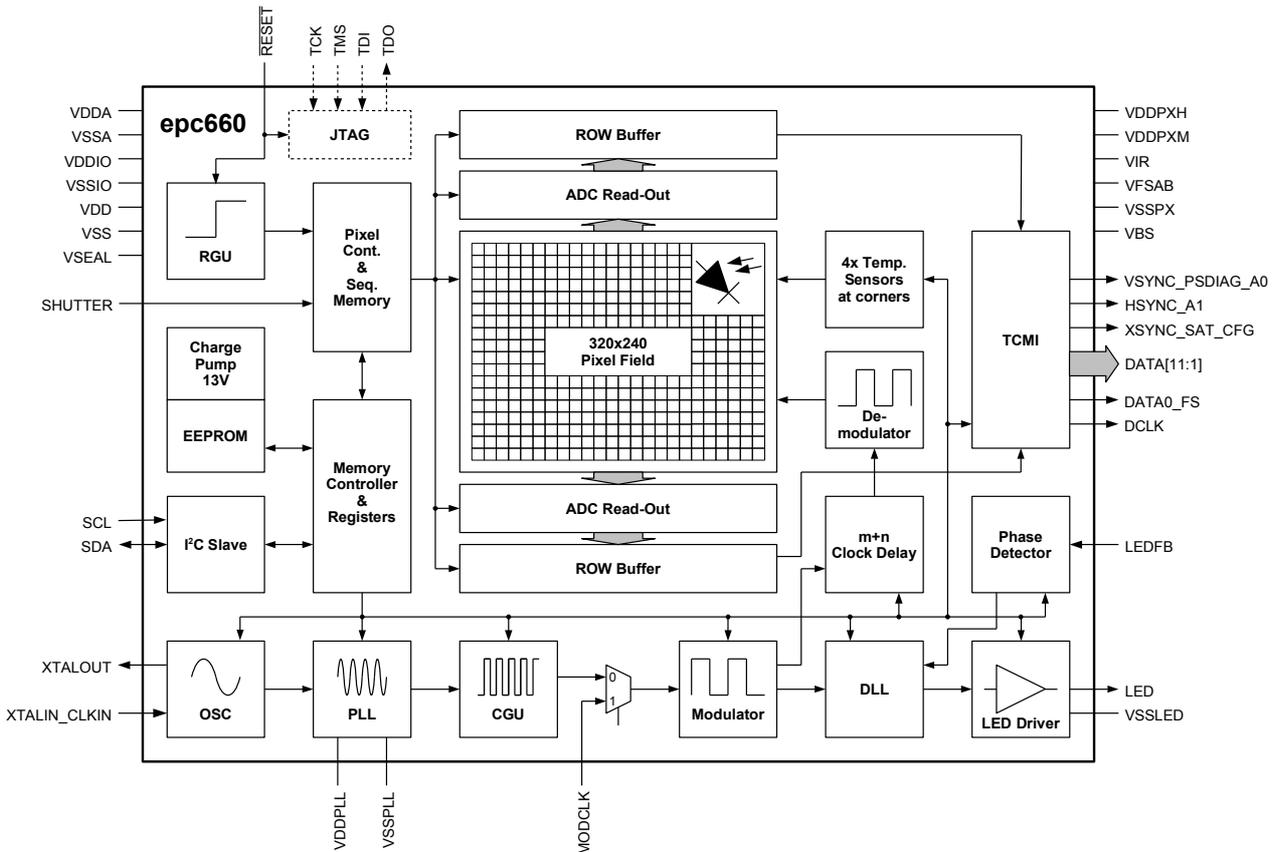


Figure 1: Functional Block Diagram

## Main Features

### ■ General

- 3D TOF imager in full monolithic design
- 320 x 240 pixel-field, backside illuminated
- 65.5fps full 3D TOF frame rate, single frame rate up to 262fps
- Region of interest setting allows up to several kfps
- Distance range up to 240 meters depending on system design
- 4 integrated temperature sensors for drift compensation

### ■ Measurement performance

- Absolute accuracy in the sub-centimeter range with appropriate setup and calibration

### ■ Integrated LED (or laser diode) driver

- LED feedback for drift compensation
- Laser diode (LD) illumination possible
- Single LED output pad, up to 350mA drive

### ■ Parallel digital data interface TDMI

- 80MS/s max. data rate, 2.5/3.3V compatible
- 12-bit parallel DATA output + XSYNC/SAT flag
- VSYNC, HSYNC ('ITU-R656 like' HW synchronization) and DCLK outputs

### ■ I<sup>2</sup>C control interface (slave)

- 400kHz (FM) / 1MHz (FM+)

### ■ Integrated EEPROM 128 x 8-bit

- Calibration data and user programmable parameters
- Unique chip ID

### ■ System / Modulation clock

- System clock 4MHz, internal by using crystal/resonator or using external input
- External LED/LD modulation input MODCLK (optional) up to 80MHz

### ■ Power supply

- Supply voltages +10V, +5V, +2.5/3.3V, +1.8V, -10V
- Power consumption approx. 0.75W (average)

### ■ Packaging

- 9.7x8.7mm cost optimized 68pin CSP (chip scale package),
- Backside illuminated flip-chip SMD mounting

### ■ Other data

- -40 ... +85°C operating range
- ROHS compatible

## Measurement Modes

### ■ LED/LD modulation modes

- Sinusoidal modulation for single camera applications
- PN modulation with programmable sequence lengths for multi-camera applications
- Selectable modulation frequencies 0.625 ... 20MHz resulting in unambiguity distance of 7.5m ... 240m

### ■ Distance measurement modes

- 65.5 fps 3D TOF with 4x DCS frames, full pixel-field
- 131 fps 3D TOF with 2x DCS frames, full pixel field
- 262 fps 3D TOF with rolling read-out 4x DCS frames, full pixel-field
- Ultra fast measurement by reduction of the image field (ROI)
- SHUTTER release input for precise start/stop and single/continuous measurement control

### ■ Non distance measurement modes

- Ambient-light measurement (Black & white image without illumination)
- Black & white image with active illumination

## Readout Modes

### ■ ROI (Region of Interest)

- Rectangular sub-pixel-field read-out
- Increased frame rate

### ■ Binning and resolution reduction

- Binning of two adjacent pixels
- Resolution reduction by  $n^{\text{th}}$  row or column, restricted to 2<sup>nd</sup>, 4<sup>th</sup> or 8<sup>th</sup> row or column (can be set independently) to read-out
- Increased frame rate for reduced number of rows

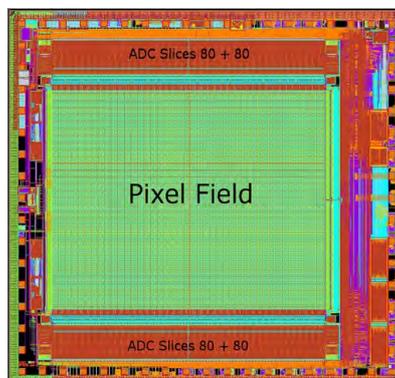


Figure 2: Picture of the epc660

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# 1. Electrical, optical and timing characteristics

## 1.1. Operating conditions and electrical characteristics

Typ. operational ratings,  $T_A = +25^\circ\text{C}$ , unless otherwise stated

Parameter	Description	Conditions/Comments	$V_{sc}$	Min.	Typ.	Max.	Units
$V_{DD}, V_{DDPLL}$	Digital supply voltage	Ripple <sup>1</sup> < $\pm 20$ mV	$V_{DD}$	1.71	1.80	1.98	V
$V_{DDIO}$	IO supply voltage <sup>3</sup>	Ripple <sup>1</sup> < $\pm 50$ mV	$V_{DDIO}$	2.25	2.5/3.3	3.63	V
$V_{DDA}, V_{DDPXM}, V_{IR}$	Analog supply voltage <sup>2</sup>	Ripple <sup>1</sup> < $\pm 20$ mV	$V_{DDA}$	4.5	5.0	5.5	V
$V_{DDPXH}$	Pixel analog 2 supply voltage <sup>2</sup>	Ripple <sup>1</sup> < $\pm 20$ mV	$V_{DDPXH}$	9.5	10	10.5	V
$V_{BS}$	Bias supply voltage	Ripple <sup>1</sup> < $\pm 50$ mV	$V_{BS}$	-10.5	-10.0	-9.75	V
$I_{VDD}$	Digital supply current	@nominal voltage			18		mA
$I_{VDDPLL}$	PLL supply current	@nominal voltage			4		mA
$I_{VDDIO}$	IO supply current <sup>4</sup>	DCLK = 40MHz			8		mA
$I_{VDDA}$	Analog supply current	@nominal voltage			125	350	mA
$I_{VDDPXM}$	Pixel analog 1 supply current	@nominal voltage			1		mA
$I_{VIR}$	Isolation supply current	@nominal voltage			1		mA
$I_{VDDPXH}$	Pixel analog 2 supply current	@nominal voltage			13		mA
$I_{VBS}$	Bias supply current <sup>8</sup>	Depending on the amount of light on the pixel field			3.8 <sup>8</sup>		mA
$V_{DDLED}$	LED and LEDFB voltage range		$V_{DDLED}$			$V_{DDA}$	V
$V_{LED\_OFF}$	Off-voltage at output pin LED					$V_{DDLED}$	V
$V_{LED\_ON}$	On-voltage at output pin LED (forward voltage)	@ $I_{LED} = 200$ mA			200		mV
$I_{LED}$	LED output sink current; on state	modulated peak current continuous DC current				350 175	mA mA
$I_{LED\_LEAK}$	LED output leakage current; off state	$V_{LED}$ max.				10	$\mu\text{A}$
$V_{LEDFB}$	LEDFB input voltage range		$V_{DDLED}$	0		8.5	V
$V_{LEDFB\_P2P}$	LEDFB input voltage peak to peak			0.5		1.8	V
$V_{IH}$	Digital high level input voltage <sup>5</sup>			$0.7 \times V_{DDIO}$			V
$V_{IL}$	Digital low level input voltage <sup>5</sup>					$0.3 \times V_{DDIO}$	V
$V_{OH}$	Digital high level output voltage <sup>5,6</sup>			$0.8 \times V_{DDIO}$			V
$V_{OL}$	Digital low level output voltage <sup>5,6</sup>					$0.2 \times V_{DDIO}$	V
$I_{IH}$	Digital high level input current <sup>7</sup>	$V_{IH}$ max.				$10^7$	$\mu\text{A}$
$I_{IL}$	Digital low level input current <sup>7</sup>	$V_{IL}$ min.		$-10^7$			$\mu\text{A}$
$I_{OH}$	Digital output source current <sup>7</sup>	$V_{OH}$ max.				50	mA
$I_{OL}$	Digital output sink current <sup>3</sup>	$V_{OL}$ min.		-50			mA
$C_{IO}$	IO load capacitance <sup>5</sup>					30	pF
$f_{IO}$	IO switching frequency <sup>5</sup>				40	80	MHz
$P_{PK}$	Power dissipation (average)	See Table 20			0.75		W
$R_{Th}$	Thermal resistance	on PCB with underfill				40	$^\circ\text{K/W}$
$T_A$	Operating temperature			-40		85	$^\circ\text{C}$

Table 1: Operating conditions and electrical characteristics

### Notes:

- Min. and Max. voltage values include noise and ripple voltages.
- Analog voltage supplies have direct influence on measurement performance. They must be properly decoupled for low noise and ripple.
- IO voltage supply must be fixed with respect to external processor's IO supply voltage levels used in the application. It can be set to any value within min and max. operating voltage.
- When device is operated at max  $f_{DCS}$  frame rate, DCLK at 40MHz, driving loads 15pF each.
- Except I<sup>2</sup>C pins SCL and SDA. I<sup>2</sup>C pins SCL SDA are according to I<sup>2</sup>C standards.
- $V_{OHIO}$  and  $I_{OHIO}$  values are measured at max  $C_{IO}$  and max  $f_{IO}$ .
- Value is without termination resistors
- A bright illuminated white target right in front of the chip with lens leads to an  $I_{VBS}$  of approx. 3.8 mA. At room temperature,  $I_{VBS}$  is approx. 3.6 mA without any illumination.  $I_{VBS}$  with strong illumination (approx. 55 mW/cm<sup>2</sup>, no lens) typ. 17 mA.

## 1.2. Absolute maximum ratings

Parameter	Conditions
Supply voltage $V_{DD}$ , $V_{DDPLL}$	-0.5V ... +2.0V
Supply voltage $V_{DDIO}$ , $V_{DDA}$ , $V_{DDPXM}$ , $V_{IR}$ , $V_{DDLED}$	-0.5V ... +5.5V
Supply voltage $V_{DDPXH}$	-0.5V ... +13.5V
Supply voltage $V_{BS}$	-12.0 ... +0.5V
Voltage to any pin in the same $V_{SC}$ supply class. For Supply Classes refer to Table 1: Operating conditions and electrical characteristics. For Supply Classes vs. pin correspondence refer Table 8: Pin list.	$V_{SC\ min} - 0.3V \dots V_{SC\ max} + 0.3V$
ESD rating Note: This is a highly sensitive CMOS mixed signal device. Handling and assembly of this device should only be done at ESD protected workstations.	JEDEC HBM class 1C (1kV to < 2kV)
Storage temperature range ( $T_s$ )	-40°C to +85°C
Relative humidity	0 ... 95%, non-condensing

Table 2: Absolute maximum ratings

## 1.3. Temperature sensor characteristics

Typ. operational ratings, unless otherwise stated

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
$T_{TEMP}$	Measurement range		-40		+85	°C
$P_{TEMP}$	Sensor resolution			14		bit
k	Temperature sensor gain			0.067		°K/LSB

Table 3: Temperature sensor characteristics

## 1.4. Timing parameters

Typ. operational ratings,  $T_A = +25^\circ\text{C}$ , unless otherwise stated

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
$t_{STARTUP}$	Start-up time	after applying external supplies		340	1'000	µs
$t_{RESET}$	RESET		100			ns
$t_{PLLStrap\_scan}$			4x osc_clk			
$t_{PLL}$	PLL lock time				30	µs
$t_{EEPROM\_to\_CFG}$	Load CFG registers	Copy EEPROM to CFG registers		340		µs
$f_{XTAL}$	Clock frequency	of the crystal oscillator (or ceramic resonator)	---	4	---	MHz
$df_{XTAL}$	Clock frequency deviation	any deviation is added as a linear distance error			±100	ppm
$f_{JITTER}$	Clock frequency phase jitter	peak-to-peak, cycle to cycle			50	ps
$f_{LED}$	LED modulation frequency		0.625		40	MHz
$f_{MODCLK}$	Ext. modulation clock	Refer to chapter 7.9.			80	MHz
$t_{LED\_rise/fall}$	Required rise/fall time of the illumination LED/LD				12	ns
$f_{DCLK}$	TCMI pixel rate	12 bit pixel data + saturation flag		40	80	MPixel/s
$f_{TCMI\_data}$	TCMI data rate			520	1'040	Mbit/s
$f_{SCL}$	I <sup>2</sup> C data rate				1	Mbit/s

Table 4: Timing parameters

### 1.5. Optical characteristics

Typ. operational ratings,  $T_A = +25^\circ\text{C}$ , unless otherwise stated

Parameter	Description	Conditions/Comments	Min.	Typ.	Max.	Units
$A_{\text{PIXEL}}$	Photosensitive area	1 pixel		20 x 20		$\mu\text{m}$
$A_{\text{SENSOR}}$	Photosensitive area	320 x 240 pixel		6.4 x 4.8		mm
$H_v$	Optical sensitivity			57'508		$\frac{\text{LSB}}{\text{Lux/sec}}$
$A_{\text{TOF}}$	TOF amplitude	dynamic range for distance measurement	25		1'200	LSB
$A_{\text{BW}}$	Grayscale amplitude	dynamic range for grayscale measurement	0		2'047	LSB
$t_{\text{INT}}$	Integration time	see Table 28	0.10		52'600	$\mu\text{s}$
$\Delta D_{\text{DRIFT}}$	Distance drift	without DLL with DLL and fully optimized system design		tbd tbd		cm/K cm/K

Table 5: Optical characteristics

### 1.6. TOF and grayscale sensitivity

Typ. operational ratings,  $T_A = +25^\circ\text{C}$ , modulation frequency 20MHz, integration time 103 $\mu\text{s}$ , unless otherwise stated

Optical band	640nm	850nm	940nm
Typ. TOF sensitivity $S_{\text{TOF}}$	203.5 $\frac{\text{nW/cm}^2}{\text{LSB}}$	155.0 $\frac{\text{nW/cm}^2}{\text{LSB}}$	203.5 $\frac{\text{nW/cm}^2}{\text{LSB}}$
Typ. Grayscale sensitivity		61.5 $\frac{\text{nW/cm}^2}{\text{LSB}}$	

Table 6: TOF and grayscale sensitivity

### 1.7. Ambient-light suppression

Typ. operational ratings,  $T_A = +25^\circ\text{C}$ , modulation frequency 20MHz, integration time 103 $\mu\text{s}$ , unless otherwise stated

Optical band	640nm, $\pm 27.5\text{nm}$	850nm, $\pm 32.5\text{nm}$	940nm, $\pm 30\text{nm}$
min. suppression $E_{\text{Sup}}$	26.5 $\text{mW/cm}^2$	20.0 $\text{mW/cm}^2$	26.5 $\text{mW/cm}^2$
Sunlight equivalent	70 kLux	69 kLux	192 kLux

Table 7: Ambient-light suppression

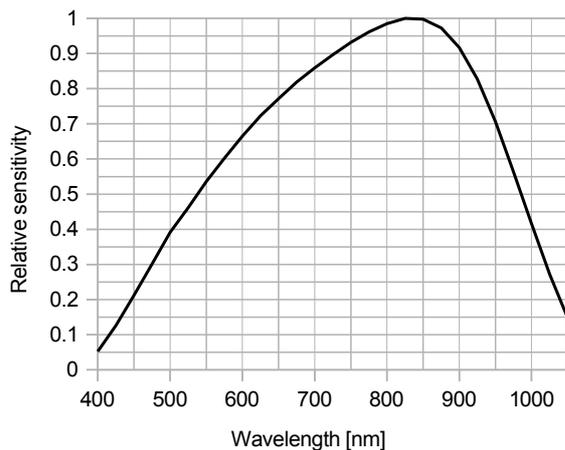


Figure 3: Relative spectral sensitivity ( $S_r$ ) sensitivity  $S_{\text{AC}}$  vs. wavelength

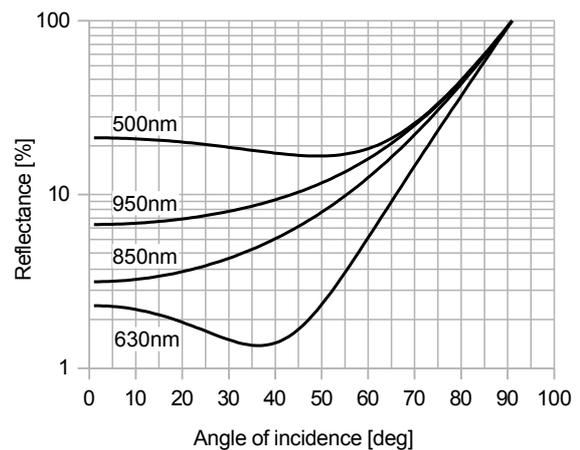


Figure 4: Reflectance vs. illumination angle (AOI)

## 2. Pin-out

### 2.1. Pin mapping

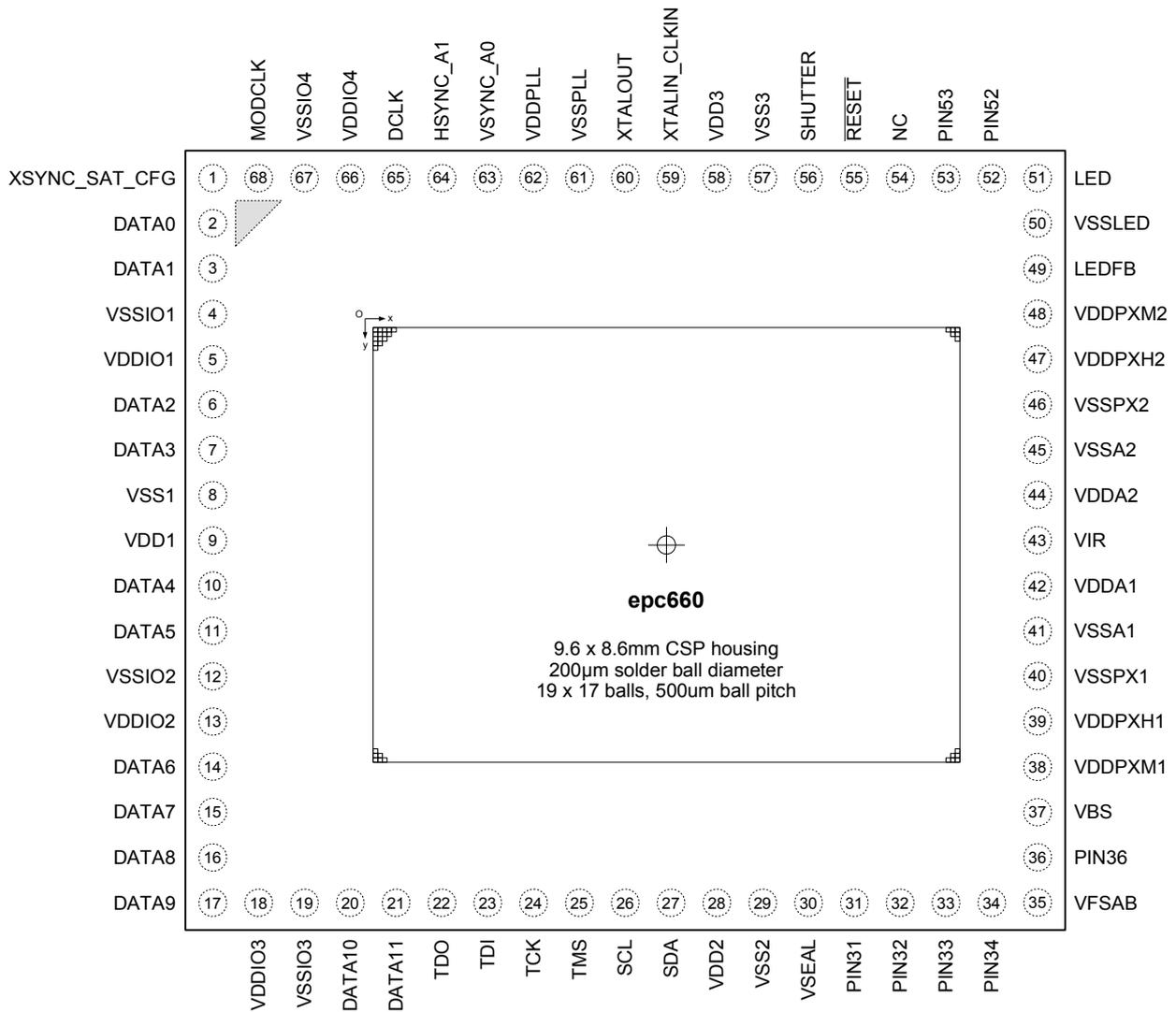


Figure 5: CSP pin mapping (top-view, solder balls are at the bottom, pixel field is at the top)

## 2.2. Pin list

Pin No.	Pin name	Supply class V <sub>sc</sub>	Pin type	Rst func	Rst level	Description
<b>IO pins</b>						
2	DATA0	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-0 (LSB) / Strap 0: reserved
3	DATA1	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-1 / Strap 1: reserved
6	DATA2	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-2 / Strap 2: reserved
7	DATA3	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-3 / Strap 3: reserved
10	DATA4	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-4 / Strap 4: reserved
11	DATA5	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-5 / Strap 5: reserved
14	DATA6	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-6 / Strap 6: reserved
15	DATA7	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-7 / Strap 7: reserved
16	DATA8	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-8 / Strap 8: reserved
17	DATA9	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-9 / Strap 9: reserved
20	DATA10	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-10 / Strap 10: reserved
21	DATA11	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI high-speed output bit-11 (MSB) / Strap 11: reserved
65	DCLK	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OL</sub>	TCMI Data Clock output / Strap 12: reserved
63	VSYNC_A0	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OH</sub>	TCMI Vsync output / Strap 13: I <sup>2</sup> C device address bit A0
64	HSYNC_A1	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OH</sub>	TCMI Hsync output / Strap 14: I <sup>2</sup> C device address bit A1
1	XSYNC_SAT_CFG	V <sub>DDIO</sub>	DIO	IPD <sup>1</sup>	V <sub>OH</sub>	TCMI Xsync output / TCMI Saturation flag output / Strap 15: reserved
26	SCL	V <sub>DDIO</sub>	DIOD	I	V <sub>IH</sub>	I <sup>2</sup> C clock input <sup>5</sup>
27	SDA	V <sub>DDIO</sub>	DIOD	I	V <sub>IH</sub>	I <sup>2</sup> C data input/output <sup>5</sup>
56	SHUTTER	V <sub>DDIO</sub>	DI	PD	V <sub>IL</sub>	Shutter release input
55	RESET	V <sub>DDIO</sub>	DI	PD	V <sub>IL</sub>	Reset input (active low), 600kΩ int. pull-down <sup>4</sup>
68	MODCLK	V <sub>DDIO</sub>	DI	PD		Modulator/demodulator external clock input. If not used, connection to a test pad suggested.
22	TDO	V <sub>DDIO</sub>	DO		V <sub>OL</sub>	JTAG test data output. Do not any electrical connection except to a test pad (suggested).
23	TDI	V <sub>DDIO</sub>	DI	PU	V <sub>IH</sub>	JTAG test data input. Do not any electrical connection except to a test pad (suggested).
24	TCK	V <sub>DDIO</sub>	DI	PD	V <sub>IL</sub>	JTAG test clock input. Do not any electrical connection except to a test pad (suggested).
25	TMS	V <sub>DDIO</sub>	DI	PU	V <sub>IH</sub>	JTAG test mode select input. Do not any electrical connection except to a test pad (suggested).
<b>Digital pins</b>						
59	XTALIN_CLKIN	V <sub>DDPLL</sub>	AI			OSC input from external XTAL or Resonator / CLKIN from external clock source
60	XTALOUT	V <sub>DDPLL</sub>	AO			OSC output (buffered) to ext. XTAL or Resonator

Table 8: Pin list

Pin No.	Pin name	Supply class $V_{sc}$	Pin type	Rst func	Rst level	Description
<b>Analog pins</b>						
51	LED	$V_{DDLED}$	AOD		$V_{LED}$ max	LED/LD driver open-drain output <sup>3</sup>
49	LEDFB	$V_{DDLED}$	AI		$V_{LEDFB}$ max	LED/LD driver feedback input <sup>3</sup>
52	PIN52	---	---			Reserved. Do not any electrical connection except to a test pad (suggested).
53	PIN53	---	---			Reserved. Do not any electrical connection except to a test pad (suggested).
31	PIN31	$V_{DDPXH}$	AI			Reserved. Do not any electrical connection except to a test pad (suggested).
32	PIN32	$V_{DDPXH}$	AI			Reserved. Do not any electrical connection except to a test pad (suggested).
33	PIN33	---	---			Reserved. Do not any electrical connection except to a test pad (suggested).
34	PIN34	---	---			Reserved. Do not any electrical connection except to a test pad (suggested).
35	VFSAB	$V_{DDPXH}$	---			Reserved. Connect to VSSPX.
36	PIN36	$V_{DDPXH}$	AI			Reserved. Connect to VSSPX.
<b>Supply pins, digital</b>						
5	VDDIO1	$V_{DDIO}$	PWR			IO supply VDDIO
13	VDDIO2	$V_{DDIO}$	PWR			IO supply VDDIO
18	VDDIO3	$V_{DDIO}$	PWR			IO supply VDDIO
66	VDDIO4	$V_{DDIO}$	PWR			IO supply VDDIO
9	VDD1	$V_{DD}$	PWR			Digital supply VDD
28	VDD2	$V_{DD}$	PWR			Digital supply VDD
58	VDD3	$V_{DD}$	PWR			Digital supply VDD
62	VDDPLL	$V_{DDPLL}$	PWR			PLL supply
4	VSSIO1	$V_{DDIO}$	GND			IO ground VSSIO
12	VSSIO2	$V_{DDIO}$	GND			IO ground VSSIO
19	VSSIO3	$V_{DDIO}$	GND			IO ground VSSIO
67	VSSIO4	$V_{DDIO}$	GND			IO ground VSSIO
8	VSS1	$V_{DD}$	GND			Digital ground VSS
29	VSS2	$V_{DD}$	GND			Digital ground VSS
57	VSS3	$V_{DD}$	GND			Digital ground VSS
61	VSSPLL	$V_{DDPLL}$	GND			PLL ground
<b>Supply pins, analog</b>						
42	VDDA1	$V_{DDA}$	PWR			Analog supply VDDA
44	VDDA2	$V_{DDA}$	PWR			Analog supply VDDA
43	VIR	$V_{IR}$	PWR			Isolation supply
37	VBS	$V_{BS}$	PWR			Bias supply
39	VDDPXH1	$V_{DDPXH}$	PWR			Pixel analog 2 supply VDDPXH
47	VDDPXH2	$V_{DDPXH}$	PWR			Pixel analog 2 supply VDDPXH
38	VDDPXM1	$V_{DDPXM}$	PWR			Pixel analog 1 supply VDDPXM
48	VDDPXM2	$V_{DDPXM}$	PWR			Pixel analog 1 supply VDDPXM

Table 8 cont.: Pin list

Pin No.	Pin name	Supply class $V_{sc}$	Pin type	Rst func	Rst level	Description
30	VSEAL	$V_{SEAL}$	PWR			Sealring supply
41	VSSA1	$V_{DDA}$	GND			Analog ground VSSA
45	VSSA2	$V_{DDA}$	GND			Analog ground VSSA
40	VSSPX1	$V_{DDPX}$	GND			Pixel analog ground VSSPX
46	VSSPX2	$V_{DDPX}$	GND			Pixel analog ground VSSPX
50	VSSLED	$V_{DDLED}$	GND			LED/LD driver ground (return current) <sup>2</sup>
54	NC	---	---			Reserved. Do not any electrical connection except to a test pad (suggested).

Table 8 cont.: Pin list

Notes:

- <sup>1</sup> DIO pin is configured as input with internal pull-down resistor enabled during  $\overline{RESET} = 0$  (active), only. As soon as  $\overline{RESET}$  is driven to 1, pins stay in that state for another  $4 \times \text{osc\_clk}$  periods (see chapter 5.3.3., Strap pins), then the pin is configured as output, finally the internal pull-down resistor is disabled. From this moment on, the pin can be used for normal output function.
- <sup>2</sup> VSSLED is the dedicated, isolated GND pin for the LED/LD return-current from external circuitry. It must be connected to PCB GND plane together with the other VSSA GND pins.
- <sup>3</sup> LED output can be used to drive an external amplifier with an addition of a pull-up resistor. There are internal ESD protection diodes from LED output and LEDFB input to VDDA supply pins. Voltage at these pins must not exceed values in Table 1: Operating conditions and electrical characteristics.
- <sup>4</sup> RESET pin has a 600k $\Omega$  (typical) internal pull-down resistor. Therefore, this pin can be safely connected to a standard GPIO of a CPU which is initially high-Z or open-drain during power up sequence. Once the SW takes control, it can program this GPIO as output and drive 1 to release the RESET. The internal pull-down can be override by and external 10k $\Omega$  pull-up and a series capacitor to build a simple delayed power-on reset for evaluation/qualification purposes.
- <sup>5</sup> I<sup>2</sup>C pins SCL, SDA are according to I<sup>2</sup>C standards. They are I<sup>2</sup>C slave pins which need external pull-up resistors on the PCB. Values of R1 and R2 in the schematics are given only for indicative purposes and must be re-calculated according to the total capacitive load of all I<sup>2</sup>C slave/master devices and operating mode (FM or FM+) of the I<sup>2</sup>C (chapter 5.4.) in the application.

'Pin type' in Table 8 defines the following:

- DI: Digital Input
- DO: Digital Output
- DIO: Digital Input/Output (bidirectional)
- DIOD: Digital Input/Output (bidirectional), open-Drain
- AI: Analog Input
- AO: Analog Output
- AOD: Analog Output, open-Drain
- PWR: Supply
- GND: Ground

'Rst. Func.' in Table 8 defines the function of IO pins during reset:

- I: Input
- PU: internal Pull-Up
- PD: internal Pull-Down
- IPD: Input with internal Pull-Down

'Rst. Level' in Table 8 defines the level of the IO pins during/after reset (chapter 5.3.)

### 2.3. Power domain separation and ESD protection

The epc660 chip has internally 10 different power domains and 6 ground references which are interconnected with ESD protection diodes. All pins are also equipped with ESD protection diodes. Figure 6 shows this functional circuit. The diodes have a breakthrough voltage of 0.3V. The designer has to take care that none of these diodes become conductive either at power-up, power-down or normal operation.

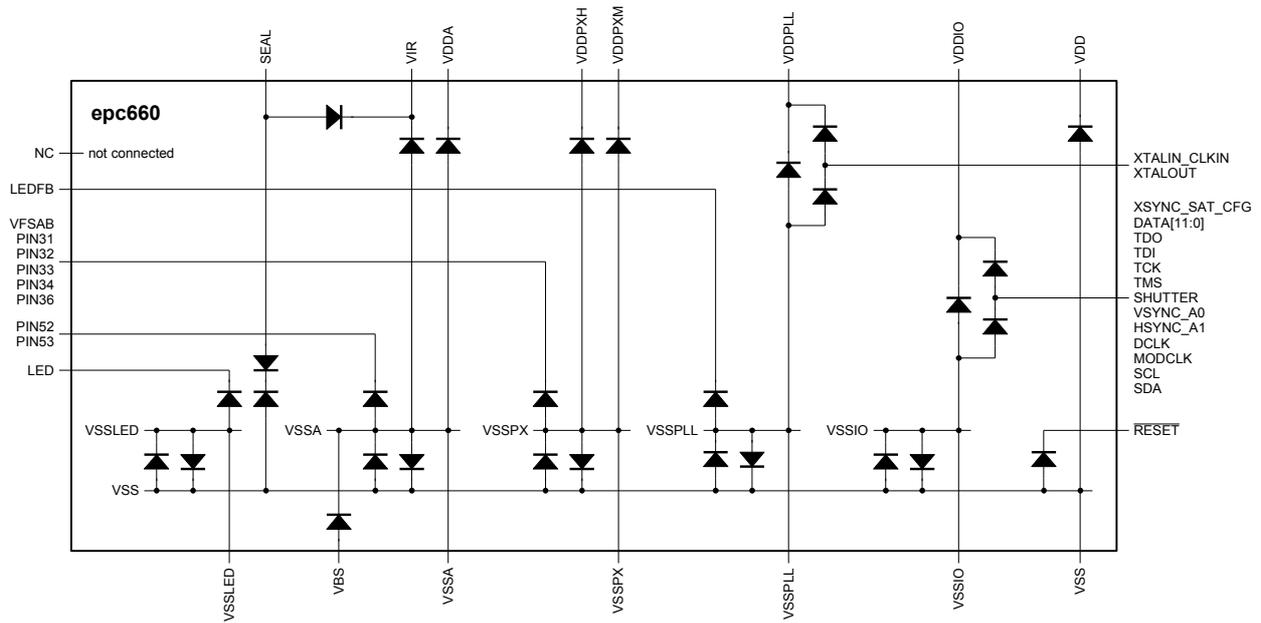


Figure 6: I/O pins and ESD protection diagram

#### Note:

Pin 51, NC can be used, to check if the chip is assembled the correct way on the PCB board. It is chip-internally not connected and will not show any ESD diodes.

### 3. Packaging and layout information

#### 3.1. Mechanical dimensions

The center of the effective pixel field (320x240) is positioned with respect to the center of CSP pin 1 (XSYNC\_SAT\_CFG) with an offset of 4'900µm by 4'000µm (x,y). This point corresponds to intersection of middle of columns C163 - C164 and middle of rows R125 - R126 when mapped to pixel field coordinate system on the die (see Figure 29).

The packaging technology is chip scale packaging (CSP).

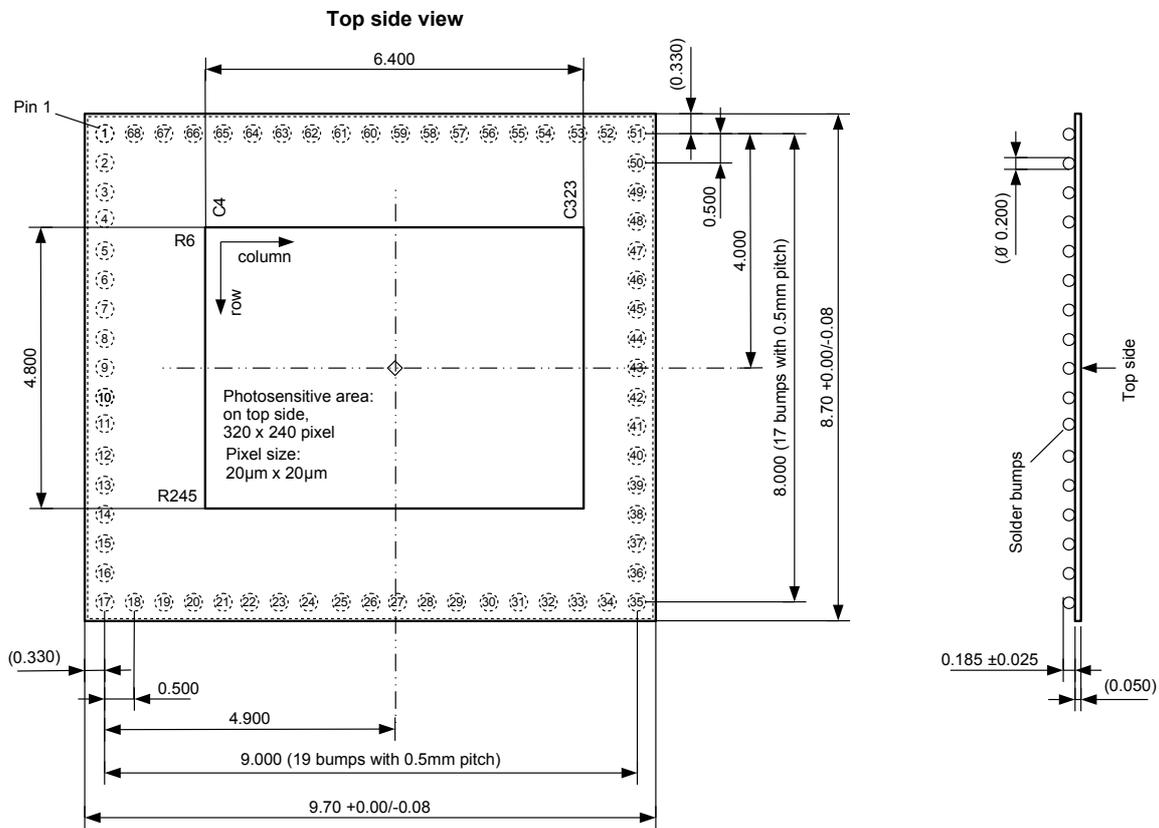


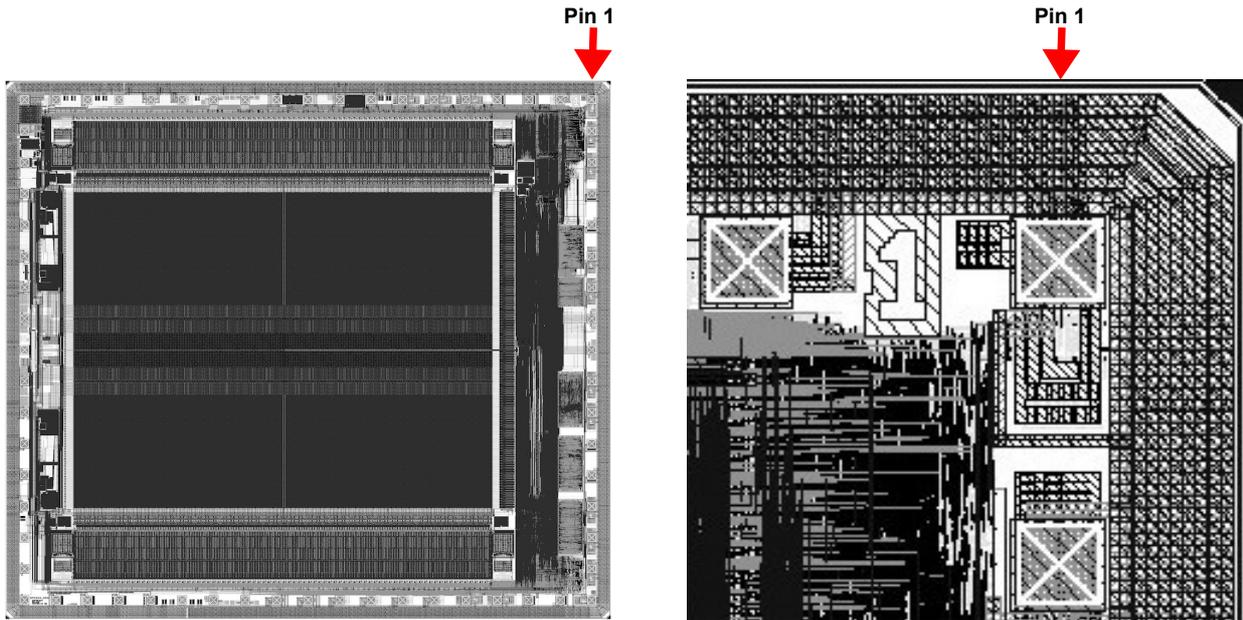
Figure 7: Mechanical dimensions

Notes:

- 
- all measures in mm
- not specified tolerances: ±0.001mm
- Dimensions in brackets: informal only
- Top side is illumination side

### 3.2. Pin1 marking

The following pictures shows the epc660 chip from the bottom side with view to the solder balls. Please note the location of pin 1.



epc660 chip from the solder ball side

Top right corner from the solder ball side

Figure 8: Pin 1 marking

### 3.3. Location of the photosensitive area

The photosensitive area is not marked neither on the front nor on the backside of the IC. As a visible reference, a metal ring of the IC can be used. From the solder ball side it is visible. Also from the front side (photosensitive area) it can be seen with a camera which is sensitive in the near infrared wavelength domain (950 .. 1'150nm).

### 3.4. PCB design and SMD manufacturing process considerations

Since the epc660 chip comes in a very small 68 pin chip scale package, the PCB layout should be made with special care. Since the silicon chip is small and light weight compared the the solder balls, it is highly recommended that all tracks to the chip should come straight from the side. A consequent symmetrical design is therefore highly recommended to achieve high production yield.

The pads and the tracks should also have exactly the same width and shall be covered by a solder resist mask in order to avoid drain of the solder tin alloy to the track.

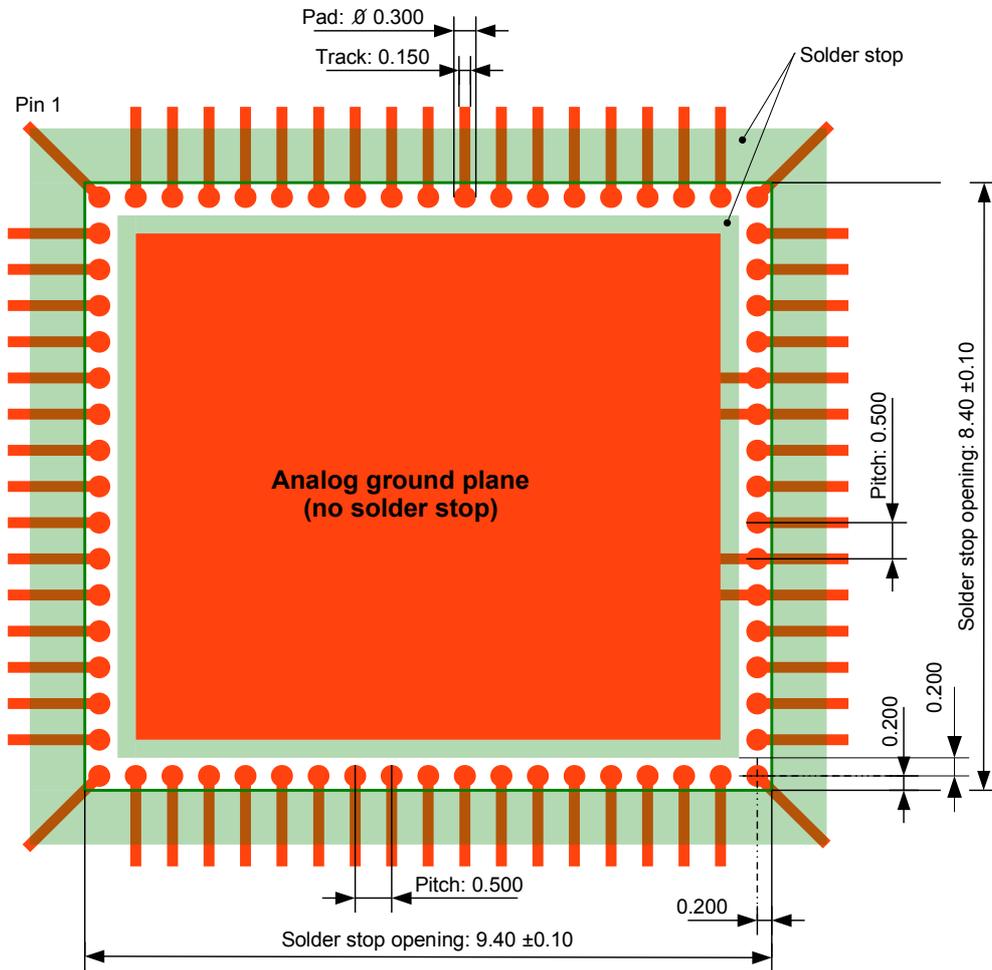


Figure 9: Recommended PCB layout (all measures in mm)

As shown in Figure 9, a ground plane shall be placed on the top PCB layer underneath the chip. This ground plane acts as a shield to suppress high frequency emission of fast interface signal lines. It is important that this plane is completely flat. Thus, the plane must not be scattered nor divided into sections. It should be rather full-faced and no via must be placed in this plane. Otherwise, the chip will pick up the surface and get bended.

Underfill of the components reduces stress to the solder pads caused by e.g. temperature cycling or mechanical bending. The thermal and mechanical fatigue will be reduced and the longterm reliability will be increased. Underfill and underfill selection is application specific. It shall follow JEDEC-STD JEP150: Stress-Test-Driven Qualification of and Failure Mechanisms Associated with Assembled Solid State Surface-Mount Components.

Please also refer to the application note AN04 - Assembly of Wafer Level Chip Scale (WL-CSP) Packages - which can be downloaded from the ESPROS website at [www.espros.com/application-notes](http://www.espros.com/application-notes). Obeying the recommendations in the applications AN04, a high manufacturing yield can be achieved.

### 3.5. Soldering and IC handling

Since the chip is only 50µm thick, a careful handling during the surface mount assembly process shall be taken in order to avoid mechanical damage. In addition to that, careful PCB layout is needed in order to achieve reliable assembly results with a high yield. Please refer to the application note AN04 from epc which contains comprehensive information to these topics. This application note can be downloaded at [www.espros.com/application-notes](http://www.espros.com/application-notes).

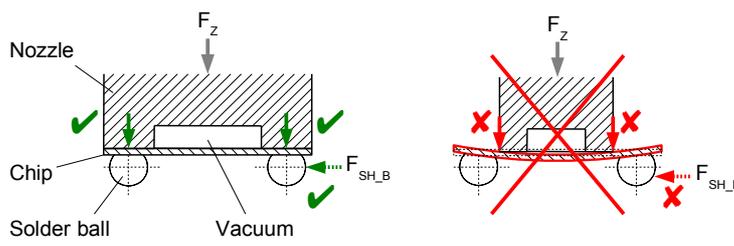
Item	Description
Solder balls: Alloy	Sn96.5Ag3.0Cu0.5 (SAC305)
Soldering profile	For infrared or conventional soldering, the solder profile has to follow the recommendations of IPC/JEDEC J-STD020C (revision C and later) for lead-free assembly.
Soldering lead temperature	$T_L = 260\text{ °C}$ for 4s with a maximum gradient of 6 °C/s
Allowed cleaning agents	Isopropanol
Packaging technology	Bare-die CSP with underfill
Pick and place	 <p>Figure 10: Pick &amp; place; left: good nozzle, good picking; right: bad nozzle, bad picking</p> <p>The nozzle needs a flat surface. It must not touch the pixel-field area. It should not have any flashes where it touches the chip. The chip can get damaged. The nozzle has to bring the <math>F_z</math> force evenly distributed in a vertical way to the center of the solder balls during picking and placing. Refer to Figure 10, left picture. It means that it should be large enough so that it picks the chip not just in the middle of the part but in the area above the solder balls. Bending of the chip is not allowed. Refer to Figure 10, right picture. Keep attention having no shear forces to the solder balls during picking the chip from the tape pocket and/or placing.</p> <p>Maximum vertical force <math>F_z</math> per chip: <math>\leq 0.8\text{ N}</math>.  Maximum shear force <math>F_{SH,B}</math> per ball: <math>\leq 0.5\text{ N}</math>.  Preferred is forceless picking with vacuum only.  It is also highly recommended to use a „kiss-and-goodbye“ concept to place the component. It means that the nozzle should blow the part away when it does the placing.</p>

Table 9: IC handling specification

## 4. Ordering Information

Part Number	Part Name	Package	RoHS compliance
P100 183	epc660-CSP68	CSP68	Yes
P100 244	epc660 Card Edge Connector Carrier	PCB 37.25 x 36.00 mm	Yes

Table 10: Ordering Information

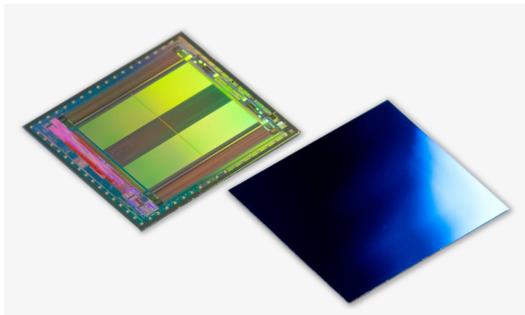


Figure 11: epc660-CSP68 (bottom and top side)



Figure 12: epc660 Card Edge Connector Carrier

## 5. Functional Description

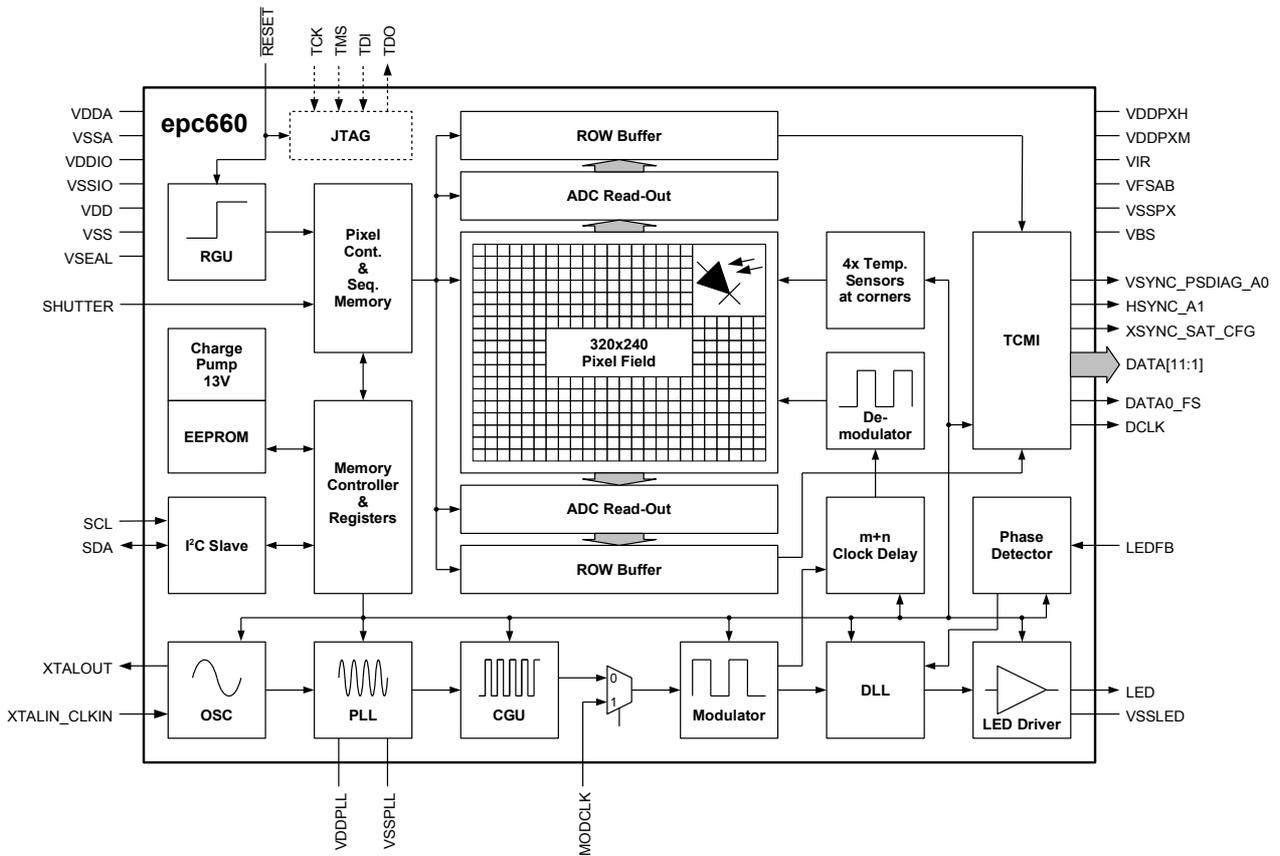


Figure 13: Block diagram

Figure 13 shows the relations between the functional blocks with signal flow diagram.

Based on the clock and mode setup of the chip, the modulation signal is generated and output over the LED driver to the external IR LED. Current flowing through the LED output pin can be monitored via LEDFB pin. This information is used for compensating delays generated due to temperature changes and aging of the LED in the system. Instead of an LED, also Laser diodes (LD) can be used.

The compensation is used for delaying the demodulation signal going into the pixel field.

In the pixel field, the reflecting IR light returning from the object is captured and converted to electrons which are transferred into two storage gates within each pixel (MGA and MGB) depending on the phase information of the demodulation signal.

The parallel ADC blocks on top and bottom pixel field efficiently convert and transfer the phase information to the digital domain where it will be formatted and finally output via the TCMI for external distance calculation.

### 5.1. Typical Application Diagram

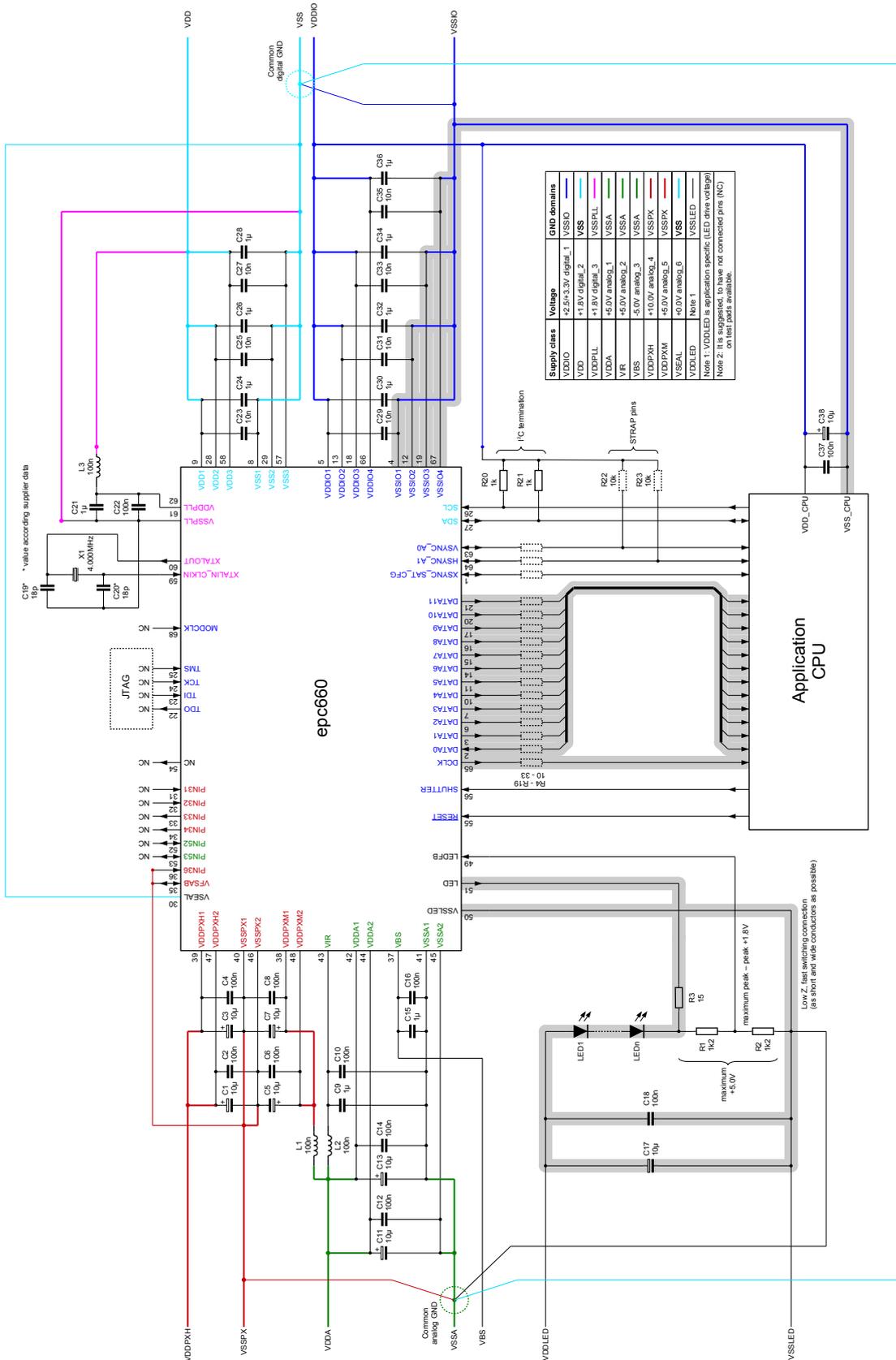


Figure 14: Typical Application Diagram

epc660 is supplied with four positive (+1.8V, +2.5/3.3V, +5V, +10V) and one negative (-10V) external DC supply voltage levels (Figure 14).

- Decoupling capacitors must be placed next to each supply pin pair in order to minimise the instantaneous voltage drop on internal supply rails due to fast switching high-speed signals (Table 11). They help reducing switching noise on internal/external supply rails. Therefore, they minimize the impact on system's optical/electrical performance.

+1.8V is used for supplying the digital logic (VDD), the on-chip oscillator OSC and the phase-look-loop PLL (VDDPLL).

- The digital logic creates some internal switching noise on VDD.
- When same supply is shared together with OSC and PLL, their supply wiring must be separated from the digital wires and physically isolated from each other. These supplies are marked in the application diagram as VDD and VDDPLL, respectively (Figure 14). A good practice is inserting on the PCB a series inductance of 100nH between them close to the supply source, then creating separate supply islands for both on the board. The XTAL/OSC and PLL are critical parts of the chip which directly impacts the optical system performance (i.e. distance calculation). Therefore, if the +1.8V supply is too noisy, it is recommended for the application to have a dedicated silent +1.8V supply only for OSC and PLL.

+2.5/3.3V is used for supplying the high-speed IO pins and the slow I<sup>2</sup>C pins (VDDIO).

- High speed IO pins toggle at 20/40/80MHz during data transfer, hence generating continuously switching noise (much more dominant than the digital noise). Therefore VDDIO supply wires and layers must be carefully designed and isolated in a separate supply island on the PCB.
- I<sup>2</sup>C pins external pull-up resistors can share the same supply on the PCB.
- As the name implies, the IO supply voltage can be one of the two +2.5V, +3.3V or in between. The specific IO voltage depends on the choice of the application CPU's IO voltage and other system supply requirements. It is not recommend to change this voltage on the fly when the TCMI or I<sup>2</sup>C interfaces are running. When the application needs power saving during system idle periods, it can be scaled from +3.3V down to +2.5V only after frame acquisition is stopped and both interfaces are completely inactivated. It can be increased back to +3.3V before re-activating the chip for frame acquisition, accessing I<sup>2</sup>C or TCMI interface. Note that, voltage scaling must be done in a controlled way having both application CPU's and epc660's IO voltages at the same time at the same level.
- Some CPU's can also work at +2.5V IO voltage but with reduced IO toggle speed. In such situations, application must make sure that the right TCMI DCLK frequency is set, both on the epc660 and on the CPU itself.

+5V is used for supplying three different analog blocks of the chip, pixel field drivers (VDDPM), ADC readout circuitry (VDDA) and isolation (VIR). Refer to Figure 14).

- Internal supplies of these three blocks are decoupled from each other. Therefore, their supply pins must also be decoupled on the PCB. It is recommended to insert a series inductance of 100nH between them close to the supply source on the PCB. A separate supply island on the PCB is also recommended.

VBS is used for biasing the the pixel field.

- The use of a stable supply source with a low ripple is recommended. There is no switching or active internal circuit working on that. Therefore this input can be simply decoupled as indicated application diagram (Figure 14), and does not need a dedicated supply island on the PCB.

A 4MHz quartz crystal or a ceramic resonator together with two 18pF load capacitors must be connected to XTALIN\_CLKIN and XTALOUT pins in order to use internal oscillator OSC as time base for the epc660. The capacitor value has to be selected according the crystal or resonator supplier's recommendation. The frequency accuracy and stability are directly related to the distance readings. Alternatively an external clock source can be connected to XTALIN\_CLKIN pin, leaving XTALOUT unconnected (chapter 5.2.).

The optional MODCLK input can be used for user controlled/modulated clock for both the LED driver and the pixel field demodulator.

SCL, SDA are I<sup>2</sup>C slave pins which need external pull-up resistors on the PCB (see also VDDIO supply). Values of R20 and R21 are given only for indicative purposes and must be re-calculated according to the total capacitive load of all I<sup>2</sup>C slave/master devices and the operating mode FM or FM+ of the I<sup>2</sup>C (chapter 5.4.) in the application.

VSYNC\_A0, HSYNC\_A1, XSYNC\_SAT\_CFG, DATA[11:0], DCLK high-speed TCMI signals (chapter 5.8.), SHUTTER and  $\overline{\text{RESET}}$  control signals toggle in the VDDIO range.

- To minimize the skew, the high-speed \*VSYNC, DATA[11:0], DCLK signals wires must be routed equal in impedance and length less than 10cm long with less than 10mm difference on the PCB. As they are toggling all the time, they can be separated with ground wires on the side adjacent to other signals/supply lines, routed with enough distance from other sensitive signal wires on the board. Series termination resistors R4 ... R19 (10 ... 33 $\Omega$ ) are needed at high-speed outputs to control the slew.
- They must be directly connected to the application CPU. In some cases  $\overline{\text{RESET}}$  can also be driven from power management device.
- There are optional pull-up resistors R22 and R23 (10k $\Omega$ ) to set initial values of some configuration registers during start up of the chip. Such outputs pins are called strap pins. They are scanned one time immediately after  $\overline{\text{RESET}}$  is released (chapter 5.3.3.). Two LSB of the I<sup>2</sup>C device address bits are programmable via these strap pins during start-up (chapter 5.3.). When there is only one slave and one master on the I<sup>2</sup>C bus as in the application diagram (Figure 14), these resistors can be omitted.

The LED pin is the internal open-drain IR LED/LD driver output. When the driver is active (on), the IR LED/LD on-current flows through the power resistor R3 into the LED pin, through the driver and comes out of the chip on the VSSLED ground pin.

- The LED pin toggles up to 20MHz or according to the MODCLK clock with a current maximum of 350mA limited by the resistor R3.
- The number of IR LEDs depends on the level of the LED supply voltage and the turned-on forward voltage drop of the IR LEDs.
- This signal creates a lot of ground noise. Therefore, VSSLED pin is decoupled from the other analog grounds internally. It must be shorted with the other analog ground pins with a low-ohmic connection as short as possible on the PCB. In this way, there will be minimal voltage differences in the ground planes of the board.
- The LED supply line must be isolated properly from any analog supply on the PCB to minimize noise coupling from the LED drivers.

The LEDFB pin is the amplifier input for the LED feedback signal. The easiest way is to pick it from a voltage divider R1 and R2 following the IR LEDs on the PCB.

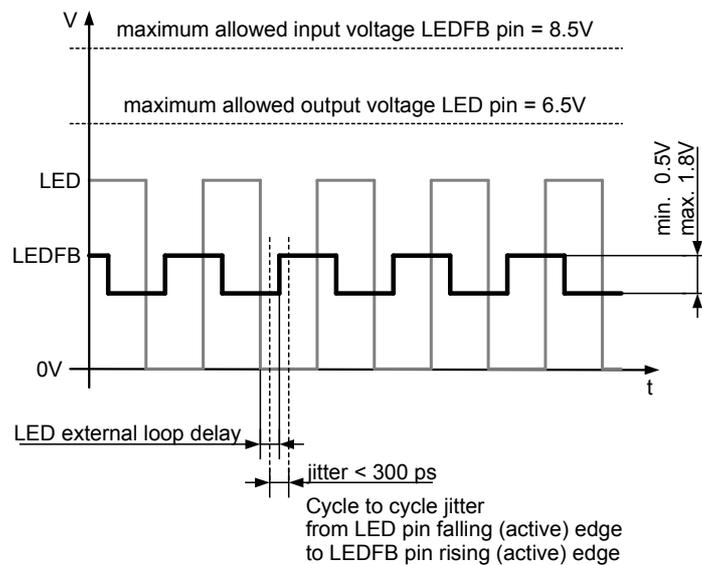


Figure 15: LED and LEDFB pin signal restrictions

TCK, TMS, TDI, TDO are standard JTAG controller pins (Additional information upon request)

It is recommended having “not connected pins” (NC) on test pads available. It helps e.g. to check after assembly for correct orientation of the chip or for short-cuts.

To guarantee the proper function of the chip, the remaining, not here listed pins have to be connected according Figure 14.

Part No.	Description	Pin No.	Value			Tolerance	Supply class V <sub>sc</sub>	Comments
			Min.	Typ.	Max.			
C1, C3	VDDPXH	46 – 47, 39 - 40	10 µF			±20%	V <sub>DDPXH</sub>	Low ESR
C5, C7	VDDPXM	46 – 48, 38 - 40	10 µF			±20%	V <sub>DDPXM</sub>	Low ESR
C11, C13	VDDA	44 – 45, 41 - 42	10 µF			±20%	V <sub>DDA</sub>	Low ESR
C9	VIR	41 - 43	1 µF			±20%	V <sub>IR</sub>	Ceramic X7R
C15	VBS	37 - 41	1 µF			±20%	V <sub>BS</sub>	Ceramic X7R
C21	VDDPLL	61 - 62	1 µF			±20%	V <sub>DDPLL</sub>	Ceramic X7R
C24, C26, C28	VDD	8 – 9, 28 – 29, 57 - 58	1 µF			±20%	V <sub>DD</sub>	Ceramic X7R
C30, C32, C34, C36	VDDIO	4 – 5, 12 – 13, 18 – 19, 66 - 67	1 µF			±20%	V <sub>DDIO</sub>	Ceramic X7R
C2, C4	VDDPXH	46 – 47, 39 - 40		100 nF		±20%	V <sub>DDPXH</sub>	Ceramic X7R
C6, C8	VDDPXM	46 – 48, 38 - 40		100nF		±20%	V <sub>DDPXM</sub>	Ceramic X7R
C10	VIR	41 – 43		100 nF		±20%	V <sub>IR</sub>	Ceramic X7R
C12, C14	VDDA	44 – 45, 41 - 42		100 nF		±20%	V <sub>DDA</sub>	Ceramic X7R
C16	VBS	37 - 41		100 nF		±20%	V <sub>BS</sub>	Ceramic X7R
C22	VDDPLL	61 - 62		100 nF		±20%	V <sub>DDPLL</sub>	Ceramic X7R
C23, C25, C27	VDD	8 – 9, 28 – 29, 57 - 58		10 nF		±20%	V <sub>DD</sub>	Ceramic X7R
C29, C31, C33, C35	VDDIO	4 – 5, 12 – 13, 18 – 19, 66 - 67		10 nF		±20%	V <sub>DDIO</sub>	Ceramic X7R
C19, C20	XTAL	59, 60	---	18 pF <sup>2</sup>	---	±20%	V <sub>DDPLL</sub>	Ceramic NPO
L1	VDDPXM	---		100 nH		±20%	V <sub>DDPXM</sub>	Inductor
L2	VIR	---		100 nH		±20%	V <sub>IR</sub>	Inductor
L3	VDDPLL	---		100 nH		±20%	V <sub>DDPLL</sub>	Inductor
X1	XTAL	59 - 60	---	4 MHz	---	±100ppm	V <sub>DDPLL</sub>	Quartz / Resonator
R4 - R19	Bus termination		0 Ohm	10 Ohm	33 Ohm	±20%	V <sub>DDIO</sub>	Resistors
R20, R21	I <sup>2</sup> C pull-up			1 kOhm		±20%	V <sub>DDIO</sub>	Resistors
R22, R23	I <sup>2</sup> C address			10 kOhm		±20%	V <sub>DDIO</sub>	Resistors

Table 11: Values of component related to epc660 chip (Figure 14)

Notes:

<sup>1</sup> All other components are application specific.

<sup>2</sup> The capacitor value has to be selected according the crystal or resonator supplier's recommendation.

## 5.2. External Clock

epc660 can be driven by an external 4MHz clock source connected to XTALIN\_CLKIN input pin. XTALOUT output pin left unconnected. Input clock signal levels must match  $V_{DDPLL}/V_{SSPLL}$  supply levels (Table 1).

When the external clock source is coming from +2.5/3.3V voltage domain, a simple resistor divider circuit can be deployed to adjust the voltage levels. The following resistor values R26/R27 are recommended: 1.2k $\Omega$ /2.7k $\Omega$  with +2.5V voltage domain; 1k $\Omega$ /1k $\Omega$  with +3.3V voltage domain (see Figure 16).

XTALOUT is not designed to drive external loads. Therefore, it is not recommended to use XTALOUT as a "buffered clock source" for another device in the application circuit.

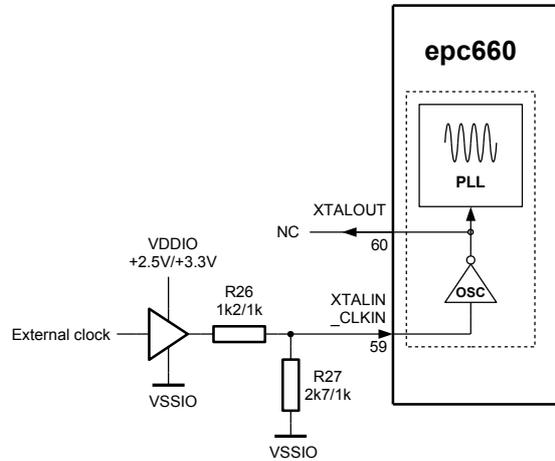


Figure 16: Resistor divider to adjust external clock voltage levels to XTALIN\_CLKIN

**IMPORTANT:** The optical performance of the chip directly depends on the input clock precision/stability; therefore, only a clean, stable clock must be used as external clock source.

### 5.3. Supply, Reset and Start-up Options

#### 5.3.1. Supply voltages and external reset

During the power-up sequence,  $V_{DD}$  and  $V_{DDPLL}$  supplies (Figure 17) must be applied at the same time to the epc660.  $V_{DDIO}$  can be applied either at the same time or after  $V_{DD}$  and  $V_{DDPLL}$  supplies become stable. In a system where  $V_{DDIO}$  voltage is connected in parallel to application CPU IO supply pins (see Figure 14),  $V_{DD}$  and  $V_{DDPLL}$  can be generated by a linear regulator directly from  $V_{DDIO}$  supply. In this case, all these three supplies ramp together.

$V_{DDA}$ ,  $V_{IR}$ ,  $V_{DDPX}$  and  $V_{DDPXH}$  supplies must be applied as a second group, after all  $V_{DD}$ ,  $V_{DDPLL}$  and  $V_{DDIO}$  supplies become stable.

The negative supply  $V_{BS}$  must be applied after all positive supplies reached their rated levels.

The  $\overline{RESET}$  input must be kept active (low) while all positive voltages are ramping-up in order to guarantee proper reset of all internal circuits. As soon as rated positive levels are reached,  $\overline{RESET}$  can be released (high). On the other hand, there is no strict relation between  $V_{BS}$  level and  $\overline{RESET}$  timing. Application must guarantee that the  $V_{BS}$  supply is turned on and reached its negative rated level before the chip is triggered via the SHUTTER for frame acquisition. In case of an external clock is applied at XTALIN\_CLKIN instead of a crystal/resonator is used with on-chip OSC, clock must be present before  $\overline{RESET}$  is released.

#### IMPORTANT:

- It is possible to shutdown entire supplies for a very low standby current. In that case, first  $\overline{RESET}$  must be driven low, then supplies must be turned off in the reverse order. Refer for details to chapter 7.7., Power saving options.
- $V_{DDA}$ ,  $V_{IR}$ ,  $V_{DDPX}$  and  $V_{DDPXH}$  supplies must be never kept on while turning off  $V_{DD}$ ,  $V_{DDPLL}$  and  $V_{DDIO}$ . Such condition may create a permanent damage to the chip.

For rated values of supply voltages, refer to Table 1: Operating conditions and electrical characteristics.

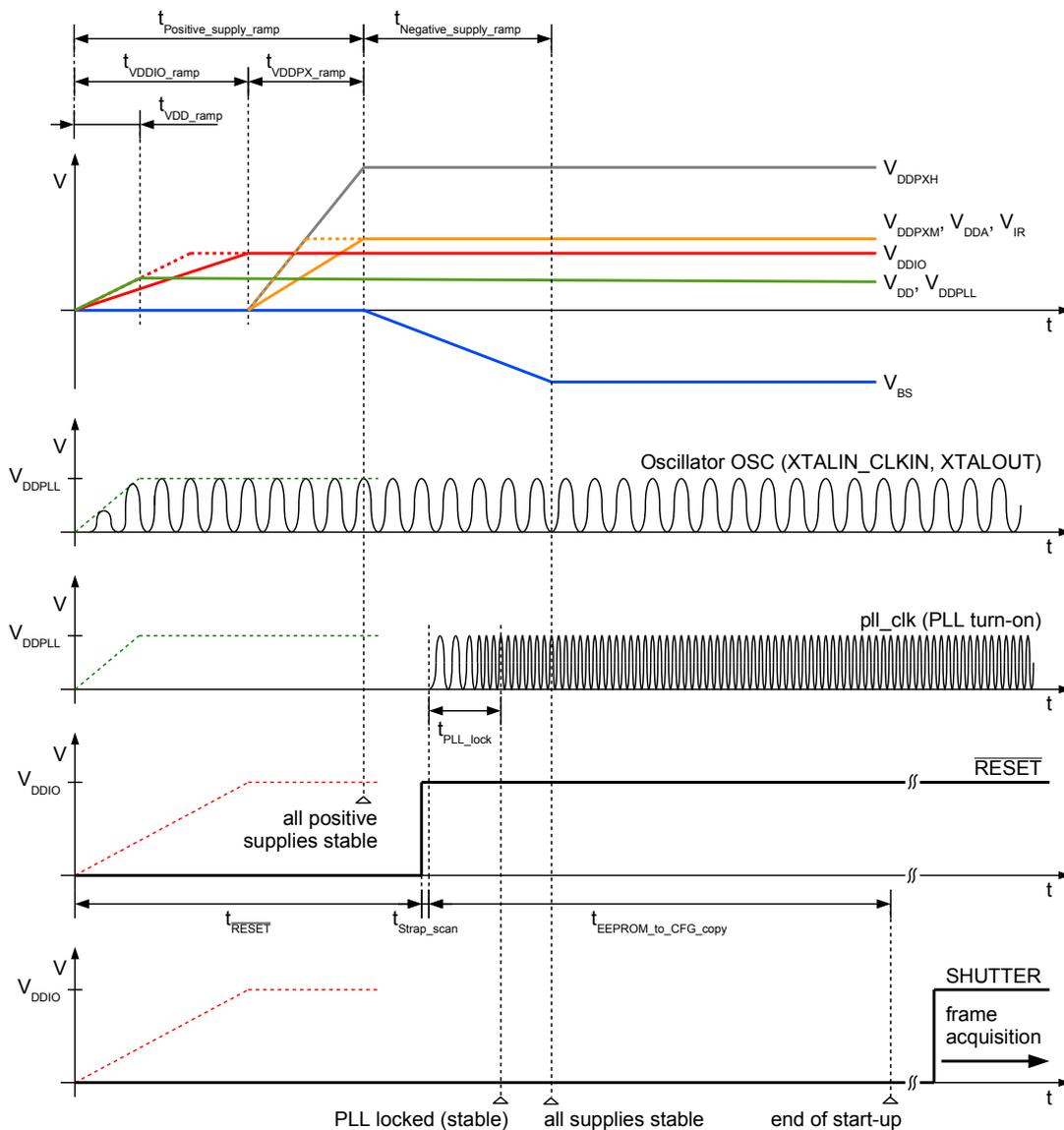


Figure 17: Start-up and reset sequence during power-up (normal mode)

### 5.3.2. Software reset via I<sup>2</sup>C

The epc660 can be software reset by sending I<sup>2</sup>C general call reset command (chapter 5.4.4.). Reset behaviour is similar to RESET pin. The chip is resetting including all analog and digital blocks at the same time.

### 5.3.3. Strap pins

The epc660 has output pins with dual/alternative functionality for PCB level flexible start-up configuration changing, called 'strap pins'.  $\overline{\text{RESET}}$  release is followed by a very short strap pin scanning step. The chip programs all of its strap pins as inputs with internal weak pull-downs enabled for 4 *osc\_clk* periods. If there is no external pull-up resistor connected, the corresponding strap pin will be scanned as logic 0 due to internal pull-down resistor. If there is an external pull-up resistor connected (Figure 14), it will override the internal pull-down and corresponding pin will be scanned as logic 1. After the strap scan period, pins are programmed back as outputs so that they can be used for their main function. Strap pins and their definitions are listed below (Table 12).

Pin	Strap pin	Definition
XSYNC_SAT_CFG	15	reserved
HSYNC_A1	14	Set A1 bit of 7-bit I <sup>2</sup> C slave device address (section 5.4.1.).
VSYNC_A0	13	Set A0 bit of 7-bit I <sup>2</sup> C slave device address (section 5.4.1.).
DCLK, DATA11 ... DATA0	12, 11 ... 0	reserved

Table 12: Strap pin definition

#### IMPORTANT:

For having the strap pin function correctly, there should be only one 10k $\Omega$  pull-up resistor per pin be active on the line during strap-scan phase. No other pull-down/pull-up resistor, neither on the board nor in the pins of the application CPU shall be added or enabled, respectively. Destination pins in the receiving device (application CPU) must be configured always as inputs during the start-up and never programmed as outputs at any time. If the receiving device by default enables its internal pull-down/up resistors during start-up phase, the application SW must disable them before the reset is released and until the end of the strap-scan phase.

### 5.3.4. Start-up (Clock, PLL turn-on and EEPROM copy)

The epc660 starts using either the internal 4MHz oscillator OSC with a crystal/resonator (Figure 14) or an external 4MHz clock, followed by an EEPROM copy sequence in parallel to the PLL turn-on phase. This is the factory default configuration.

Several configuration registers are modified by copying the EEPROM content (Figure 74 and Table 42, i.e. overwrite reset values). The EEPROM copy step takes 340 $\mu$ s after the  $\overline{\text{RESET}}$  is released. Note, the PLL lock time (stable < 32 $\mu$ s) is relatively faster compared to the slower EEPROM copy.

## 5.4. I<sup>2</sup>C Slave

The I<sup>2</sup>C-bus interface allows accessing the RW registers and the programming of the EEPROM registers which stores the configuration parameters. It is the only interface through which the configuration registers can be accessed (Figure 74, Table 41 and Table 42). It works as a slave device according to the I<sup>2</sup>C specification (refer to chapter 9.2.) with a transfer rate of up to 400 kbit/s in Fast Mode (FM) or 1M-bit/s in Fast Mode plus (FM+). The I<sup>2</sup>C master such as an external CPU can set the transfer speed simply by driving the SCL input at that frequency (up to 1MHz), therefore there is no prior register configuration or setting necessary.

I<sup>2</sup>C specification is supported in epc660 with following remarks/exceptions:

- Only 7-bit addressing is supported.
- Clock stretching is supported.
- General call address: By transmitting 0x00 followed by 0x06 (issues software reset) or transmitting 0x00 followed by 0x04 (device address reload), the programmable part (A0, A1) of the I<sup>2</sup>C address pins is overwritten by the initially scanned value through strap pins during start-up or reset phase.
- Software reset is supported.
- Other uses of I<sup>2</sup>C bus are not supported.

### 5.4.1. Device addressing

The epc660 7-bit I<sup>2</sup>C device address is hard-wired to the value shown below in Figure 18. Two address bits A0, A1 can be optionally initialized as 1 through strap pins (chapter 5.3.3.). In a typical single-camera 3D TOF imager application in which epc660 is directly connected as a single I<sup>2</sup>C slave to a single I<sup>2</sup>C master, the strap pins can be used without any external pull-up resistors. In this case, the device address is set after reset default as 0100000. In a multi-camera application with up to 4 epc660 devices connected on the same I<sup>2</sup>C bus as slaves or together with other I<sup>2</sup>C slaves talking to a single I<sup>2</sup>C master, external pull-up resistors can be utilized on the strap pins to initialize different I<sup>2</sup>C device addresses in order to correctly identify different epc660 slaves on the bus.

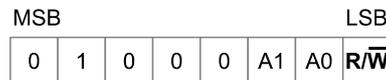


Figure 18: Device address through I<sup>2</sup>C

### 5.4.2. I<sup>2</sup>C bus protocol notation

The following notation is used:

- S        **S**TART condition
- P        **S**TOP condition
- A        **A**cknowledge last byte (ACK)
- $\overline{A}$       **N**ot-Acknowledge last byte (NACK)
- Shaded part of protocol: transmitted by master
- Unshaded part of protocol: transmitted by slave

### 5.4.3. I<sup>2</sup>C bus timing

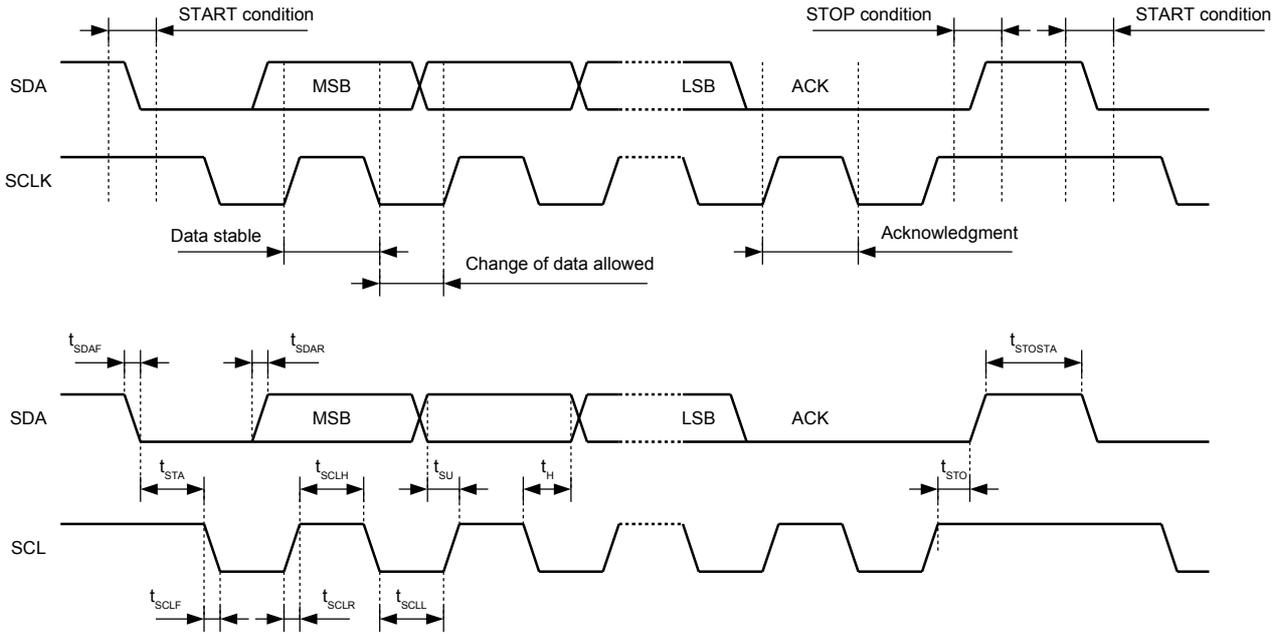


Figure 19: I<sup>2</sup>C bus timing  
top : Basic communication sequence  
below: Timing parameters

Symbol	Parameter	Min.	Max.	Units
$f_{SCL}$	I <sup>2</sup> C data rate		1	Mbit/s
$t_{SCLL}$	SCL clock low time	0.5		$\mu$ s
$t_{SCLH}$	SCL clock high time	0.26		$\mu$ s
$t_{SU}$	SDA setup time	50		ns
$t_H$	SDA hold time		0	ns
$t_{SDAR}$ $t_{SCLR}$	SDA and SCL rise time		120	ns
$t_{SDAF}$ $t_{SCLF}$	SDA and SCL fall time		120	ns
$t_{STA}$	Start condition hold time	0.26		$\mu$ s
$t_{STO}$	Stop condition setup time	0.26		$\mu$ s
$t_{STOSTA}$	Stop to start condition time (bus free)	0.5		$\mu$ s
$C_b$	Capacitive load for each bus line		550	pF
$t_{SP}$	Pulse width of the spikes that are suppressed by the analog filter		50	ns

Table 13: I<sup>2</sup>C bus timing: Timing parameters (FM+)

#### 5.4.4. General calls

epc660 supports two general call commands:

- (0x00, 0x06) issues a software reset, same behavior like with  $\overline{\text{RESET}}$  pin.

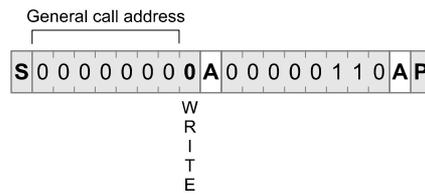


Figure 20: Software reset through I<sup>2</sup>C

- (0x00, 0x04) activates the I<sup>2</sup>C address stored in register 0xCA. Note that the the values of A0 and A1 cannot be changed by software. Therefore, this general call command only works for bits 2 to 6 of register 0xCA (chapter 5.3.3).

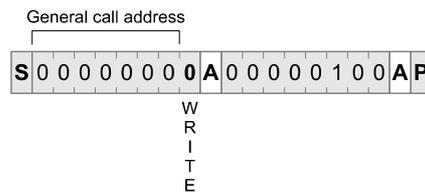


Figure 21: Device address A1, A0 reload through I<sup>2</sup>C

#### 5.4.5. Write access

The epc660 I<sup>2</sup>C interface offers single-byte write access and multi-byte write access, where the former is basically a subset of the latter.

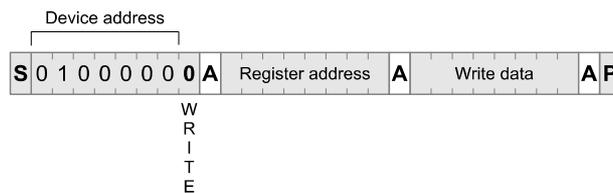


Figure 22: Single-byte Write access through I<sup>2</sup>C

During a single-byte write, only one register is written. After the device address is transmitted, the master has to transmit the register address and the write data in two I<sup>2</sup>C data packets (Figure 22). The access is terminated by a STOP condition.

During a multi-byte write operation, the master transmits the device address and the address of the first register to be written. All subsequent bytes until the STOP condition are interpreted as write data packets by the epc660 (Figure 23). The write address pointer is incremented internally. It is illegal to transmit so many data packets that the write address pointer reaches the limit of reserved address space (see chapter 8.4., Table 41, Table 42).

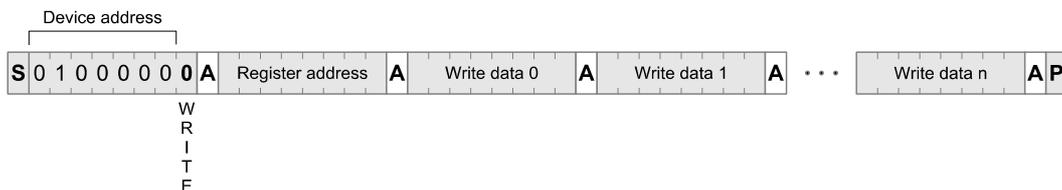


Figure 23: Multi-byte Write access through I<sup>2</sup>C

#### 5.4.6. Read access

The epc660 I<sup>2</sup>C interface offers single-byte read access and multi-byte read access, where the former is basically a subset of the latter.

During a single-byte read, only one register is read. After the device address is transmitted, the master transmits the register address. After addressing the epc660 with a read-command, epc660 answers with the read data (Figure 24). The access is terminated by a not-acknowledge (NACK) and a STOP condition from the master.

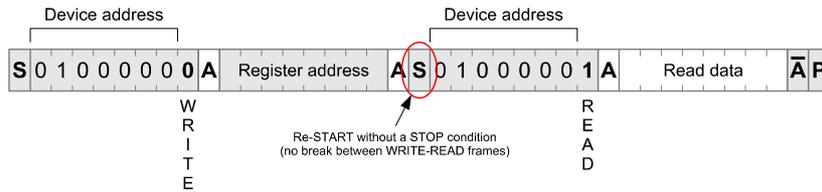


Figure 24: Single-byte Read access through I<sup>2</sup>C

During a multi-byte read operation the master transmits the device address and the address of the first register to be read. After the epc660 is addressed with a read command, epc660 answers with read data bytes until the master does not acknowledge a byte. The master is expected to terminate the access with a STOP condition thereafter (Figure 25). During the access the read address pointer is incremented epc660 internally. It is illegal to read so many data bytes that the read address pointer reaches the limit of reserved address space (see chapter 8.4., Table 41, Table 42).

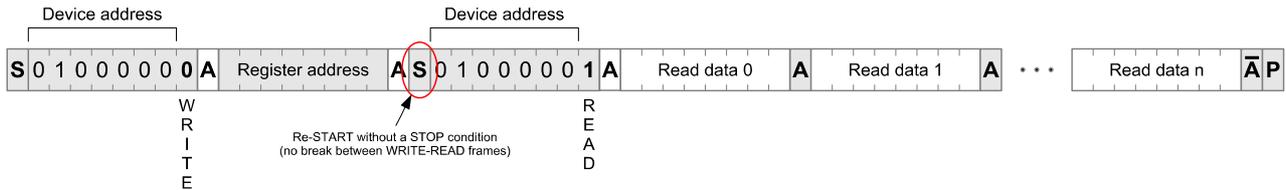


Figure 25: Multi-byte Read access through I<sup>2</sup>C

#### 5.4.7. Control commands

The operating modes of the epc660 are initialized, activated, deactivated and monitored by sending several single or multi-byte write and read command sequences through I<sup>2</sup>C interface. This section lists and explains all available commands together with their access times ( $f_{SCL} = 1\text{MHz} \rightarrow t_{SCL} = 1\mu\text{s}$ ).

Listed in Table 14 is a summary of main control command sequences to operate the chip including the total number of command bytes transferred and their duration. There is no particular order defined for sending the commands. The only requirement is having no on-going frame acquisition process in the pipe when updating non-shadowed registers. The shadowed registers (marked with \*\* in the register map e.g. INTM\_hi/lo, Int\_len\_hi/lo, etc., see section 8.4., Table 42) can be updated on-the-fly during a frame acquisition. New values are taken into account by the next frame. The more safe approach would be finishing the last frame acquisition completely, only then update registers or change mode of operations.

Command	Description	Length [Bytes]	Time [ $\mu\text{s}$ ]
Reset	I <sup>2</sup> C soft reset of the chip (same effect like the RESET pin)	2	20
Device address activation	I <sup>2</sup> C device address activation, see chapter 5.4.4	2	20
Single-byte Write	I <sup>2</sup> C Single-byte write to control registers	3	29
Multiple-byte Write	I <sup>2</sup> C Multiple-byte write (n bytes) to control registers	2 + n	20 + n x 9
Single-byte Read	I <sup>2</sup> C Single-byte read from control registers	4	39
Multiple-byte Read	I <sup>2</sup> C Multiple-byte read (n bytes) from control registers	3 + n	30 + n x 9
Mode set	Sine or PN mode; 4, 2, or 1 DCS set using MOD_control registers	3	29
Integration time (short) set	Integration time set (up to 800 $\mu\text{s}$ ) using Int_len_hi/lo registers	4	38
Integration time (long) set	Integration time set (up to 26s) using INTM_hi/lo, Int_len_hi/lo registers	6	56
Dual Integration time (long) set	Dual int. time set using Int_len_mgx1_*, INTM_*, Int_len_* registers	8	74
Distance offset set	PN mode distance offset set using Dist_offset register	3	29
Resolution reduction set	Binning and row reduction set using Resolution_reduction register	3	29
ROI set	Region of interest set using ROI_* registers	8	74
Shutter	Soft shutter using Shutter_control registers (shutter_en bit)	3	29
Integration time (short) + Shutter	Int. time + soft shutter in one go! (Int_len_*, Shutter_control registers)	5	47
EEPROM Indirect Single Write	Indirect single write to EEPROM (bypass control registers)	9	20ms
EEPROM Direct Burst Write	Direct byte burst write (n bytes) to EEPROM (bypass control registers)	8 + n	n x 20ms
EEPROM Indirect Single Read	Indirect single read from EEPROM (bypass control registers)	10	97
EEPROM Direct Burst Read	Direct byte burst read (n bytes) from EEPROM (bypass control registers)	8 + n	78 + n x 9

Table 14: I<sup>2</sup>C Control commands summary

#### 5.4.8. I<sup>2</sup>C control command examples:

To simplify command sequence definitions, following C-programming language style functions are defined for the I<sup>2</sup>C master CPU:

- i2cGeneralCall(byte genAdr, byte cmd); // 20 x t<sub>SCL</sub> = 20μs
- i2cSingleWrite(byte devAdr, byte regAdr, byte regVal); // 29 x t<sub>SCL</sub> = 29μs
- i2cMultiWrite(byte devAdr, byte regAdr, byte\* regVal, byte n // 20 + (n x 9 x t<sub>SCL</sub>) = 20 + (n x 9)μs
- byte i2cSingleRead(byte devAdr, byte regAdr); // 39 x t<sub>SCL</sub> = 39μs
- byte\* i2cMultiRead(byte devAdr, byte regAdr, byte n); // 30 + (n x 9 x t<sub>SCL</sub>) = 30+(n x 9)μs

#### Software reset with I<sup>2</sup>C general call command

PRECONDITION: None

1. i2cGeneralCall(0x00, 0x06); // Software reset, same effect like  $\overline{\text{RESET}}$  pin, 20μs
2. ... // Wait for t<sub>RESET</sub> (> 100ns, see chapter 5.3.2., Software reset via I2C)

continue frame acquisition

#### Activates device address with I2C general call command

PRECONDITION: None

1. i2cGeneralCall(0x00, 0x04); // Activates I<sup>2</sup>C device address, 20μs
2. i2cSingleWrite(0x22, 0x92, 0x34); // Start with Sine mode, 4x DCS acquisition on I<sup>2</sup>C device 0x22...
3. i2cMultiWrite(0x22, ...
4. ...

continue frame acquisition

#### Sine mode, 4x DCS mode: Acquire DCS 0 ... 3 frames with integration time = 10μs

PRECONDITION: All other registers contain default values.

1. i2cSingleWrite(0x20, 0x92, 0x34); // MOD\_Control = 0x34 (mod\_sel = 00, dcs\_sel = 11), 29μs
2. i2cMultiWrite(0x20, 0xA2, &(0x031F), 2); // Int\_len = 0x031F (Integration time = 10μs), 38μs
3. i2cSingleWrite(0x20, 0xA4, 0x01); // Shutter\_Control = 0x01, (shutter\_en = 1), 29μs
4. ... // Acquisition starts. Wait until all 4x DCS frames are finished.

done.

#### Sine mode, 4x DCS mode: Acquire DCS 0 ... 3 with integration time = 10μs, followed by DCS 0 ... 3 with integration time 200μs

PRECONDITION: All other registers contain default values.

1. i2cSingleWrite(0x20, 0x92, 0x34); // MOD\_Control = 0x34 (mod\_sel = 00, dcs\_sel = 11), 29μs
2. i2cMultiWrite(0x20, 0xA2, &(0x031F), 2); // Int\_len = 0x031F (integration time = 10μs), 38μs
3. i2cSingleWrite(0x20, 0xA4, 0x01); // Shutter\_Control = 0x01, (shutter\_en = 1), 29μs
4. ... // Acquisition starts. Wait until all 4x DCS frames are finished.
5. i2cMultiWrite(0x20, 0xA2, &(0x3E7F), 2); // Int\_len = 0x3E7F (integration time = 200μs), 38μs
6. i2cSingleWrite(0x20, 0xA4, 0x01); // Shutter\_Control = 0x01, (shutter\_en = 1), 29μs
7. ... // Acquisition starts. Wait until all 4x DCS frames are finished.

done.

#### Sine mode, 2x DCS mode: Acquire DCS 0, 1 frames with integration time = 10μs

PRECONDITION: All other registers contain default values.

1. i2cSingleWrite(0x20, 0x92, 014); // MOD\_Control = 0x14 (mod\_sel = 00, dcs\_sel = 01), 29μs
2. i2cMultiWrite(0x20, 0xA2, &(0x031F), 2); // Int\_len = 0x031F (integration time = 10μs), 38μs
3. i2cSingleWrite(0x20, 0xA4, 0x01); // Shutter\_Control = 0x01, (shutter\_en = 1), 29μs
4. ... // Acquisition starts. Wait until all 2x DCS frames are finished.

done.

#### Indirect single write to EEPROM: Store 2 bytes at address 0xE8 and 0xE9

PRECONDITION: None

1. i2cSingleWrite(0x20, 0x11, 0xE8); // EE\_ADDR = 0xE8, 29μs
2. i2cSingleWrite(0x20, 0x12, 0x22); // EE\_DATA = 0x22 (Temp\_tl\_cal1 = 0x22), 29μs + 20ms = ~20ms
3. i2cSingleWrite(0x20, 0x12, 0x28); // EE\_DATA = 0x28 (Temp\_tl\_cal2 = 0x28), 29μs + 20ms = ~20ms
4. ...

done.

Note 1: Start address is written in EE\_ADDR.

Note 2: Each EE\_DATA write starts erase/programming EEPROM. Each EEPROM write takes 20ms, then it auto-increments the EE\_ADDR by 1.

Note 3: Corresponding control register value is not modified. Only EEPROM register is modified.  
Note 4: EEPROM content will only be copied to corresponding control register after RESET.

**Direct burst write to EEPROM: Store 8 bytes at address 0xE8 ... 0xEF**

PRECONDITION: None

1. `i2cMultiWrite(0x20, 0xE8, &(0x22,0x28,0x20,0x26,0x18,0x17,0x19,0x19), 8);` // Store 8x bytes,  
// calibration point registers Temp\_xx\_cal1/2, 20µs + 8 x (9µs + 20ms) = ~160.1ms
2. `i2cSingleWrite(0x20, 0x02, 0x05);` // MEM\_CTRL\_CONF = 0x05 (ee\_direct\_access = 0), 29µs

done.

Note 1: Start address is sent only one time.

Note 2: Corresponding control register value is not modified. Only EEPROM register is modified.

Note 3: EEPROM content will only be copied to corresponding control register after RESET.

**Indirect single read from EEPROM: Read 2 bytes from address 0xEA and 0xEB**

PRECONDITION: None

1. `i2cSingleWrite(0x20, 0x11, 0xEA);` // EE\_ADDR = 0xEA, 29µs
2. `cal1 = i2cSingleRead(0x20, 0x12);` // cal1 = EE\_DATA (Temp\_tr\_cal1 = 0x20), 39µs
3. `cal2 = i2cSingleRead(0x20, 0x12);` // cal2 = EE\_DATA (Temp\_tr\_cal2 = 0x26), 39µs
4. ...

done.

Note 1: Start address is written in EE\_ADDR.

Note 2: Each EE\_DATA read auto-increments the EE\_ADDR by 1.

Note 3: Corresponding control register value is not modified. Only EEPROM is read.

**Direct burst read from EEPROM: Read 8 bytes from address 0xE8 ... 0xEF**

PRECONDITION: None

1. `i2cSingleWrite(0x20, 0x02, 0x07);` // MEM\_CTRL\_CONF = 0x07 (ee\_direct\_access = 1), 29µs
2. `cal_arr[] = i2cMultiRead(0x20, 0xE8, 8);` // Read 8 bytes calibration points Temp\_xx\_cal1/2, 20µs + 8 x 9µs = 92µs
3. `i2cSingleWrite(0x20, 0x02, 0x05);` // MEM\_CTRL\_CONF = 0x05 (ee\_direct\_access = 0), 29µs

done.

Note 1: Start address is sent only one time.

Note 2: Corresponding control register value is not modified. Only EEPROM is read.

## 5.5. LED driver and DLL

### 5.5.1. LED driver

The LED driver is an open-drain MOSFET device. It can sink up to 350mA peak current during operation. The modulation signal is a square-wave up to typically 20MHz with a duty cycle of 50% which depends on the mode of operation.

**IMPORTANT:** There are non-modulating DC modes (e.g. black & white with LED/LD illumination) which keeps the LED driver always turned on. In this case, the user has to take care that LED driver and the epc660 chip does not exceed the maximum operating limits.

The LED\_driver register contains several static bit fields that can be used for setting drive strength, polarity, etc. depending on the external LED/LD circuitry used in the application (see chapter 8.7.6.). These bit fields must not be modified during the frame acquisition.

- The led\_drv\_sel bits set LED driver output maximum current e.g. for 200mA to 100% , 64%, 46% or 33%.
- The led\_on bit permanently turns on the LED/LD (torch function). Keep care to the power dissipations if you operate the LEDs and laser diodes in this mode.
- The led\_drv\_en bit enables the internal LED driver circuits. The enabled after reset (default), can be disabled if there will be no frame acquisition for a long time.
- The led\_inv\_en bit sets the polarity of the LED driver. This must be set/cleared with respect to external LED/LD driver circuit topology and stored in the EEPROM. It is cleared after reset (default), which matches to the simple external LED circuit shown in Figure 14
- led\_ssr\_en bit sets a slower slew rate for the LED driver (part of the LED driver transistor is switched on with a delay to lower the current peaks).

### 5.5.2. DLL (Delay Locked Loop)

The LED driver and external LED's/LD's phase stability suffer mainly from temperature, ageing, etc. of the system. This shows itself as distance error. The built-in DLL circuit minimizes this behaviour. It minimizes the above mentioned long term deviations in the phase delay of critical signals. They are from seconds up to several minutes and longer and impact the performance of the distance accuracy. The DLL can be used with Sine and PN modes. It is located between the modulator and the LED driver (see Figure 27).

The modulator invokes the DLL before DCS frame acquisition at the rate set by the DLL\_measurement\_rate register. Otherwise the DLL period is skipped and the last compensation delay value is preserved on the led\_mod signal path. Figure 26 shows the example for 4x DCS frames and DLL\_measurement\_rate = 4.

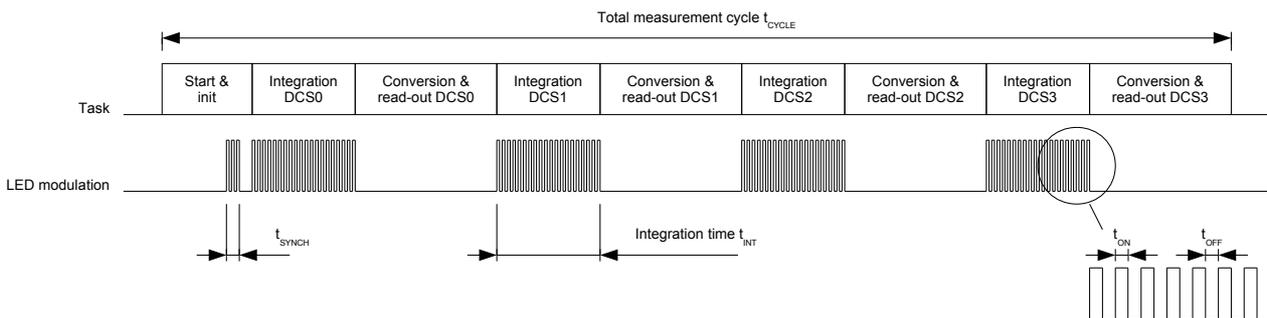


Figure 26: DLL synchronization example for 4x DCS frames

Is the DLL invoked, the mga demodulation signal, originated from the modulator, goes first through digital delay stages. Secondly, it is distributed to the individual pixels in the pixel field (red path, until point A).

The same time, the led\_mod signal goes through the DLL, the LED driver and comes to the LED pin. This pin drives the external LED circuit on the PCB, which generates the modulated IR light (blue path, until point B).

These two signal paths are subject to phase delay deviations depending of e.g. temperature or aging. This delays translate into distance errors. The DLL minimizes deviations by adding a certain delay on the led\_mod signal (x-Delay).

The DLL compares the demodulation signal phase coming from a pixel as mga (point A) with the current feedback signal from the LEDFB pin of the external LED circuit (point B). The distance reading error of the epc660 is minimal if the delays to the signals from the points A and B are identical.

User should minimize the path delay from the feedback node between the resistor dividers to the LEDFB pin (yellow). This can be achieved by placing the resistor dividers as close as possible to the LEDFB pin on the PCB. Other noisy circuits should be placed away from the LEDFB pin and resistor dividers.

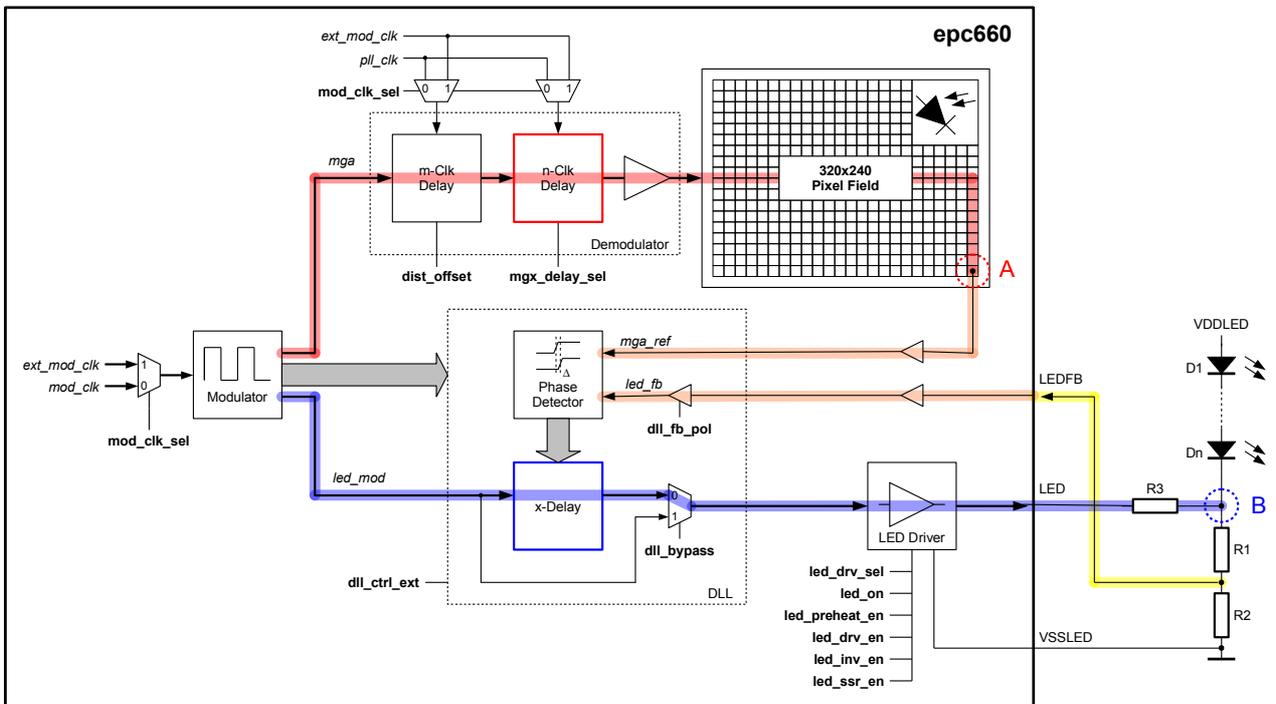


Figure 27: Simplified modulator, demodulator, DLL and LED driver diagram

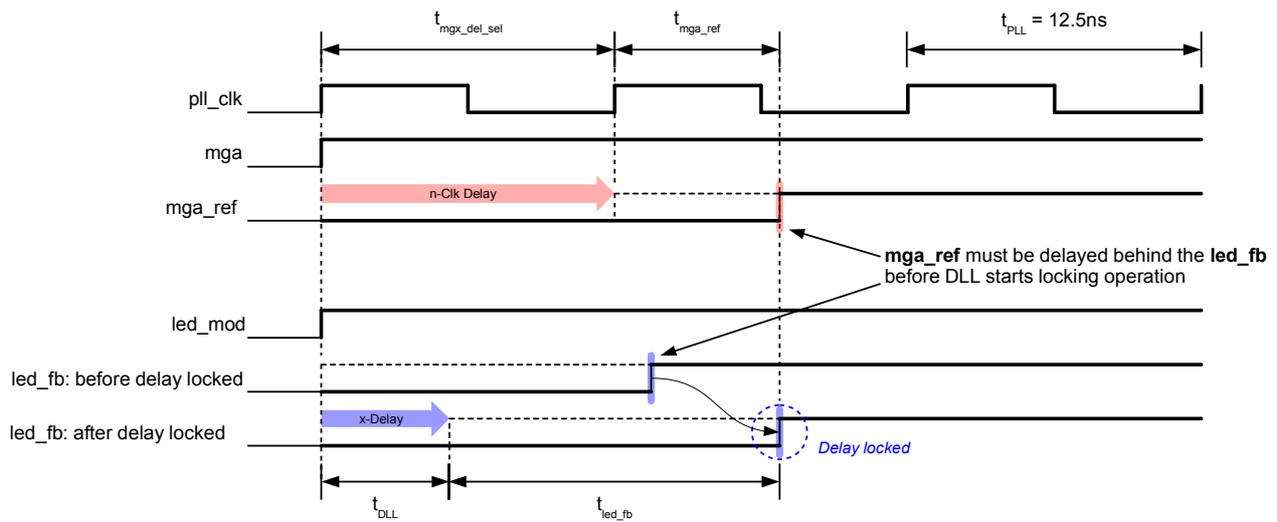


Figure 28: DLL delay locking operation

### DLL locking operation

Before the DLL starts its locking operation, the `mga_ref` signal must be delayed behind the `led_fb` signal (see Figure 28). This is achieved by setting `mgx_delay_sel = 1` or higher in the register `Demodulation_delays`, which gives an initial 12.5ns phase offset to the `mga_ref` signal (PLL is set to 80MHz). Next, the modulator starts toggling the `mgx` and `led_mod` signals for a certain time without enabling the DLL (DLL pre-synchronization: `DLL_en_del`). Finally, the modulator enables the DLL and keep toggling the `mgx` and `led_mod` signals until the locking operation is finished (`DLL_en`). The DLL pre-synchronization and DLL lock time is set to 10µs, respectively 30µs, in Figure 26 indicated as  $t_{SYNC}$ . These default values can be changed by `DLL_en_del/DLL_en` registers (see Table 42, DLL Synchronization registers).

When locked, the DLL adds and freezes the compensation delay (`x-Delay`) to bring point A and B together in time, until the same operation is restarted by the modulator again. The rate of DLL measurements is set in terms of number of DCS frames by `DLL_measurement_rate` register. Note, this value must be set to multiples of number of DCS frames selected by the `MOD_Control.dcs_sel` register e.g. when `dcs_sel = 11`, the system is in the 4x DCS mode, then set `DLL_measurement_rate = 4`. This way, all DCS frames (0 ... 4) are acquired with the same DLL compensation delay and the samples stay correlated with each other. For `DLL_measurement_rate = 0`, last measured compensation delay value is kept and used for the next DCS frames.

**IMPORTANT:** The DLL has a delay locking range of 6ns ... 76ns with 7ps fine delay steps. There is always a minimum 6ns delay inserted on the `led_mod` line when the DLL is enabled. The LED driver, the external LED/LD circuit and the LEDFB input amplifier delays are added on top. Therefore, `mgx_del_sel` must always set to 1 or higher.

If the dependent delay variation of the external LED/LD circuit is more than the one pll\_clk period, mgx\_del\_sel must set to a higher value the way, that the DLL can compensate this wide-range variation. LED/LD circuits placed on the board far away from the epc660 or placed even more on another PCB are connected with long wires. This can cause long time offset.

## 5.6. Pixel Field

### 5.6.1. Pixel coordinates

The epc660 pixel field consists of a total of 328 x 252 pixels. 6 rows top/bottom and 4 columns left/right on the periphery of the pixel field contain dummy pixels which cannot be used for 3D-TOF and black & white imaging. The active pixels, so called “effective pixels”, can be used for TOF and black & white imaging modes. They are in the central rectangle area forming a full QVGA resolution 320 x 240 pixel (Figure 29).

The upper-left corner (top view on chip) is the origin (0/0) of the epc660 pixel coordinate system. Pixel x-axis starts at 0 and counts up to 327 to the right. Pixel y-axis starts at 0 and counts up to 251 to the bottom. All readout modes (ROI, resolution reduction, binning, etc.) and control registers use this coordinate system to set or change modes of the chip.

User should not readout dummy columns (x = 0 ... 3; 324 ... 327) or dummy rows (y = 0 ... 5; 246 ... 251) as there cannot be acquired useful imaging data from these pixels.

The QVGA rectangle with the effective pixels range between the upper-left (4/6) and bottom-right (323/245) pixel. It is set as the default ROI area during start-up.

The pixel field is split vertically into two equal parts as pixel field top and bottom. The data read-outs are duplicated symmetrically on the top and bottom of the chip in order to double the frame rate of the epc660.

Default readout starts in the middle of the row axis and continues symmetrically towards up and down, row by row and in parallel, to the top and bottom of the pixel field. As example, default readout starts with rows R125/R126, followed by R124/R127, and so on. The vertical readout direction can be changed by the application appropriately.

The internal readout of a row is split in two sections: first all even pixels; second all odd pixels. Later on the TCMI interface presents the row in the regular order with even and odd pixels mixed.

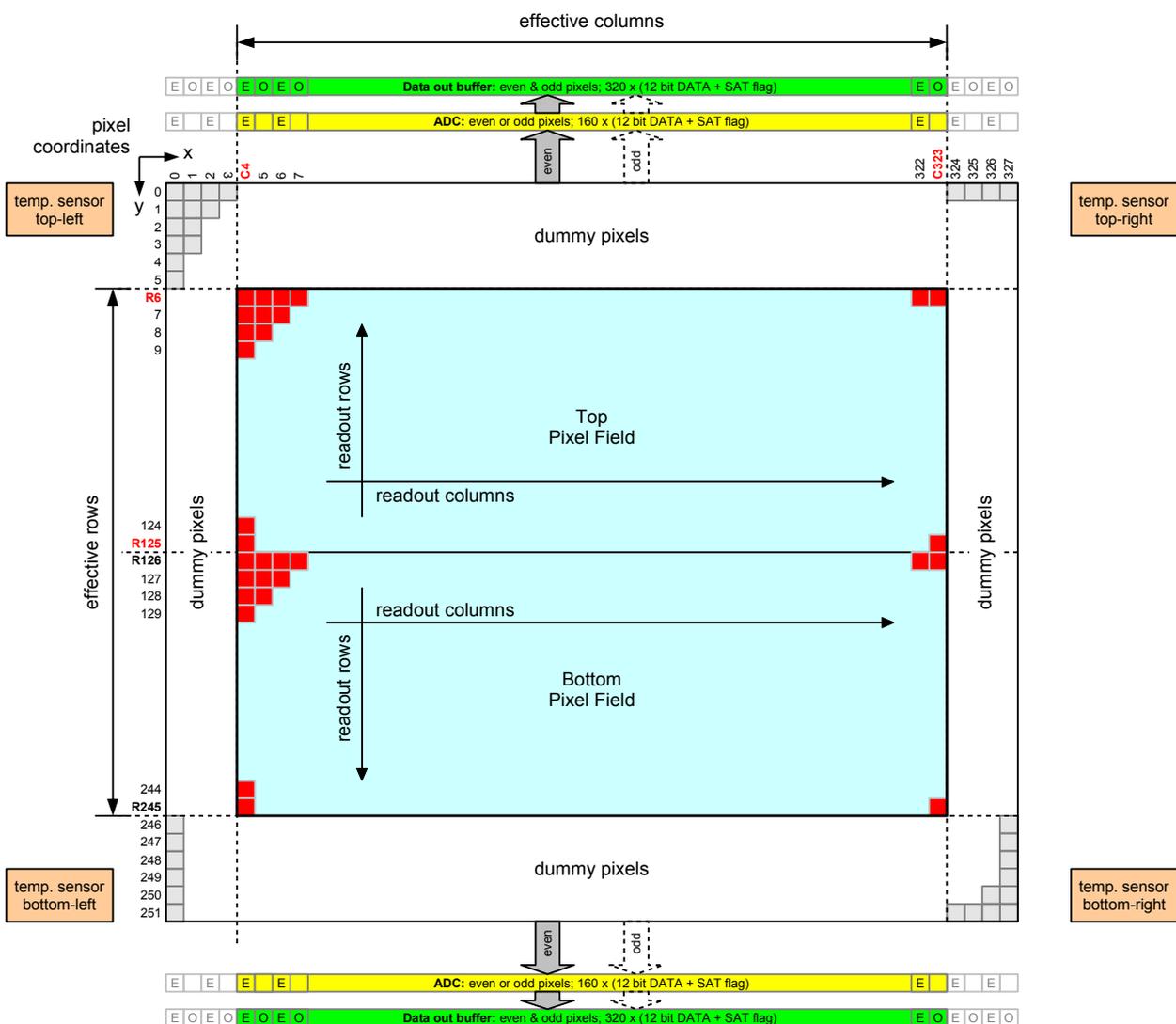


Figure 29: Pixel field coordinates with row and column numbering scheme (top-view, solder balls are bottom side)

### 5.6.2. Pixel architecture

The pixels are placed in groups 2x2 pixels, called herein "pixel group". The pixel group performs two basic operations: Measurement (integration) and readout (ADC). Pixels are named as UE (Upper-row, Even-column), UO (Upper-row, Odd-column), LE (Lower-row, Even-column) and LO (Lower-row, Odd-column) depending on their location within the pixel group (see Figure 29). Pixels with the same name are controlled simultaneously in the whole pixel field. More precisely, pixels in the upper and lower rows are controlled simultaneously during measurement, pixels in the even and odd columns are controlled simultaneously during readout.

The pixel group architecture allows the epc660 to operate the pixel field in different modes and in combinations thereof according to the following chapters.

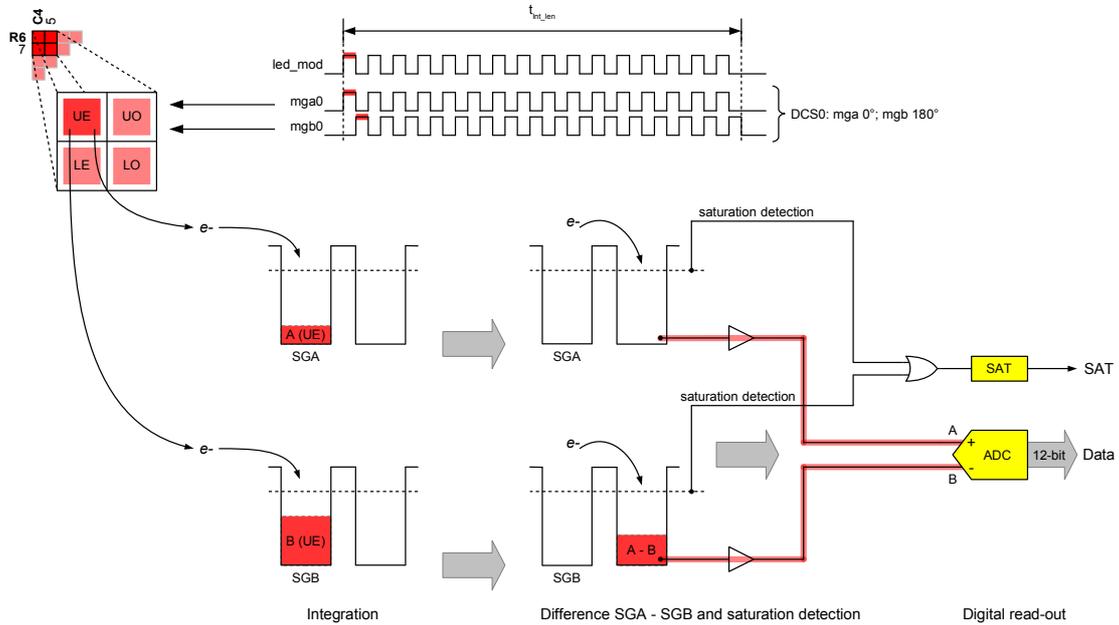


Figure 30: The 2x2 pixel group and the simplified function overview

Each pixel has its own pair of storage gates SGA and SGB. During the integration time, they accumulate the charges ( $e^-$ ) created by the reflected modulated light coming from the object (see section 6., Measurement Modes). They are controlled by the  $mga$  and  $mgb$  demodulation signals. After the measurement is finished, the readout phase starts. The charges stored in the storage gates SGA and SGB are read out as a difference  $A - B$  (ambient-light suppression) and converted into a single 12-bit digital value and a 1 bit saturation flag.

Depending of the operation mode the ADC readout is different:

- Differential mode: Used for 3D TOF sine and PN. It shows the difference of the two storage gate charges. Digital output values are signed values.
- Single-ended mode: Used for black & white images. It shows the charge of the selected storage gate. For the SGA readout the conversion result is a positive 11-bit value (except noise). For the SGB readout the conversion result is a negative 11-bit value (except noise).

**IMPORTANT:** The application software must take care about the negative (-) single ended sample value, accordingly.

### Single MGX mode (default)

When `dual_mgx_mode = 0`, all UE, UO, LE, LO storage gates work simultaneously during measurement operation. The storage gate control signals `mga`, `mgb` that are coming to all pixels are driven identically. In this mode, one DCS frame (0 ...3) is acquired at the time (see Figure 31).

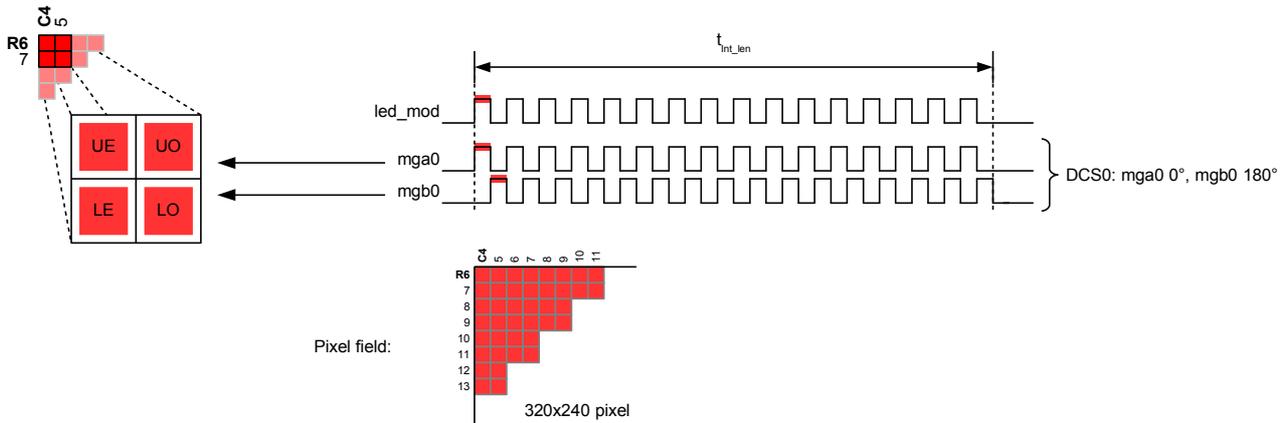


Figure 31: Single MGX mode: upper and lower pixel rows are controlled identically with `mgx0`

### Dual MGX mode with same integration time (motion blur reduction)

When `dual_mgx_mode = 1` and `int_len_mgx1_en = 0`, the UE, UO, LE, LO storage gate control signals `mgx` (`mga`, `mgb`) are generated as two independent groups as `mgx0` (`mga0`, `mgb0`) and `mgx1` (`mga1`, `mgb1`). As a result, two correlation frames DCS0 and DCS1 (or DCS2 and DCS3) can be acquired simultaneously (see Figure 32). The upper row pixels store DCS0 (or DCS2) while the lower row pixels store DCS1 (or DCS3). The vertical pixel pairs (e.g. UE/LE) must be treated for distance calculation as if they are one single pixel. This comes at the cost of a reduced resolution along the y-axis. The result provides a total of 320x240 pixel field readout with an effective 3D TOF resolution of 320x120 pixel.

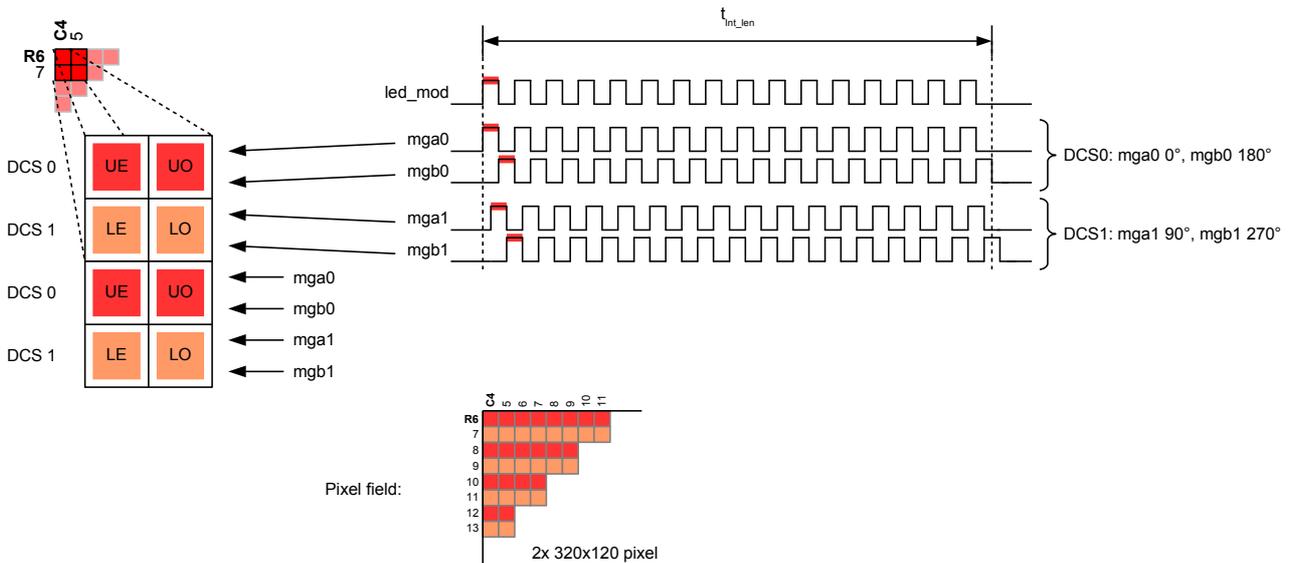


Figure 32: Dual MGX mode with same Integration time  
(upper and lower rows independently controlled by `mgx0` and `mgx1` with different phase shifts)

**IMPORTANT:** This mode requires an optical anti-aliasing filter (similar to a colour imager), so that adjacent pixels receive the same light. Otherwise, light from different locations cause 'zebra like' artefacts at the end of every strip.

### Dual MGX mode with different integration times (High dynamic range)

When `dual_mgx_mode = 1` and `int_len_mgx1_en = 1`, the UE, UO, LE, LO storage gate control signals `mgx` (`mga`, `mgb`) are generated as two independent groups as `mgx0` (`mga0`, `mgb0`) and `mgx1` (`mga1`, `mgb1`). Both groups provide exactly the same DCS modulation signals (phases). One stops earlier than the other due to different integration times (see Figure 33). The effect: As a consequence, the two pixels collect different amount of light simultaneously. There is no restriction about which integration time is shorter or longer with respect to the other. The upper row pixels integrate with `Int_len_hi/lo` register value, while the lower row pixels integrate with `Int_len_mgx1_hi/lo` value. The upper and lower pixels (e.g. UE, LE) can be used independently for distance calculation. This comes at the cost of a reduced resolu-

tion along the y-axis. Instead of one frame with 320x240 pixels, a single readout provides two DCS or black and white frames with an effective resolution of 320x120 pixels but with different integration times.

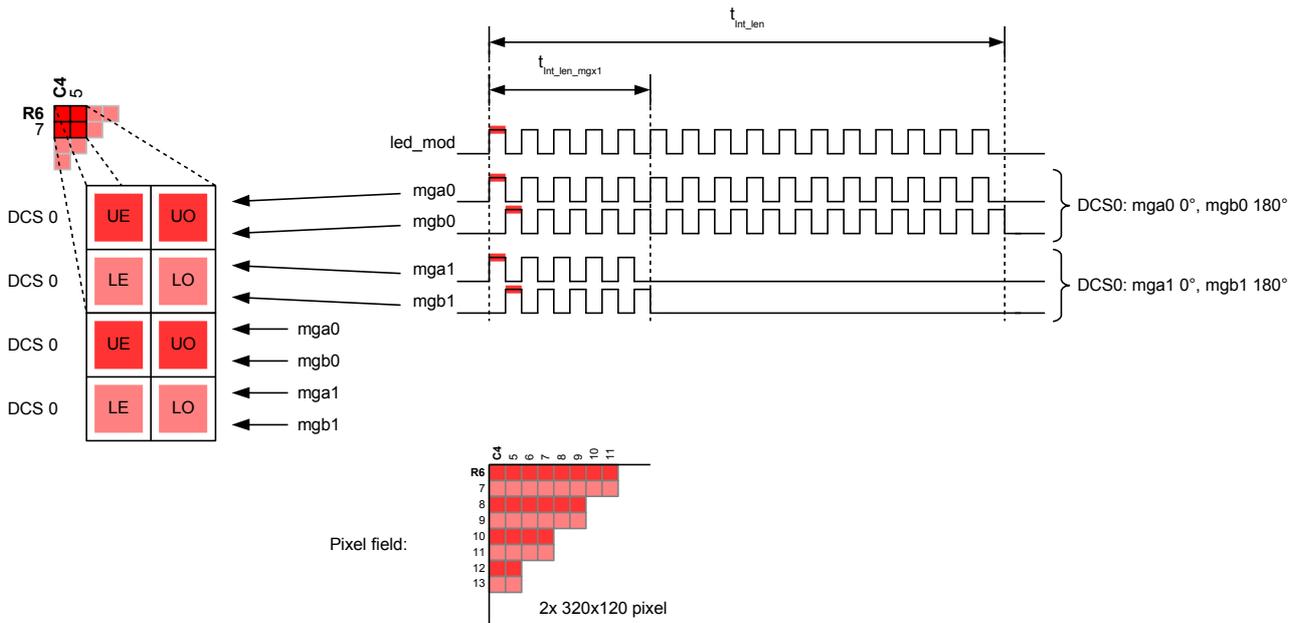


Figure 33: Dual MGX mode with different integration times (upper and lower rows independently controlled by mgx0 and mgx1. One stops earlier than the other)

### Pixel binning

The charges accumulated in the storage gates during measurement can be combined in various ways during the readout phase. This is called binning. There are three binning choices: horizontal, vertical, horizontal+vertical (see Figure 34). Advantages of binning can be: higher sensitivity, reduced integration time, better ratio signal to shot-noise and faster readout of frames (Note: TCMI data rate stays unchanged).

Binning modes require corresponding resolution reduction modes being enabled at the same time. Refer to Pixel operating and readout control registers, Resolution reduction, Table 42.

**IMPORTANT:** Pixel binning cannot be used with dual MGX modes.

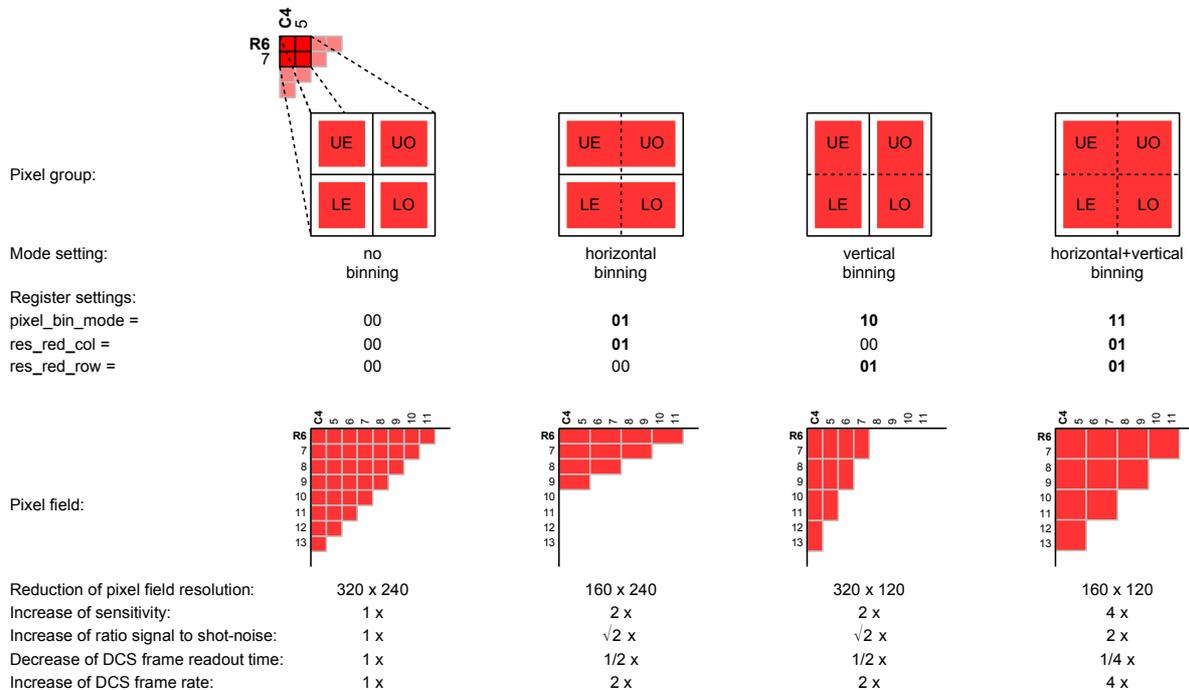


Figure 34: Overview pixel binning modes and readout

### 5.6.3. Pixel readout modes

#### Resolution Reduction

The aim of resolution reduction is to shrink the data set to the really necessary amount of data required for the application. The advantage is the reduced amount of data which has to be processed online for the final measurement result (reduced frame buffers, processing time and so on), shorter readout times for frames with short integration times and an increase of the achievable data rate.

Resolution reduction can be performed in terms of columns and rows, independently. Reductions by reading only every 2<sup>nd</sup> column on x-axis and every 2<sup>nd</sup>, 4<sup>th</sup> and 8<sup>th</sup> row on y-axis are supported. The resolution reduction can be combined with pixel binning modes (see chapter before Pixel binning), ROI (see next section) and Dual MGX modes (see Figure 35 - Figure 38 for valid combinations).

Note: Resolution reduction along x-axis is supported for every 2<sup>nd</sup> column only. This is required by the horizontal binning mode (see chapter Pixel binning). Reduction to 4<sup>th</sup> and 8<sup>th</sup> column only are not supported as they are not providing any frame rate improvement.

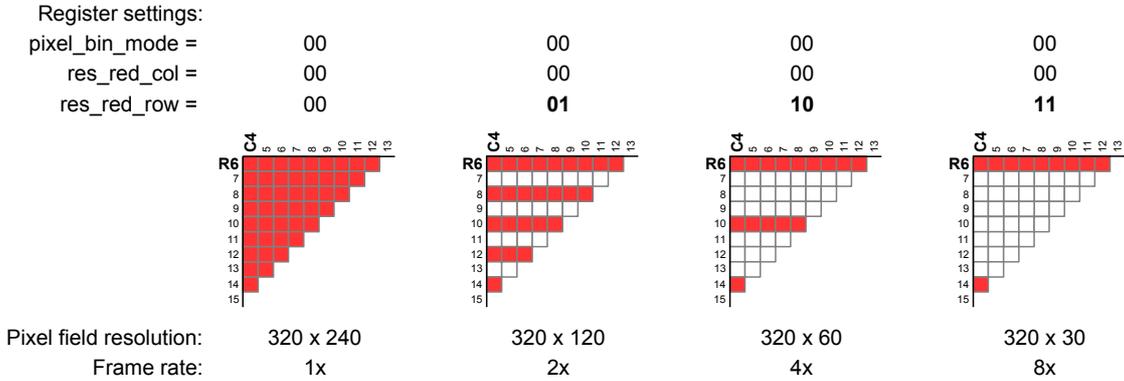


Figure 35: Resolution reduction of rows (y-axis) without binning

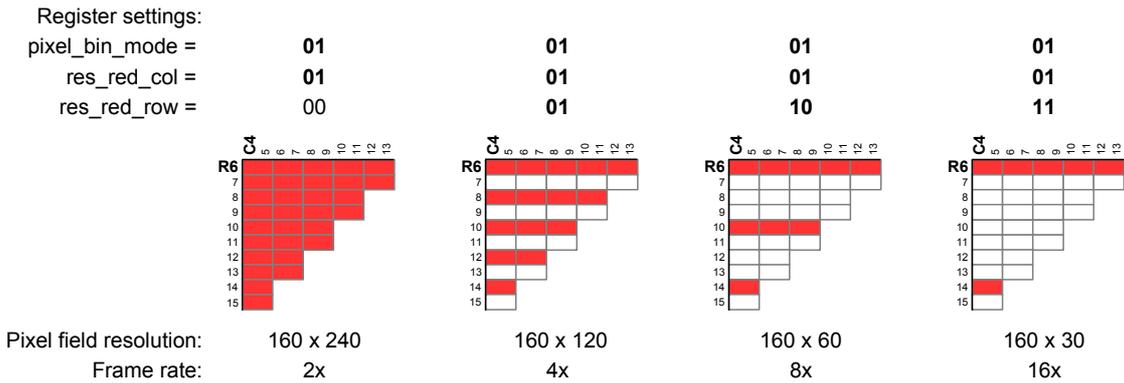


Figure 36: Resolution reduction of rows (y-axis) combined with horizontal binning

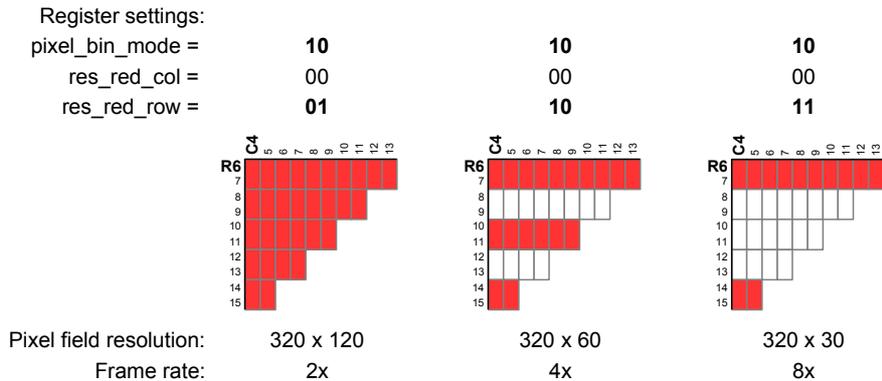


Figure 37: Resolution reduction of rows (y-axis) combined with vertical binning

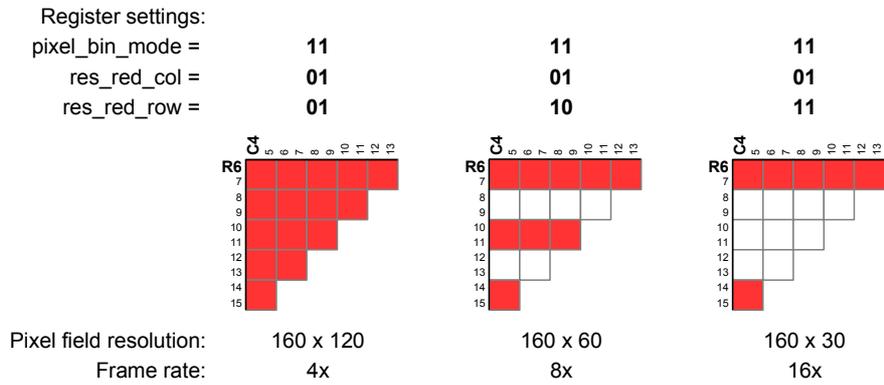


Figure 38: Resolution reduction of rows (y-axis) combined with horizontal and vertical binning

The resolution reduction modes can be mixed also with Dual MGX modes, either with Dual MGX mode with same integration time (motion blur reduction, see Figure 39) or with MGX mode with different integration times (high dynamic range, see Figure 40). For details of these two modes, refer to chapter 5.6.2, Pixel architecture.

**IMPORTANT:** Pixel binning cannot be used with dual MGX modes.

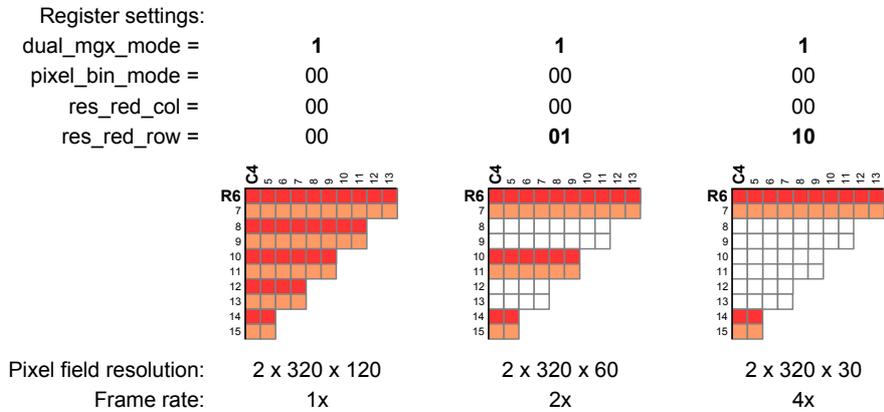


Figure 39: Resolution reduction of rows (y-axis) combined with dual MGX mode with same integration time (motion blur reduction)

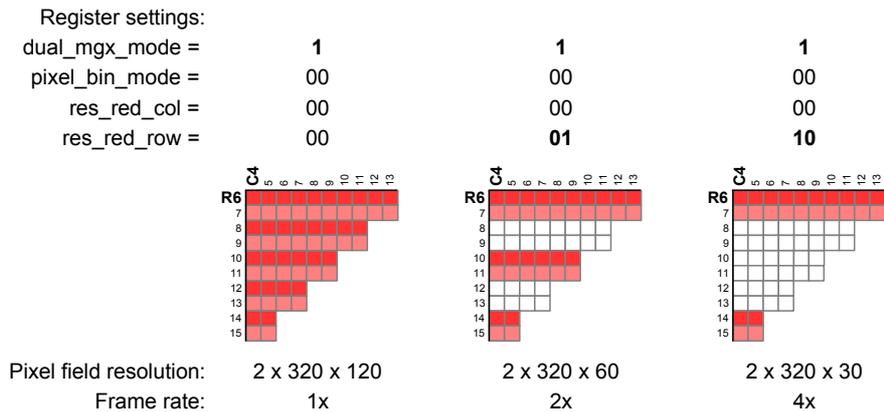


Figure 40: Resolution reduction of rows (y-axis) combined with dual MGX mode with different integration times (high dynamic range)

## ROI (Region of Interest)

The ROI feature allows to readout and transfer the portion of the pixel field data which is necessary for the application. The advantages are (same as for the resolution reduction) the reduced amount of data which have to be processed online for the final measurement result (Reduced data readout time, frame buffers, processing time and so on), also shorter readout times for frames with short integration times and so far an increase of the possible data rate. For integration times much shorter than the row conversion time (in the  $\mu\text{s}$  range, see Figure 42), the frame rate directly scales with the number of rows readout via ROI setting.

ROI is always operational and cannot be disabled. It works symmetrically over the top and bottom pixel fields. Therefore it must be set only in the top pixel field between the minimum top-left [C4,R6] and the maximum bottom-right [C323,R125] pixel coordinates (see registers ROI\_tl\_x\_hi/lo, ROI\_tl\_y, ROI\_br\_x\_hi/lo, ROI\_br\_y in Table 42, Frame column / row mapping registers). The symmetric part in the bottom pixel field is generated simultaneously and always.

The ROI must be set by the application always starting with even row and column and ending with odd row and column. Top-left coordinates must be smaller than the bottom-right.

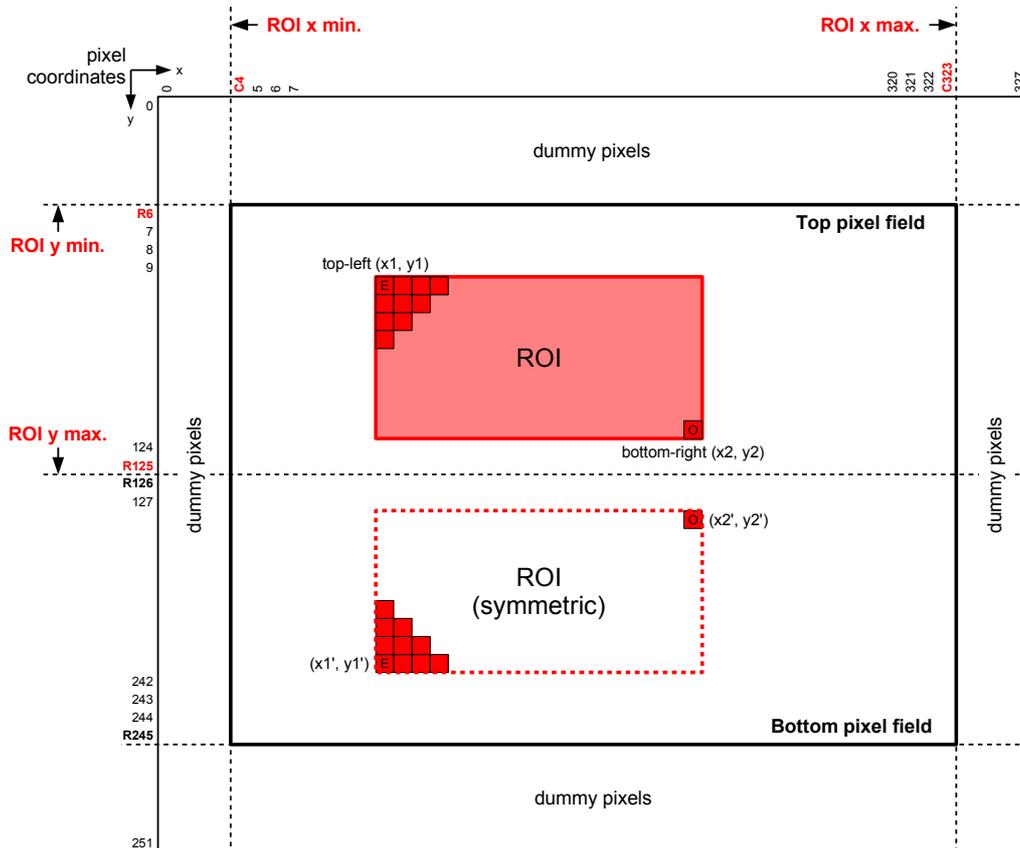


Figure 41: Region of interest (ROI)

The ROI registers can be changed on-the-fly via I<sup>2</sup>C without waiting the completion of current frame's readout cycle. The new values will be used immediately with the next frame. In parallel, the application must make sure that the frame buffers of the application are synchronized/readjusted to the new ROI frame size prior to data readout starts.

### IMPORTANT:

1. ROI can be set to a minimum rectangle of columns by rows of 6 by 2.
2. If row reduction is enabled, the minimum number of ROI rows is inversely scaled, e.g.: **row reduction by 2** makes the minimum ROI to 6 by **4**.
3. If column reduction is enabled, the minimum number of ROI columns is inversely scaled, e.g.: **column reduction by 2** makes the minimum ROI to **12** by 2.

Note: For the emulation of the epc635 refer to the application section: chapter 7.6.4., epc635 emulation.

#### 5.6.4. Pixel saturation detection

The pixels collect continuously modulated and non-modulated, ambient (background) light during the integration period. Depending on these light intensities, sometimes the pixels collect more charge (over-exposure) than they can accommodate in their storage gates (refer to Figure 30). In such a case, the 12 bit sample data is not valid and cannot be used. Therefore, each pixel generates a “saturation detection” flag along with the sample data, so that the data can be discarded by the application.

The saturation flag is generated in the pixel binning modes as well. It is set when one or more storage gates of the binned pixels is/are saturated or the sum thereof. Due to this architecture, two binned pixels cannot collect twice the full storage gate charge.

The saturation detection flag is transmitted via XSYNC\_SAT\_CFG pin synchronously to the DATA[11:0] for every 12 bit pixel sample. If XSYNC\_SAT\_CFG pin is programmed for an another function by setting tcmi\_xsync\_sat\_sel = 0 or not connected at all, tcmi\_data\_sat\_en = 1 can optionally drive all DATA[11:0] pins to 0xFFFF when the pixel is saturated (see TCMI\_polarity register in chapter 8.4., Table 42, TCMI registers). In this configuration, the application must discard those samples equal to 0xFFFF, otherwise use it for calculation.

#### 5.6.5. Ambient-light suppression

An important function of the 3D TOF pixel is the ability to separate the self-emitted and reflected modulated light from the ambient light. The built-in ambient-light suppression removes the DC or low frequent signal distortions, caused by foreign light sources e.g. sunlight, daylight, room illumination, etc., from the measuring signal. The user has not to take care of this, it is done by the pixel automatically by using only the charge difference of the storage gates (see Figure 30). To see the capability of this function, refer to Table 7 for example values as a function of the wavelength and compared to sunlight. Similar to the system's sensitivity of the modulated light, is the ambient-light suppression also a function of the integration time. The longer the integration time, the more the measurement becomes sensitive to the ambient-light.

Notes:

- The ambient-light suppression of the chip must not be confused with the ambient-light measurement. It is a fixed built-in functionality, which is removing the DC light component from the AC measurement signal only.
- A DC or AC photo signal can be generated by ambient-light (e.g. sunlight) or by cross-talk from the IR-LEDs. However, if this is above the stated maximum value, then the sensor or the input electronics are saturated. This blocks the detection of the AC modulation signal.

#### 5.7. Temperature Sensors

There are four temperature sensors located at the corners of the pixel field (Figure 29). They are not calibrated and reading the values as they are. Temperature sensor registers can be read on-the-fly via I<sup>2</sup>C interface while a frame acquisition is going on. Internal synchronization guarantees that always a valid temperature value is readout via I<sup>2</sup>C as long the following conditions are fulfilled:

Each sensor is sampled synchronously to the row readout cycles. Always four consecutive readings are summed up to the resulting 14 bit value written into the corresponding Sum\_Temp\_xx\_hi/lo registers (see Table 41, Temperature sensor registers). The update of the upper or lower temperature sensor values takes place every time, the corresponding pixel field half (top or bottom) has been row readout two times. Temperature sensors will be reset with every new frame start.

There will be not enough information to calculate the temperature value

- after a frame start until two row readout cycles are performed per half pixel field.
- or if the ROI and the binning are set such that less than two row readout cycles are performed per half pixel field and per frame.

## 5.8. TOF camera interface (TCMI)

The TCMI is a programmable high-speed parallel data output interface to off-load raw DCS (Differential Correlation Samples) data for all or part of the 320x240 pixel field (see chapter 5.6.) to an external application, e.g. to a DSP processor. It is programmable through the TCMI registers.

The TCMI interface provides:

- programmable active high/low logic levels on all clock and control signals individually (default: all active high).
- programmable output clock rates.
- 12-bit parallel output with 1 bit saturation flag.
- programmable 'ITU-R 656 like' synchronization options which allows easy connection to a wide variety of high-performance low-cost SoC embedded processors available in the market (supports hardware synchronization, but not embedded 0xFF/0x00 sync data packets)

When the integration period is terminated and all ADC conversions are finished, the readout results are moved into the data out buffers to be immediately transmitted via the TCMI interface to the outside of the chip. The parallel conversion of two full rows (top and bottom pixel field) takes in total 31.25µs independent of the number of selected columns.

Depending of the mode selection (4x DCS, 2x DCS, ...) a programmable number of DCS frames are generated by the epc660. The generated data is streamed out as a complete block of 1 DCS frame, one after the other following the procedure described in chapter 5.6. Each row contains 12-bit DCS values and the SAT bit for the selected number of pixels per row.

The pixel values are streamed out as 12 bit signed numbers. Two rows are streamed out in sequence together, the first one from the top and the second one from the bottom pixel field e.g. R125 (C4, C5, ... C323), R126 (C4, C5, ... C323), R124 (C4, C5, ... C323), R127 (C4, C5, ... C323), R6 (C4, C5, ... C323), R245 (C4, C5, ... C323) and so on. The stream-out of a row pair takes 16µs with default clock settings (40MHz TCMI clock rate).

Transmitting columns left to right or vice-versa can be changed by setting the bit `col_dir_sel` (see `Readout_dir **`, Table 42). The row readout direction cannot be changed.

The transfer of a DCS frame should not be interrupted or stopped, once it is started. The application should have enough bandwidth to receive all transmitted frames.

### 5.8.1. TCMI clock mode

The TCMI interface supports the continuous clock mode. It uses the internal `tcmi_clk` as a time base. The user must program the appropriate clock speed before running the TCMI interface. It is the output data transfer rate (refer to signal DCLK).

The frames are transmitted at high-speed using all `*SYNC` (`VSYNC_A0`, `HSYNC_A1`, `XSYNC_SAT_CFG`), `DATA[11:0]` and `DCLK` outputs (Figure 42).

The DCLK signal toggles continuously. The frequency is programmable to 10, 20, 40, 80MHz. The user application is responsible to set the correct clock rate in order to achieve the most efficient data acquisition throughput for the target application. The choice depends on user system factors such as e.g. application CPU/DSP's GPIO and/or bus speeds.

tcmi_clk_div (0x89)		
20MHz DCLK	40MHz DCLK	80MHz DCLK
[#]	[#]	[#]
2	1 <sup>1</sup>	0

Table 15: DCLK settings

<sup>1</sup> Note: Default setting 40MHz TCMI clock.

All `*SYNC*`, `DATA[11:0]` signals are synchronously updated with positive edge of the DCLK signal when its polarity is set as active-high; with negative edge of the DCLK signal when its polarity is set as active-low. The non-active edge of the DCLK output can be used by the receiving end (application CPU) as a sampling clock. It should approximately be in the center of the data.

By using the default configuration, the active states of `VSYNC_A0` and `HSYNC_A1` signals indicate blanking periods during the frame transmission. It is a legacy feature from the ITU-R 656 standard for video signal transmission. While DCLK toggles continuously, any data during the blanking periods are not valid and must be ignored.

As soon as the measurement result of the first row of the new frame is available, `VSYNC_A0` and `HSYNC_A1` are set consecutively with the next active edge of DCLK. `VSYNC_A0` is active from the start until the end of the each complete frame. Whereas, `HSYNC_A1` indicates the validity of the `DATA[11:0]` and `XSYNC_SAT_CFG` (saturation bit) from the start until the end of a row pair.

By default, the `XSYNC_SAT_CFG` pin is used for the saturation bit. Optionally, it can be programmed to indicate the end of a frame (`tcmi_xsync_sat_sel = 0`).

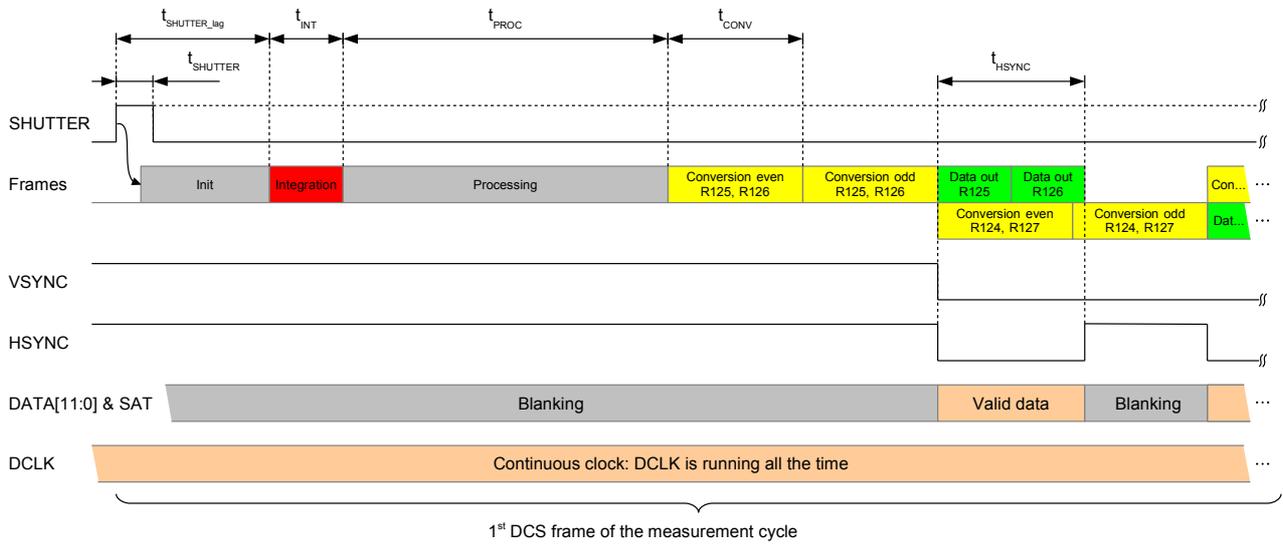


Figure 42: Frame timing: Start 1<sup>st</sup> DCS frame (DCLK: 40MHz)

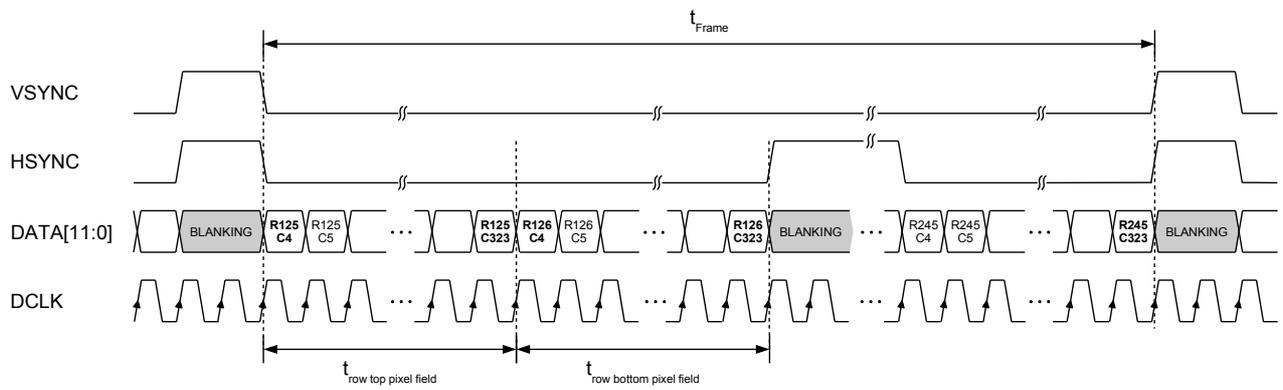


Figure 43: Data readout timing

## 5.8.2. Single or continuous measurement control

### Single measurement control

The selected measurement mode (4x DCS, 2x DCS, black & white, ...) defines, how many frames the chip performs by the stimulation of one SHUTTER pulse for a measurement cycle. This pulse can be applied either by the HW SHUTTER pin or by SW control of the shutter\_en bit. Whereas the SW controlled SHUTTER is auto-cleared after propagation, the HW Shutter needs a minimum hold time of 250ns and must be set back manually latest before the HSYNC\_A1 signal of the last row pair of the last DCS frame (last HSYNC\_A1 of the last frame).

During such a measurement cycle, the next frame acquisition starts immediately after the last data readout on the TCMI interface until all frames are performed.

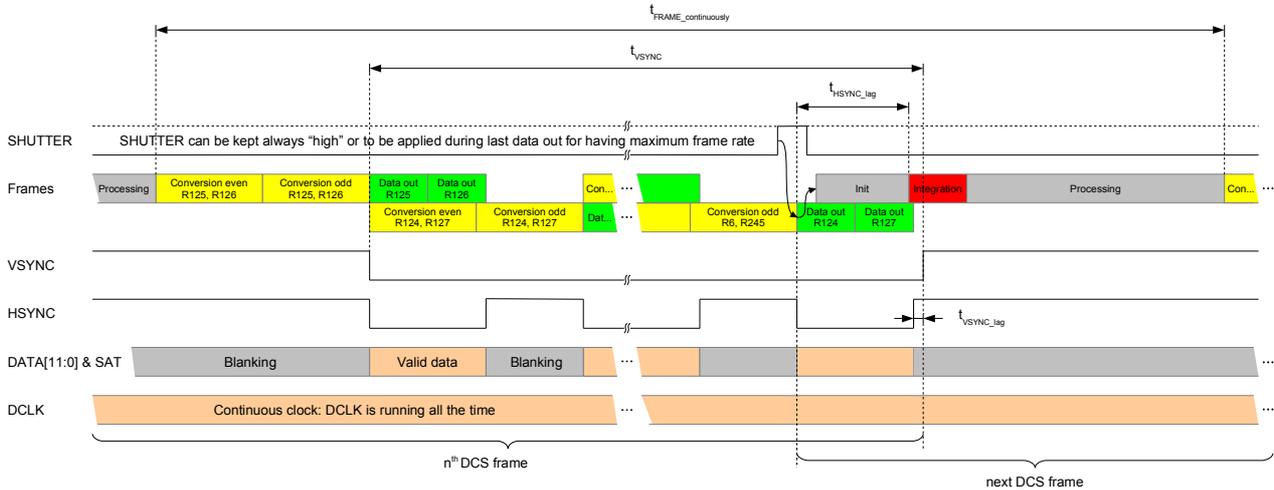


Figure 44: Frame timing: Inter frame timing, end of frame and start next frame (DCLK: 40MHz)

### Continuous measurement control (auto-run)

As long as in the Shutter\_Control register the multi\_frame\_en = 1 is set or the HW SHUTTER is applied during the readout of the last row pair of the last frame, the epc660 runs in a non-stop measurement mode. The chip starts immediately next measurement cycle if the actual one is terminated (Figure 44). If the trigger arrives before the readout of the last row pair of the last frame, then it is ignored.

### 5.8.3. Frame rates and data-out performance

#### Default QVGA frame and 3D TOF 4x DCS distance measurement

Frame rate:

The epc660 can perform a maximum of 262 fps (frames per second) in any mode with its full 320x240 pixel resolution (1µs integration time, 80MHz mod\_clk, 40MHz DCLK, DLL off, 4x DCS, continuous measurement control).

For 3D TOF, each frame is referred as a DCS frame. Either 4x (with π-delay matching) or 2x (without π-delay matching) DCS frames must be acquired for one distance calculation. Therefore, the resultant distance measurement rate turns out to be 65.5 fps or 131 fps respectively.

For the black & white mode the maximum frame rate applies: 262 fps.

The TCMI transfers during HSYNC a burst of 2 rows at the time, which gives 2row x 320pixel x 13bits/pixel = 8'320 bits or 640 samples (pixels) in every burst transfer. This gives a total burst duration (HSYNC) of 32, 16 and 8µs at f<sub>DCLK</sub> = 20, 40 and 80MHz respectively.

The data-out latency is defined as the time from the SHUTTER = 1 (or shutter\_en = 1 via I<sup>2</sup>C) to the first sample data coming out of the TCMI interface, refer to Figure 42. This is <69µs (excluding integration time). For 1 µs integration time, data-out latency is 69.8µs. Latency is fixed for all binning and resolution reduction modes.

The time of one full 320x240 pixel DCS frame is defined as the time from the SHUTTER = 1 (or shutter\_en = 1 via I<sup>2</sup>C) to the last sample data coming out of the TCMI interface. For 1 µs integration time, this frame time is 3'807µs/frame (262fps). Note, frame time gets shorter (frame rate gets faster) linearly with binning and resolution reduction modes for very short integration times.

Symbol	Parameter	Min.		Max.	Units
t <sub>DCLK</sub>	TCMI readout clock e.g. f <sub>DCLK</sub> = 40MHz		25		ns
t <sub>SHUTTER</sub>	Hold time for the signal on pin SHUTTER	250			ns
t <sub>SHUTTER_lag</sub>	Delay from the rising edge of SHUTTER signal to the 1 <sup>st</sup> LED pulse		18		µs
t <sub>INT</sub>	Image acquisition (integration time)				
t <sub>PROC</sub>	Delay from the last LED pulse until the 1 <sup>st</sup> row conversion		38.75		µs
t <sub>CONV</sub>	Conversion time for a pair of half rows (even or odd)		15.625		µs
t <sub>HSYNC</sub>	Readout time for a pair of rows e.g. f <sub>DCLK</sub> = 40MHz		16		µs
t <sub>HSYNC_lag</sub>	Delay from the begin of last readout until the 1 <sup>st</sup> LED pulse of next DCS frame		17		µs
t <sub>VSYNC_lag</sub>	Delay end of HSYNC to end of VSYNC at the end of each DCS frame		50		ns
t <sub>VSYNC</sub>	Data readout time for one DCS frame e.g. f <sub>DCLK</sub> = 40MHz t <sub>VSYNC</sub> = (2x t <sub>CONV</sub> x 119 rows) + t <sub>HSYNC</sub> + t <sub>VSYNC_lag</sub>		3'735		µs
	<b>Single measurement control mode:</b>				
t <sub>1st_FRAME_START</sub>	Delay from rising edge of SHUTTER signal until start of data readout of 1 <sup>st</sup> frame		3'824		µs
t <sub>1st_FRAME_TOTAL</sub>	Total time for reading one DCS or B&W frame from rising edge of SHUTTER signal until end of readout of 1 <sup>st</sup> frame		3'890		µs
	<b>Continuous measurement control mode:</b>				
t <sub>FRAME_continuously</sub>	Total time for reading one DCS or B&W frame t <sub>FRAME_continuously</sub> = (2x t <sub>CONV</sub> x 120 rows) + t <sub>HSYNC_lag</sub> + t <sub>INT</sub> + t <sub>PROC</sub>		3'807		µs
t <sub>4DCS_continuously</sub>	Total time for one 3D TOF distance measurement (4 DCS) t <sub>FRAME_continuously</sub> = ((2x t <sub>CONV</sub> x 120 rows) + t <sub>HSYNC_lag</sub> + t <sub>INT</sub> + t <sub>PROC</sub> ) x 4 DCS		15.23		ms

Table 16: Timings for one DCS or B&W frames and for 3D TOF distance measurements (4x DCS)  
(Reference: see Figure 42 and Figure 44, f<sub>DCLK</sub> = 40MHz, t<sub>INT</sub> = 1µs)

Note:

t<sub>init</sub>: In frame cycles having a DLL synchronization t<sub>init</sub> = 37µs + t<sub>SYNC</sub>. = 37µs + DLL pre-synchronization + DLL lock time e.g. t<sub>init</sub> = 77µs.

Action	Comments	Value	Units
DCS & B&W frame rate	1 DCS or B&W frame	262	fps
Distance measurement frame rate	4 DCS measurement	65.5	mps

Table 17: Frame rates based on the Table 16 timing  
(Continuous measurement control mode)

Memory space estimation:

The data-out operation transfers effectively 320x240pixel x 13bits/pixel (12 bit DATA + 1 bit SAT) = 998'400 bits per frame (~1Mbps) with each frame via the TCMI interface.

In a typical application with a CPU having a high-speed parallel interface (GPIO, CPI, CMI, etc.), each 13 bit sample can be packed into a 2 byte word, then stored in the application's frame buffer (internal SDRAM of the CPU or external SDRAM bridged via CPU). In that case, a burst (2 rows) makes 1'280 bytes. The frame acquisition including all rows/columns requires a storage space maximum of 153'600 bytes or 150kbyte per frame (1 kbyte = 1'024 bytes). For the 3D TOF distance measurements with 4 DCS, the application frame buffer must be large enough to accommodate at least 4 DCS frames plus (may be) another 1 DCS frame size to store back the calculated distance data. For a smooth SW programming, doubling this space is highly recommended as a bare minimum for the application frame buffer size. This corresponds to a total of 2 x (4 + 1) x 150 kbytes = 1'500kbytes (~1.5 Mbytes) memory space. In practice, this can be realized with a single 2 Mbyte (or 2x 1Mbyte) SDRAM. Depending on the complexity of the application SW, this size must be increased.

Balance between frame rate, resolution, measurement dynamic and memory space can be adjusted by combining binning, resolution reduction and ROI modes together.

There is a comparison in Table 18 below to give an overview on the performance figures (conditions: 1µs integration time, 1 DLL measurement every 100 frames) in different resolution reduction modes with ROI set to QVGA (default: 320 x 240 pixel).

Ref. Figure	Imager settings (Input)			Imager output		
	MGX mode <sup>1</sup>	Binning <sup>2</sup> hor., ver., both	Row reduction y-axis: 2, 4, 8	Resolution x-y [imager pixel]	Frame rate <sup>3</sup> [fps]	Frame size <sup>4</sup> [kbytes]
35	single	no	1	320 x 240	262	150
35	single	no	2	320 x 120	524	75
35	single	no	4	320 x 60	1'048	37.5
35	single	no	8	320 x 30	2'096	18.75
36	single	horizontal	1	160 x 240	524	75
36	single	horizontal	2	160 x 120	1'048	37.5
36	single	horizontal	4	160 x 60	2'096	18.75
36	single	horizontal	8	160 x 30	4'192	9.375
37	single	vertical	2	320 x 120	524	75
37	single	vertical	4	320 x 60	1'048	37.5
37	single	vertical	8	320 x 30	2'096	18.75
38	single	both	2	160 x 120	1'048	37.5
38	single	both	4	160 x 60	2'096	18.75
38	single	both	8	160 x 30	4'192	9.375
39	dual	no	1	2 x 320 x 120	262	150
39	dual	no	2	2 x 320 x 60	524	75
39	dual	no	4	2 x 320 x 30	1'048	37.5

Table 18: Frame rate and resolution versus different modes of operation for default QVGA mode  
Default ROI setting: 320 x 120 pixel: top-left (4, 6) and bottom-right (323, 125)

Notes:

- <sup>1</sup> When dual MGX mode is turned on, resolution, frame rate and frame size are identical for both MGX modes (same integration time, motion blur reduction or with different integration times, high dynamic range).
- <sup>2</sup> Dual MGX mode and binning together is not possible.
- <sup>3</sup> Frame rate is the DCS frame rate.
- <sup>4</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the application frame buffer.

### Half QQVGA frame (160x60 pixel)

The second example shows the ROI set symmetrically to 2 x 160 x 30 (Half-QQVGA) in the middle of the pixel field.

The frame time scales linearly with the reduced number of rows readout (see Table 19).

The TCMI data-out time scales linearly with the reduced number of columns set in the ROI.

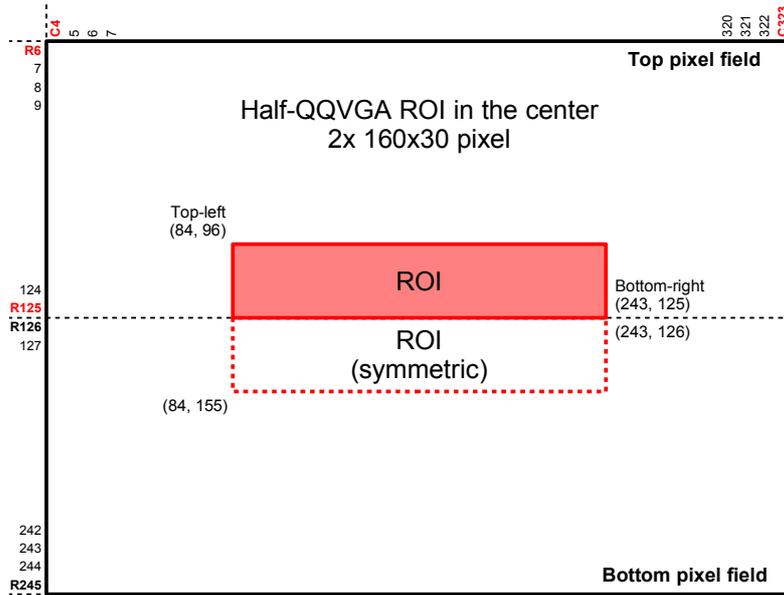


Figure 45: ROI for Half-QQVGA: 2 x 160 x 30 pixel

Ref.	Imager settings (Input)			Imager output		
Figure	MGX mode	Binning <sup>1</sup> hor., ver., both	Row reduction y-axis: 2, 4, 8	Resolution x-y [imager pixel]	Frame rate <sup>2</sup> [fps]	Frame size <sup>3</sup> [kbytes]
35	single	no	1	160 x 60	1'048	18.75
35	single	no	2	160 x 30	2'096	9.375
36	single	horizontal	1	80 x 60	2'096	9.375
36	single	horizontal	2	80 x 30	4'192	4.6875
37	single	vertical	2	160 x 30	2'096	9.375
38	single	both	2	80 x 30	4'192	4.6875
39	dual	no	1	2 x 160 x 30	1'048	18.75

Table 19: Frame rate and resolution versus different modes of operation for default Half-QQVGA mode  
ROI setting: 160 x 30 pixel: top-left (84, 96) and bottom-right (243, 125)

Notes:

<sup>1</sup> Dual MGX mode and binning together is not possible.

<sup>2</sup> Frame rate is the DCS frame rate.

<sup>3</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the application frame buffer.

Note: For the emulation of the epc635 refer to the application section: chapter 7.6.4., epc635 emulation.

### 5.8.4. Example applications of CPU architectures for high-speed frame data transfer

Several possible application CPU, DSP, FPGA configurations can be used with the epc660. Here are two architectures proposed as examples, to give the application developer a high-level overview.

The first one is a completely symmetric, non-blocking application frame buffer CPU architecture with a high-throughput imager to application frame buffer data transfer concept. While the frame is continuously acquired, the current frame data is streamed from the epc660 to the application frame buffer A. At the same time, the CPU can access and calculate the previously acquired data from the application frame buffer B. The next frame, the memory channels are dynamically swapped between epc660 and the CPU by re-configuring the DMA channels. As there are two physically identical, separated memory channels, both transfers can flawlessly happen at the same time (see Figure 46).

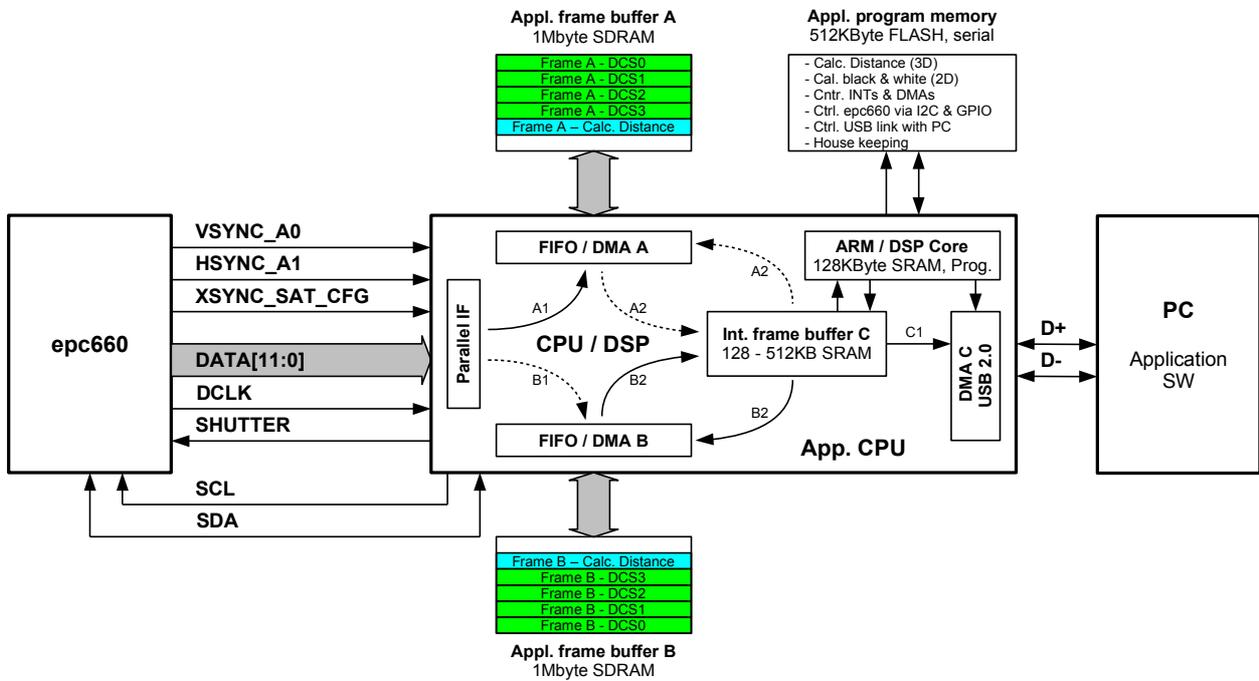


Figure 46: Symmetric, non-blocking application frame buffer CPU architecture

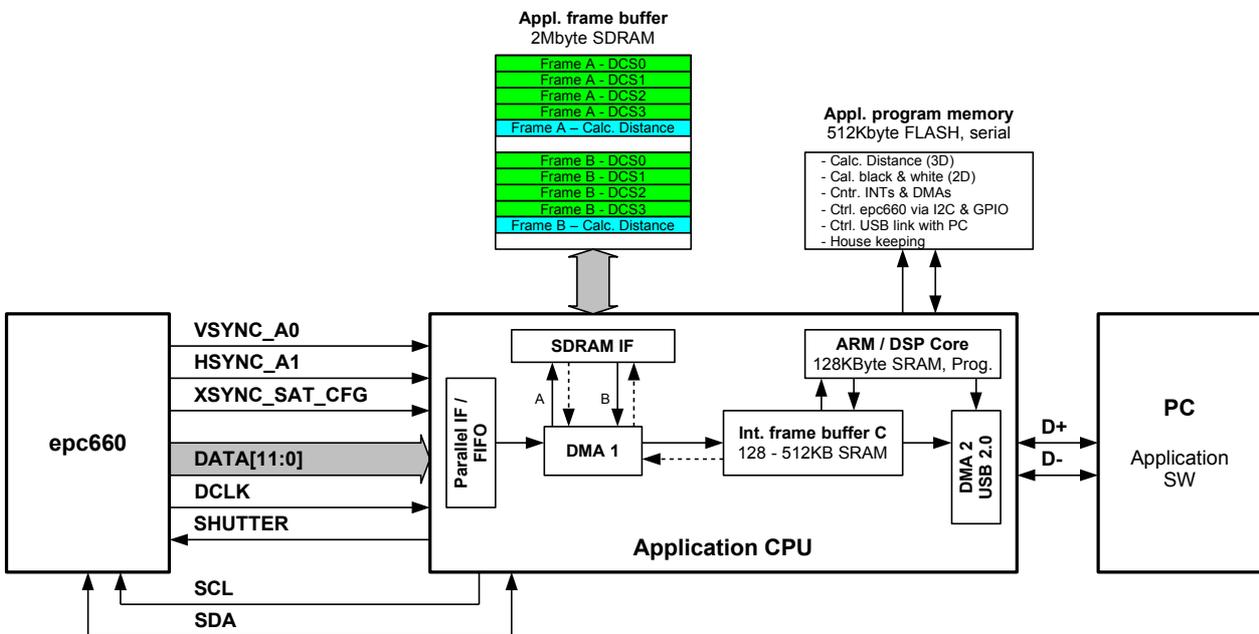


Figure 47: Time-shared application frame buffer CPU architecture

The second example is a time-shared application frame buffer CPU architecture. The epc660 must have a higher priority over CPU (see Figure 47) when accessing the application frame buffer SDRAM. The memory is blocked to the CPU as long as epc660 is transferring the burst. At the end of the burst, the memory channel is released by the DMA controller and the CPU gets access granted. In the time-shared bus architecture, the application developer must carefully tune the bus access ratio between the epc660 and the CPU. This can be adju-

ted by setting a different TCMI DCLK frequency (20, 40 or 80MHz) on the epc660 side. The higher the TCMI bus frequency, the faster the burst is transmitted (min. burst duration for full pixel rows:  $8\mu\text{s}$  at  $f_{\text{DCLK}} = 80\text{MHz}$ ).

Another option is using a CPU having a much wider and faster SDRAM interface. Example:

Assume using a CPU which has a 128 bit wide SDRAM bus running at 160MHz clock. The TCMI DCLK is set at 40MHz. This gives 4x performance increase between FIFO → application SDRAM due to the TCMI to SDRAM bus clock ratio. Another 8x increase is due to 16-bits packed samples in the FIFO and transferred over a 128 bit wide bus to the SDRAM. It results in a total of 32x faster transfers between FIFO → application SDRAM, application SDRAM → internal SRAM of the CPU and vice-versa. This gives a lot of bandwidth to the CPU to transfer data back and forth between the application SDRAM and the internal SRAM between computations.

### 5.9. Power consumption levels

The epc660 has mainly 7 power states/levels during the different operation phases. RESET state is the lowest, INTEGRATE is the highest average power consumption level.

Power state	Power [mW]	Operation description
RESET	54	All supplies are ON, $\overline{\text{RESET}} = 0$ , Oscillator is ON, PLL and all system system clocks are OFF
READY	81	$\overline{\text{RESET}} = 1$ , PLL and all system clocks ON, waiting for SHUTTER
INTEGRATE	1'300	SHUTTER = 1 or shutter_en= 1 via I <sup>2</sup> C, integrating
CONVERSION	580	Integration finished, conversion of rows
CONVERSION + DATAOUT	555	Transmit row data via TCMI while converting next row
DATAOUT	110	Transmit last row data via TCMI

Table 20: Typical average power consumption levels at different operating states (integration time < 5ms)

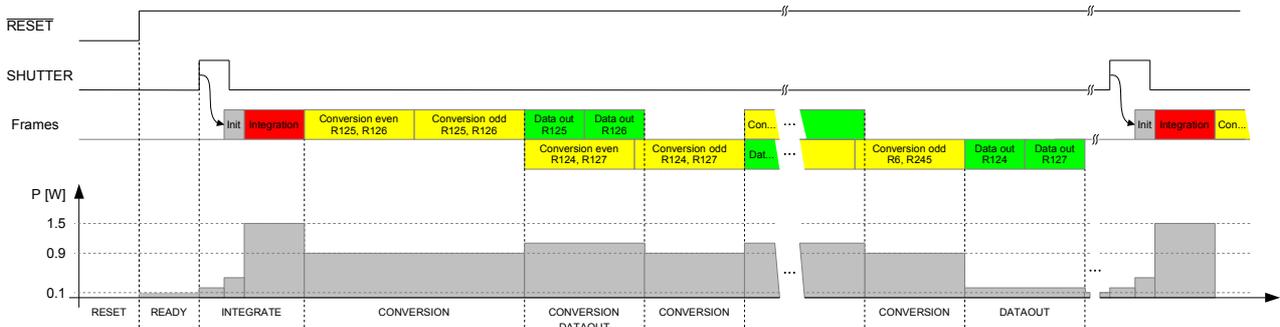


Figure 48: Power consumption levels and operating states

## 6. Measurement Modes

### 6.1. Distance Measurement Modes (3D TOF)

The distance measurement modes use the on chip LED driver and the external IR-LED/LD to provide modulated light on the target. Modulation control signals to the LED driver are provided by the programmable modulator (see chapter 6.1.1.). Two modulation sequences are supported: Sine mode and PN mode.

Sine mode can be used for single camera environments. PN mode can be used for multi-camera environments.

#### 6.1.1. Modulator

The modulator (see Figure 27) generates all signals to modulate the external IR-LED/LD via the LED driver and simultaneously all demodulation signals to the pixel field for performing a measurement. Sine, PN and black & white mode with all the variants are generated here.

The mode selection takes place by the modulation table registers (refer to Table 41). More details to these modes are listed in following the chapters and in Table 26. The registers can be updated via I<sup>2</sup>C bus between the frame acquisitions. The application must take care that the last frame's integration phase is completed before modifying these registers on the fly. This time can be detected by the application by waiting for the falling-edge of VSYNC or the first falling-edge of HSYNC signal after SHUTTER = 1 was applied. This allows to run continuously at the maximum frame rate. For a full-frame readout, the margin is a 3.6ms to alter these registers via I<sup>2</sup>C on the fly. This margin scales linearly with the number of row readouts.

#### 6.1.2. Sine mode (Sinusoidal modulation)

The epc660's default modulation mode is the sinusoidal modulation. After reset, all internal register values are default to operate the chip: at 4MHz XTAL/external clock input, multiplied up to 80MHz at the PLL output, clocks the modulator with 80MHz internal mod\_clk, modulates LED/LD with 20MHz and acquires 4 successive DCS frames (0 ... 3) using 25.6µs integration time.

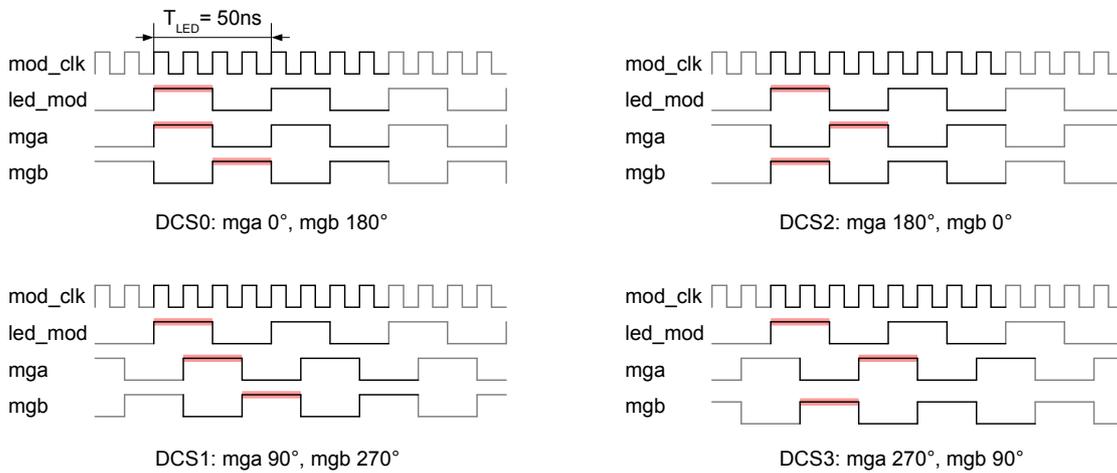


Figure 49: Sine mode 4x DCS modulation/demodulation waveforms (mod\_clk = 80MHz)

With the application of the shutter trigger pulse (HW SHUTTER = 1 or SW shutter\_en = 1 via I<sup>2</sup>C), the chip performs 4 successive DCS (Difference Correlation Sample) frame acquisitions. Each one of the 4 DCS frame types has a different phase relation between modulation (led\_mod) and demodulation (mga, mgb) signals which makes phase-to-distance calculation possible. In case of DCS0, led\_mod is phase-shifted by 0° and 180° with respect to mga and mgb, respectively. In case of DCS1, led\_mod is phase-shifted by 90° and 270°. For DCS2, the phase shifts are 180° and 0° and for DCS4, the phase shifts are 270° and 90° (see Figure 49). Note that for DCS2 and DCS3, the demodulation signals mga and mgb are simply swapped with respect to DCS0 and DCS1, respectively.

By programming dcs\_sel = 01 (see MOD\_Control register in Table 42, Modulator/demodulator registers), shutter trigger initiates 2 successive DCS frame acquisitions (see Figure 50).

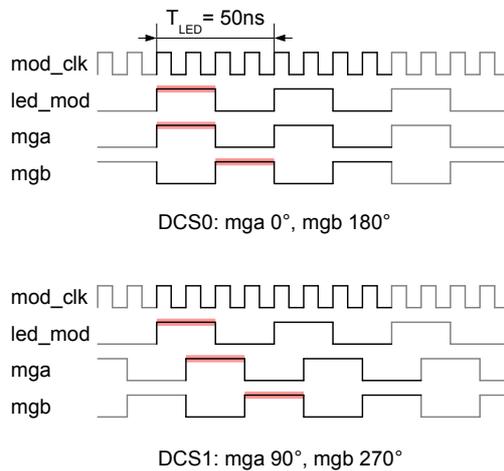


Figure 50: Sine mode 2x DCS modulation/demodulation waveforms (mod\_clk = 80MHz)

The first sample pair (DCS0 and DCS1) is enough to calculate 3D TOF distance for that pixel. The second pair (DCS2 and DCS3) can be used for calculating the  $\pi$ -delay matching algorithm to compensate for fixed pattern noise and device mismatches during pixel readout operation. The application SW must run the same algorithm on every pixel to compute the 3D TOF distance for the entire pixel field.

**Sine mode: Distance calculation algorithm**

The use of the atan definition of the Cartesian coordinate system (atan2) guarantees a continuous distance calculation algorithm in the range of phases between  $-\pi \dots +\pi$ . In our case, we use the range from  $0^\circ \dots 360^\circ$  which corresponds to the distance from 0m up to the unambiguity distance.

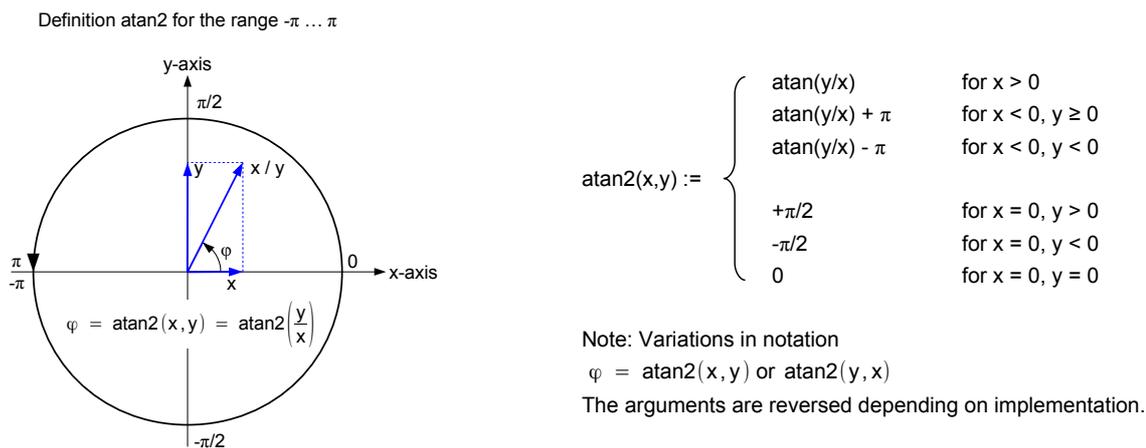


Figure 51: Continuous atan representation for the range  $-\pi \dots +\pi$

Let the respective 12 bit samples measured for a single pixel from 4 DCS (0, 1, 2, 3) frames be DCS0, DCS1, DCS2 and DCS3. Thereof, the sampling of 4x DCS samples corresponds to the following sinusoidal signal representation for the epc660 chip:

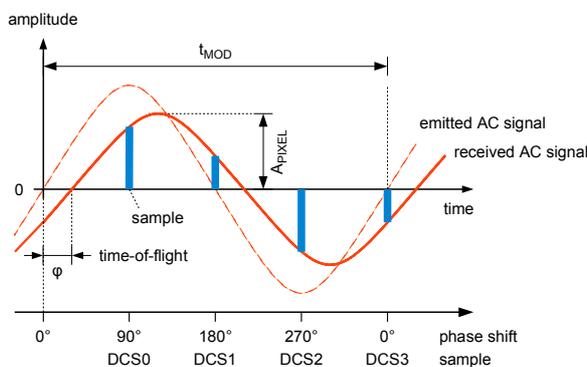


Figure 52: Sampling of the received waveform

The following terms are used for the formulas:

$D_{TOF\ sine}$	Distance in meters [m]
$c$	Speed of light e.g. 300'000'000m/s
$f_{LED}$	LED/LD modulation frequency e.g. 20MHz
DCS0 - DCS3	Sampling amplitude [LSB]
$\varphi$	Phase shift caused by the time-of-flight [rad]
$D_{OFFSET}$	Offset compensation [m]

In the real case of 4x DCS samples used with  $\pi$ -delay matching algorithm, the time of flight calculation will be:

$$[1] \quad t_{TOF\ sine} [\text{sec}] = \frac{1}{2\pi f_{LED}} \cdot [\pi + \text{atan2}(DCS2 - DCS0, DCS3 - DCS1)] + t_{OFFSET}$$

then, the distance calculation will be (c is the speed of light):

$$[2] \quad D_{TOF\ sine} [\text{m}] = \frac{c}{2} \cdot \frac{1}{2\pi f_{LED}} \cdot [\pi + \text{atan2}(DCS2 - DCS0, DCS3 - DCS1)] + D_{OFFSET}$$

Based on the ideal case of 2x DCS samples (without any offsets), the time of flight may be computed as follows:

$$[3] \quad t_{TOF\ sine} [\text{sec}] = \frac{1}{2\pi f_{LED}} \cdot [\pi + \text{atan2}(-DCS0, -DCS1)]$$

then, the distance calculation is:

$$[4] \quad D_{TOF\ sine} [\text{m}] = \frac{c}{2} \cdot \frac{1}{2\pi f_{LED}} \cdot [\pi + \text{atan2}(-DCS0, -DCS1)]$$

#### Sine mode: Quality of the measurement result

The epc660 provides information on the quality and the validity of the received optical signal. This reflects the confidence level of the measurement result. The better the received signal, the better and more precise the distance measurement will be.

Each distance measurement of every pixel has its own validity and quality.

The primary quality indicator for the measured distance data is the peak-to-peak amplitude value of the received modulated light  $A_{TOF\ sine\ PP}$ .

After each measurement, this needs to be calculated from the DCSx values delivered by the chip. This amplitude value is the feedback parameter that is used to set the integration time for the next measurement.

$$[5] \quad A_{TOF\ sine\ PP} = \sqrt{\frac{(DCS0 - DCS2)^2}{4} + \frac{(DCS3 - DCS1)^2}{4}}$$

Amplitude $A_{TOF\ sine\ PP}$	Classification	Action
< 25 LSB	Weak illumination	Too less signal for an accurate measurement: Increase integration time for the next measurement
25 ... 100 LSB	Enough signal for a useful measurement	Distance noise approx. 4 times higher than the optimum: No action necessary. See note below
100 ... 1'200 LSB	Good signal strength	No action necessary. See note below
> 1'200 LSB	Overexposed	Decrease integration time for the next measurement. See note below

Table 21: Signal amplitude versus classification

Note:

Generally, the higher the received signal, the better and more precise the distance measurement will be. However, it is good practice to control the integration time such that an amplitude value between 100 ... 200 LSB is achieved. Higher values will only slow down the acquisition rate due to longer integration times, but are not significantly improving signal to noise ratio.

The quality indicator for the distance noise is the ratio of ambient-light  $E_{BW}$  to the peak-to-peak value of modulated light  $E_{TOF\ PP}$  (AMR). This value may be calculated and used additionally to the above amplitude value if the respective application is subject to intense ambient light.

The peak-to-peak irradiance  $E_{TOF\ sine\ PP}$  of the modulated signal at the surface of a pixel can be calculate out of the AC sensitivity  $S_{TOF\ sine}$ , the used integration time  $t_{INT-TOF}$ , the reference integration time  $t_{INT-REF-TOF}$  and the peak-to-peak amplitude  $A_{TOF\ sine\ PP}$  of the received modulated signal the following way:

$$[6] \quad E_{TOF\ sine\ PP} = S_{TOF\ sine} \cdot \frac{t_{INT-REF-TOF}}{t_{INT-TOF}} \cdot A_{TOF\ sine\ PP} \quad \text{e.g.} \quad E_{TOF\ sine\ PP} = 155 \frac{\text{nW/cm}^2}{\text{LSB}} \cdot \frac{103\mu\text{s}}{205\mu\text{s}} \cdot 1'000 \text{ LSB} = 78\mu\text{W/cm}^2$$

The formula to calculate the quality indicator “Ratio of ambient-light / modulated light” (AMR) is

$$[7] \quad \text{AMR[dB]} = 20 \cdot \log\left(\frac{E_{\text{BW}}}{E_{\text{TOFPP}}}\right) \quad \text{e.g.} \quad \text{AMR[dB]} = 20 \cdot \log\left(\frac{3.96 \text{ mW/cm}^2}{78 \mu\text{W/cm}^2}\right) = 34 \text{ dB}$$

Refer for  $E_{\text{BW}}$  to chapter 6.2. Black & white mode.

This ratio is one of the influencing factors regarding the distance noise.

AMR value	Classification	Action
< 60 dB	excellent	No action necessary.
< 70 dB	sufficient	Is a lower noise level needed, do the next measurement with a longer integration time or with an increased illumination power.
> 70 dB	weak	Do the next measurement with a longer integration time or with an increased illumination power.

Table 22: Classification ratio ambient-light to modulated light (AMR) versus distance noise

There are also validity indicators delivered by the chip after a measurement. These will help to detect saturated or not illuminated pixels as a result of too much/less illumination or too long/short integration time.

Validity indicator (per pixel)	Classification	Action
Saturation flag: = set	Pixel saturation: The pixel receives too much light (too much modulated light-signal, too reflective object or too much ambient-light) Refer to chapter 5.6.4. Pixel saturation detection and pin XSYNC_SAT_CFG.	Dump data and repeat the measurement with a decreased integration time or measure the ambient-light.
one or more of the DCSx values:   DCSx   > 1'200 LSB	DCSx value over maximum signal limit: The object is too reflective( It is too close to the sensor, there is too bright illumination or too much modulation signal is emitted)	Dump data and repeat the measurement with a decreased integration time.
all DCSx values:   DCSx   ≤ 25 LSB	DCSx values below noise level limit: Absence of an object in the operating range. The object has too little remission (reflectivity): It is too far away, the illumination is too dim or too little modulation signal is emitted)	Dump data and repeat the measurement with an increased integration time.

Table 23: Validity indicator versus classification

Table 23 shows a quality decision matrix as a summary of the validity and quality parameters for the distance measurement.

Step	Sensor status	Pixel saturation XSYNC_SAT	Maximum signal min. one   DCSx	Noise level all   DCSx	Modulated light amplitude $A_{\text{TOFPP}}$	Ratio ambient to modulated light AMR	Action
1	Saturation or bright object within scene	flag set					Repeat measurement with decreased integration time and/or illumination
2	Saturation or bright object within scene	no	> 1'200 LSB				Repeat measurement with decreased integration time and/or illumination
4	No object detected	no	< 1'200 LSB	< 25 LSB			Repeat measurement with increased integration time or illumination
3	Overexposure or bright object within scene	no	< 1'200 LSB	> 25 LSB	> 1'200 LSB		Repeat measurement with decreased integration time or illumination
4	No object detected	no	< 1'200 LSB	> 25 LSB	< 25 LSB		Repeat measurement with increased integration time or illumination
5	Too much ambient-light	no	< 1'200 LSB	> 25 LSB	25 LSB ... 1'200 LSB	> 60 db (or > 70 dB)	Repeat measurement with increased integration time or illumination
6	Object detected	no	< 1'200 LSB	> 25 LSB	Good: 100 ... 1'200 LSB Enough: 25 ... 100 LSB	< 60 db (or < 70 dB)	No action necessary

Table 24: Quality decision matrix

### 6.1.3. PN mode (Pseudo-random Noise modulation)

The epc660's PN mode is initialized via the MOD\_Control register, setting the mod\_sel = 01. This activates the PN mode to create pseudo-random 0s and 1s sequences to the modulator to drive the led\_mod modulation signal and mga, mgb demodulation signals.

In a multi-camera application, if all cameras are triggered at the same time (i.e. same signal drives all SHUTTER inputs on the PCB), each one must be initialized with a different type/length of PN sequence.

Similar to sine mode, the modulator generates 4 different DCS frames using the pseudo-random sequences (see Figure 53).

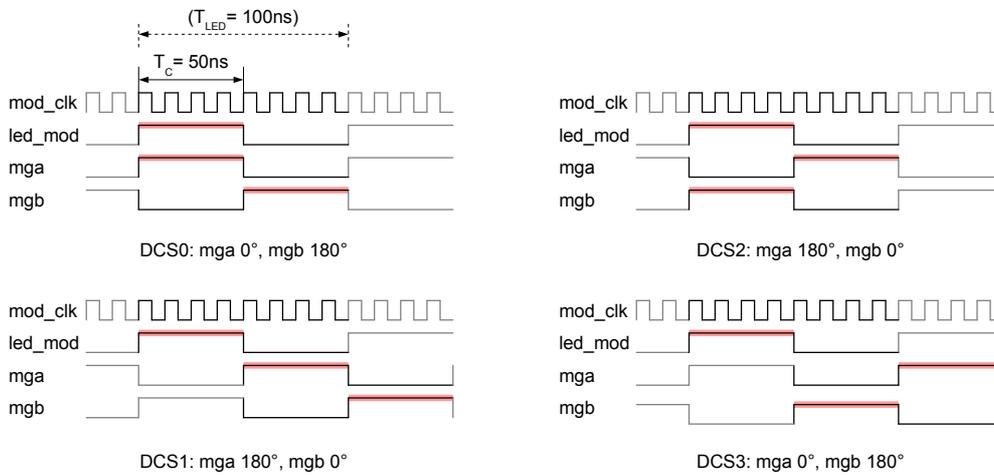


Figure 53: PN mode 4x DCS modulation/demodulation waveforms (mod\_clk = 80MHz)

By programming dcs\_sel = 01 (see MOD\_Control register in Table 42, Modulator/demodulator registers), shutter trigger initiates 2 successive DCS frame acquisitions (see Figure 54).

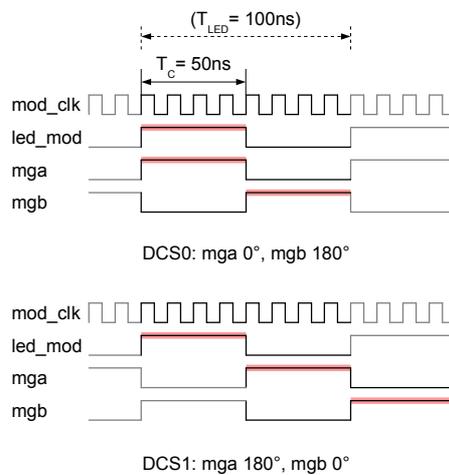


Figure 54: PN mode 2x DCS modulation/demodulation waveforms (mod\_clk = 80MHz)

**PN mode: Distance calculation algorithm:**

**Functionality**

Theoretically, the distance information can be obtained through the measurement of two orthogonal correlation values  $C_0$  and  $C_1$ . The acquisition timing and processing of the correlation samples depend on the type of modulation that is implemented. If PN modulation is used, the two samples are acquired at time  $t$  and  $t+T_c$ .  $T_c$  is the "chip period" (1 bit / fraction period) of the PN modulating sequence. The minimum integration time or the step for larger integration times is equal to the PN sequence length.

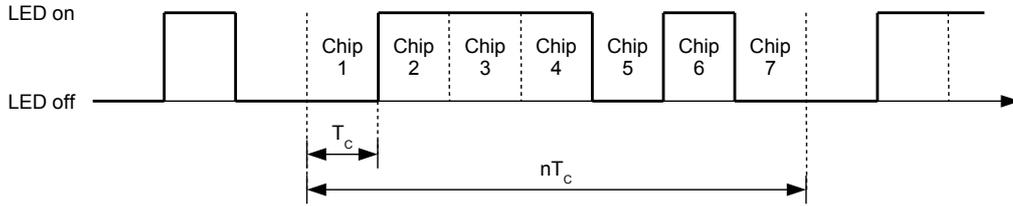


Figure 55: Example of PN modulation sequence  
Maximal PN sequence length of  $n = 7$  chips,  
 $T_c$ : Chip period,  
 $nT_c$ : Duration of a PN sequence = basic integration time

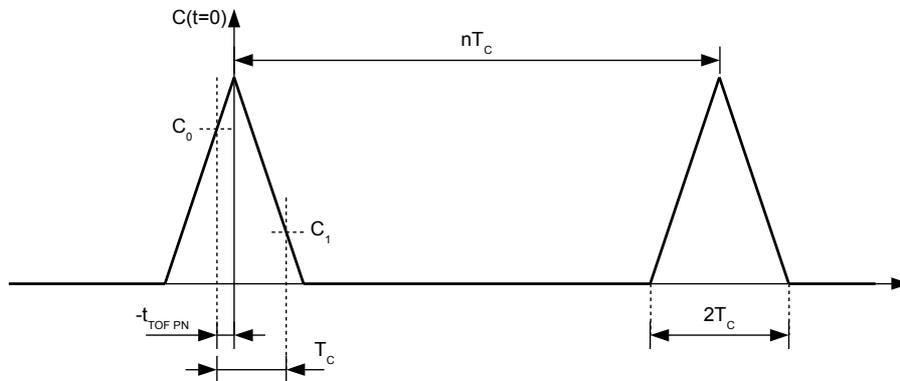


Figure 56: Auto-correlation function between the optical signal and the reference pixel signal

In order to compensate for mismatches, a swap of the two demodulation gates for each correlation sample and an averaging is operated so that 4 correlation samples are effectively used for a single distance measurement evaluation.

Let the respective samples measured for a single pixel from 4 DCS frames (0 ... 3) be DCS0, DCS1, DCS2 and DCS3. According to the above definition, the correlation samples are named as:

- DCS0:  $C_0$  correlation sample at given time  $t$ .
- DCS1:  $C_1$  correlation sample at given time  $t+T_c$  for PN modulation.
- DCS2:  $C_2$  correlation sample at given time  $t$  with swapped signals between the pixel demodulation gates.
- DCS3:  $C_3$  correlation sample at given time  $t+T_c$  for PN modulation with swapped signals between the pixel demodulation gates.

In the real case of 4x DCS samples used with  $\pi$ -delay matching algorithm, the time of flight may be computed as follows:

$$[8] \quad t_{\text{TOF PN}} [\text{sec}] = \frac{|\text{DCS1} - \text{DCS3}|}{|\text{DCS0} - \text{DCS2}| + |\text{DCS1} - \text{DCS3}|} \cdot T_c + t_{\text{OFFSET}}$$

In the case of 4 correlation samples (where DCS2 is the equivalent of DCS0 obtained by gates swap and DCS3 is the correspondent of DCS1), then the distance calculation results as follows:

$$[9] \quad D_{\text{TOF PN}} [\text{m}] = \frac{|\text{DCS1} - \text{DCS3}|}{|\text{DCS0} - \text{DCS2}| + |\text{DCS1} - \text{DCS3}|} \cdot D_{\text{TOF max}} + D_{\text{OFFSET}}$$

with maximum detectable distance range  $D_{\text{TOF max}}$  is given as

$$[10] \quad D_{\text{TOF max}} [\text{m}] = \frac{c \cdot T_c}{2} \quad \text{with } c = 300'000'000 \text{ m/s (speed of light) and } T_c.$$

and the unambiguity distance

$$[11] \quad D_{\text{TOF unamb}} [\text{m}] = n_p \cdot \frac{c \cdot T_c}{2} \quad \text{with the PN sequence bit length } n_p.$$

Based on the ideal case of 2x DCS samples, the time of flight may be computed as follows:

$$[12] \quad t_{\text{TOF PN}} [\text{sec}] = \frac{|DCS1|}{|DCS0| + |DCS1|} \cdot T_c$$

then, the distance calculation will be:

$$[13] \quad D_{\text{TOF PN}} [\text{m}] = \frac{|DCS1|}{|DCS0| + |DCS1|} \cdot D_{\text{max}}$$

### PN mode: Quality of the measurement result

The same rules for the quality and validity of the data apply as given in the section “Sine mode: Quality of the measurement result”.

The formula for the peak-to-peak amplitude  $A_{\text{TOF PN PP}}$  in PN mode is

$$[14] \quad A_{\text{TOF PN PP}} = \frac{|DSC0 - DCS2| + |DCS1 - DCS3|}{2}$$

The peak-to-peak irradiance  $E_{\text{TOF PN PP}}$  of the modulated signal at the surface of a pixel can be calculate out of the AC sensitivity  $S_{\text{TOF PN}}$ , the used integration time  $t_{\text{INT-TOF}}$ , the reference integration time  $t_{\text{INT-REF-TOF}}$  and the peak-to-peak amplitude  $A_{\text{TOF PN PP}}$  of the received modulated signal the following way:

$$[15] \quad E_{\text{TOF PN PP}} = S_{\text{TOF PN}} \cdot \frac{t_{\text{INT-REF-TOF}}}{t_{\text{INT-TOF}}} \cdot A_{\text{TOF PN PP}} \quad \text{e.g.} \quad E_{\text{TOF sine PP}} = 155 \frac{\text{nW/cm}^2}{\text{LSB}} \cdot \frac{103 \mu\text{s}}{205 \mu\text{s}} \cdot 1'000 \text{ LSB} = 78 \mu\text{W/cm}^2$$

### PN initialization

The number of the cameras that can concurrently operate and the quality of the measurement depend on the PN sequence length. Generally, longer PN sequence brings better measurements with larger number of cameras. On the other hand, longer PN sequences prolong the response time (time until a valid distance signal is available) and the amplitude. The minimum integration time and the step for larger integration times is equal to the PN sequence length.

$$[16] \quad t_{\text{INT min}} = n_p \cdot T_c \quad \text{e.g.} \quad t_{\text{INT min}} = 255 \cdot 50\text{ns} = 12.75 \mu\text{s}$$

The number of the LFSR stages ( $m_p$ ) is set by `lfsr_sel`. It directly defines:

- length of the PN sequence ( $n_p$ )
- number of different PN sequences of the maximum length (m-sequences) that can be used ( $M_p$ )

The number of the primitive polynomials (m-sequences) depends on the number of the LFSR stages. In multi-camera environment, each camera must use a unique PN polynomial. The following table shows how many independent cameras can be used for a given LFSR. For each  $m_p$  several primitive polynomials are given as example (section 7.10. describes how to generate more primitive polynomials).

Number of LFSR stages ( $m_p$ )	PN sequence bit length ( $n_p$ )	Number of m-sequences for independent cameras ( $M_p$ )	Primitive polynomial (pn_poly) <sup>1</sup>	Integration time (Int_len_hi/lo)	Integration time needed for one PN sequence [ $\mu$ s] <sup>2</sup>
8	255	16	0x11D, 0x12B, 0x12D, 0x14D, ... 0x1F5	0x03FB	12.75
9	511	48	0x211, 0x21B, 0x221, 0x22D, ... 0x3FB	0x07FB	25.55
10	1'023	60	0x409, 0x41B, 0x427, 0x42D, ... 0x7F9	0x0FFB	51.15
11	2'047	176	0x805, 0x817, 0x82B, 0x82D, ... 0xFE9	0x1FFB	102.35
12	4'095	144	0x1053, 0x1069, 0x107B, 0x107D, ... 0x1FC9	0x3FFB	204.75
13	8'191	630	0x201B, 0x2027, 0x2035, 0x2053, ... 0x3FFD	0x7FFB	409.55
14	16'383	756	0x402B, 0x4039, 0x4053, 0x405F, ... 0x7FE7	0xFFFB	819.15

Table 25: Properties of PN mode m-sequences

Notes:

<sup>1</sup> The remaining pn\_poly register values which are not listed in the table can be calculated by the formula given in chapter 7.10., Calculation of PN mode polynomials (m-sequences). It is only the first 4 and the last computed numbers listed here as a quick reference for the application developer.

<sup>2</sup> mod\_clk = 80MHz, T<sub>C</sub> = 50ns

#### LFSR stage selection:

The epc660 contains several LFSR implementations (each with different number of stages  $m_p$ ). The default implementation is an 11-bit LFSR, set by lfsr\_sel = 100 in the MOD\_Control register.

#### PN polynomial selection:

After the number of stages of the LFSR is selected, the appropriate PN sequence length must be programmed. It should have the maximum length (m-sequence). PN polynomial size is selected through PN\_POLY\_hi/lo registers, The starting point of the PN sequence is initialized through PN\_INIT\_hi/lo registers (see Table 42, Modulator/demodulator registers). Since the PN modulation has good properties (i.e. high auto-correlation, low cross-correlation) only when the complete sequence is used, the integration length should be set accordingly (Int\_len\_hi/lo). It is allowed to use integration time during which multiple PN sequences are shifted.

### 6.2. Black & white mode

The black & white mode allows using the epc660 as a grayscale imager. This mode can be used either without LED/LD illumination for ambient-light measurements or with LED/LD for active illumination of the scenery.

The black & white measurement uses the regular DCS measurement but only with DCS0. It is performed in single-ended mode with read-out of MGA. Refer to chapter 8.6.5, MT registers. Corresponding registers settings can be found in Table 26.

There will be a one frame acquisition with the 12 bit black & white values.

Due to the fact that distance measurement results can be influenced by ambient-light, the black & white measurement without illumination can thereof be used as an important quality and correction parameter for the distance measurement.

#### Black & white: Quality of the measurement result

The same rules apply for data quality and validity as given in section "Sine mode: Quality of the measurement result". The saturation flag status is invalid in this mode.

These black & white values can also be used for estimating quality information during sine/PN mode for the 3D TOF distance calculations.

The irradiance  $E_{BW}$  of the grayscale signal at the surface of a pixel can be calculate out of the DC sensitivity  $S_{BW}$ , the used integration time  $t_{INT-BW}$ , the reference integration time  $t_{INT-REF-BW}$  and the amplitude DCS0 of the grayscale signal the following way:

$$[17] \quad E_{BW} = S_{BW} \cdot \frac{t_{INT-REF-BW}}{t_{INT-BW}} \cdot DCS0 \quad \text{e.g.} \quad E_{BW} = 61.5 \frac{\text{nW/cm}^2}{\text{LSB}} \cdot \frac{103 \mu\text{s}}{1.6 \mu\text{s}} \cdot 1'000 \text{ LSB} = 3.96 \text{mW/cm}^2$$

## 7. Application information

As a help for the user to have an easier understanding of the chip, this chapter list a variety of typical application examples and their configurations for the epc660.

### 7.1. Example sequence from the start-up to frame acquisition

1. Apply all positive supplies, while keeping  $\overline{\text{RESET}} = 0$ .
2. Wait until all positive supplies reach their rated levels.
3. Apply the  $V_{\text{BS}}$  negative supply, while keeping  $\overline{\text{RESET}} = 0$ .
4. Wait until  $V_{\text{BS}}$  reached its rated level.
5. Optional: Set/check the external 10kOhm pull-up resistors on the strap pins (HSYNC\_A1, VSYNC\_A0).
6. Release  $\overline{\text{RESET}} = 1$ .
7. Wait until the start-up/reset sequence is over ( $t_{\text{Strap\_scan}} + t_{\text{EEPROM\_to\_CFG\_copy}}$ ).
8. Optional: Program the TCMI interface signal polarities with respect to the application CPU interface requirements via I<sup>2</sup>C interface.
9. Do the counterpart for the parallel data interface settings on the application CPU.
10. Optional: Set LED driver and DLL properties and polarities with respect to external LED/LD circuit on the PCB via I<sup>2</sup>C. Set DLL measurement rate via I<sup>2</sup>C (DLL\_measurement\_rate\_hi/lo register).
11. Select the measurement mode out of the Sine, PN or black & white modes (Default: Sine mode, 4 DCS).
12. Optional: If PN mode is selected, set also the number of LFSR stages (MOD\_Control register, lfsr\_sel bits), the PN polynomial (PN\_POLY\_hi/lo, PN\_INIT\_hi/lo registers) and the number for the distance offset (Dist\_offset register, 0-63 steps of  $t_{\text{pll\_clk}}$ ).
13. Optional: Set ROI via I<sup>2</sup>C interface (ROI\_tl\_x\_hi/lo, ROI\_tl\_y, ROI\_br\_x\_hi/lo, ROI\_br\_y registers).
14. Set the integration time via I<sup>2</sup>C (INTM\_hi/lo, Int\_len\_hi/lo registers).
15. Do the counterpart for the frame buffer size adjustment, pointer initializations, DMA and INT settings on the application CPU.
16. Start the frame acquisition by using shutter trigger signal (SHUTTER = 1 or shutter\_en = 1 via I<sup>2</sup>C).
17. Receive transmitted frames from TCMI interface to the external frame buffer on the application CPU.
18. Optional: Read the temperature sensor readout values via I<sup>2</sup>C (Sum\_Temp\_tl\_hi/lo, Sum\_Temp\_tr\_hi/lo, Sum\_Temp\_bl\_hi/lo, Sum\_Temp\_br\_hi/lo registers).
19. Loop back to step 12 - 19.

Note: For corresponding I<sup>2</sup>C communication examples refer to chapter 5.4.7., Control commands.

## 7.2. Basic measurement mode setting

The basic measurement functions, as they are different modes of distance measurements and black & white imaging, are selected by the appropriate settings of the corresponding control registers. For the most often used applications, Table 26 lists these configurations.

Refer to the corresponding chapters for detailed explanations to each mode.

Mode			Register setting				
Basic	Function	LSFR stages	MOD_Control (0x92)	MT_0_hi (0x22)	MT_0_lo (0x24)	PN_POLY (0x8C/0x8D)	
TOF <sup>1</sup>	Sine 4x DCS <sup>1</sup>	--- <sup>2</sup>	0x34 <sup>1</sup>	0x34	0x00	--- <sup>2</sup>	
	Sine 2x DCS	--- <sup>2</sup>	0x14	0x34	0x00	--- <sup>2</sup>	
	PN 4x DCS	8	8	0x77	0x34	0x00	Table 25
		9	9	0x76	0x34	0x00	Table 25
		10	10	0x75	0x34	0x00	Table 25
		11	11	0x74	0x34	0x00	Table 25
		12	12	0x73	0x34	0x00	Table 25
		13	13	0x72	0x34	0x00	Table 25
		14	14	0x71	0x34	0x00	Table 25
	PN 2x DCS	8	8	0x57	0x34	0x00	Table 25
		9	9	0x56	0x34	0x00	Table 25
		10	10	0x55	0x34	0x00	Table 25
		11	11	0x54	0x34	0x00	Table 25
		12	12	0x53	0x34	0x00	Table 25
13		13	0x52	0x34	0x00	Table 25	
14		14	0x51	0x34	0x00	Table 25	
Black & white	ambient only <sup>3</sup>	--- <sup>2</sup>	0x00	0x14	0x26	--- <sup>2</sup>	
	ambient & non modulated LED/LD <sup>4</sup>	--- <sup>2</sup>	0x00	0x14	0x16	--- <sup>2</sup>	
	ambient & modulated LED/LD <sup>4</sup>	--- <sup>2</sup>	0x00	0x14	0x06	--- <sup>2</sup>	

Table 26: Basic measurement mode setting

Notes:

<sup>1</sup> Default setting

<sup>2</sup> Setting is not applicable for this application.

<sup>3</sup> Black & white image passively illuminated by ambient-light only.

<sup>4</sup> Black & white image passively illuminated by ambient-light and actively illuminated by non modulated LED/LD.

<sup>5</sup> Black & white image passively illuminated by ambient-light and actively illuminated by modulated LED/LD.

Note: LED driver is always turned on. Take care that the LED driver and the epc660 chip does not exceed the maximum operating limits.

<sup>6</sup> For correct setting of DLL\_measurement\_rate, refer to chapter 5.5.2., DLL (Delay Locked Loop).

### 7.3. 3D TOF distance measurement flow

A final 3D TOF distance image will be done with different process steps according to Figure 57. Both interfaces of the epc660 are used: The I<sup>2</sup>C for configuration, mode selection and temperature reading (blue marked in the following figures) and the high-speed TCMI for reading the frame data (red marked in the following figures).

The sequence starts with the initialization of the epc660 registers with the necessary and correct configuration parameters. Next, the TOF measurement with the expected mode (sine, PN, 4x DCS, 2x DCS) will be performed. Depending of the application and the ambient conditions (ambient-light, changing temperature conditions), the TOF measurement needs some compensation. For the purpose of more accurate ambient-light compensation, a black & white measurement without illumination captures the background light level. Reading of the on-chip temperature sensors (from time to time) helps to compensate thermal influences caused by e.g. the LEDs, the optical filters and the sensor. After the rearrangement of the black & white image to the correct pixel orientation, the final 3D TOF distance image can be calculated with all for the application necessary compensations.

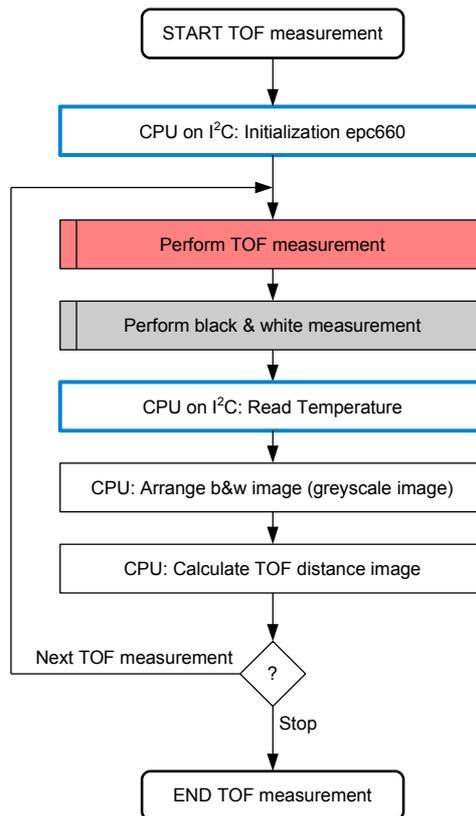


Figure 57: Generic 3D TOF distance measurement flow

The process flows for distance measurements and for black & white images are similar, see Figure 58. The main differences are the mode selection, see Table 26 and depending thereof the number of frames, which need to be read out during a process cycle. After mode setting, the cycle will be started by applying the SHUTTER signal. Once the SHUTTER is stimulated, the epc660 executes the measurement until the end of the sequence automatically. The application CPU has to follow accordingly by reading out the collected data until the end of sequence.

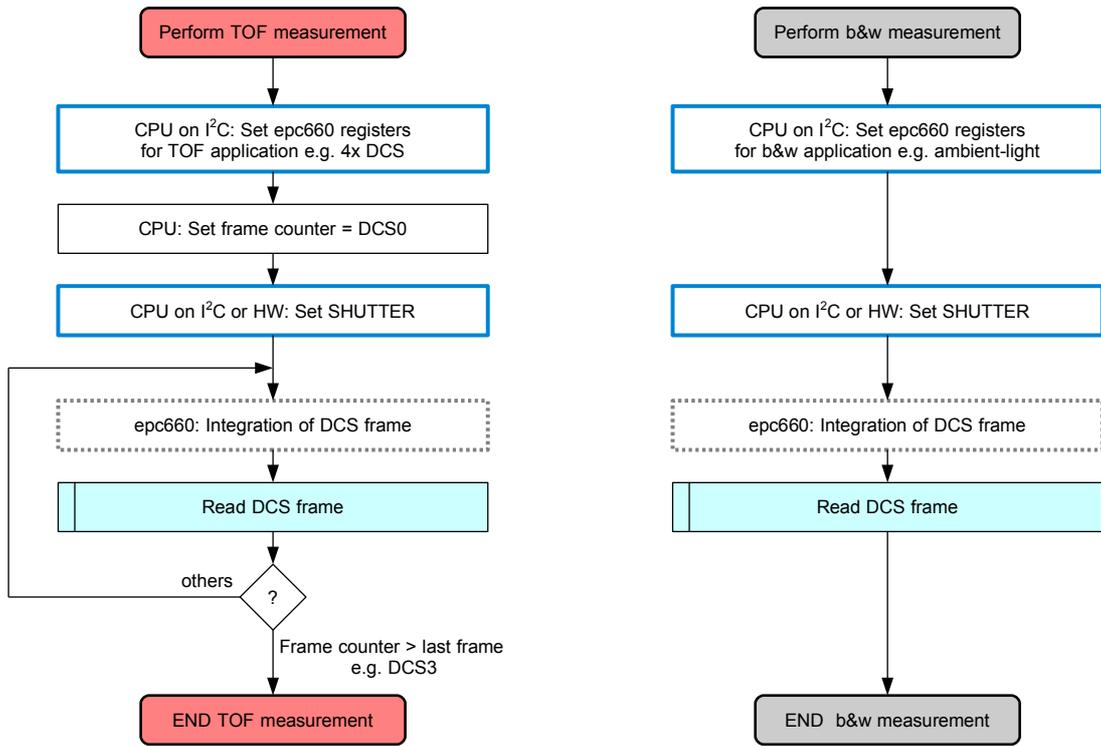


Figure 58: Generic sequences for the distance (TOF) and the black & white measurement

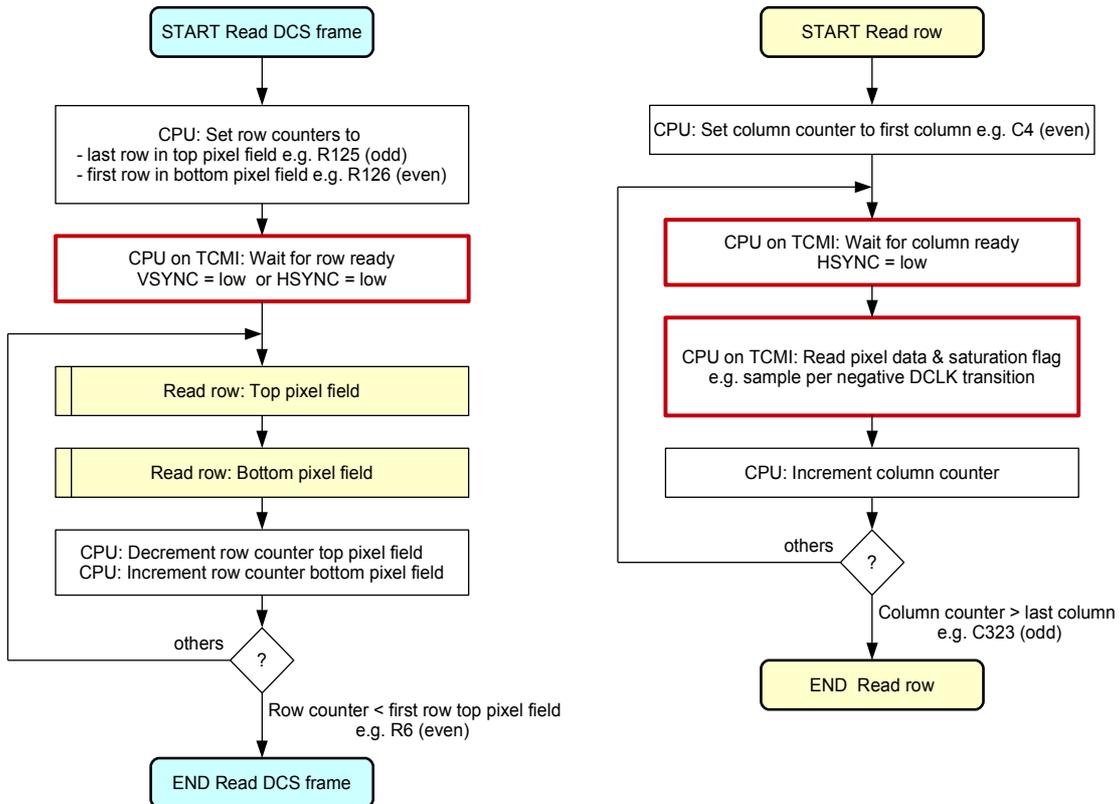


Figure 59: Generic sequences to readout frames and row by row

The generic procedures to readout frames or rows are independently of the selected modes. The application is driven only by the TCMI interface during these phases. To catch the beginning of the frame, the application CPU has to wait after the measurement start until the in-

tegration period is finished and the first frame data is available. The epc660 signals this by setting VSYNC and HSYNC active. Pixel data can be read DCLK by DCLK as long the HSYNC signal is active. Refer also to Figure 42 and Figure 43. The application has to take care of its own, to update synchronously all necessary frame, row and pixel readout counters of the application during the the whole measurement cycle.

Only if the validity and the necessary quality level of the measured data are given, the result of the distance is correct and reliable. The generic validity and quality of the data is independent of any correction or compensation algorithms. It is given by the complete epc660 camera system with chip, lens, illumination and environmental conditions.

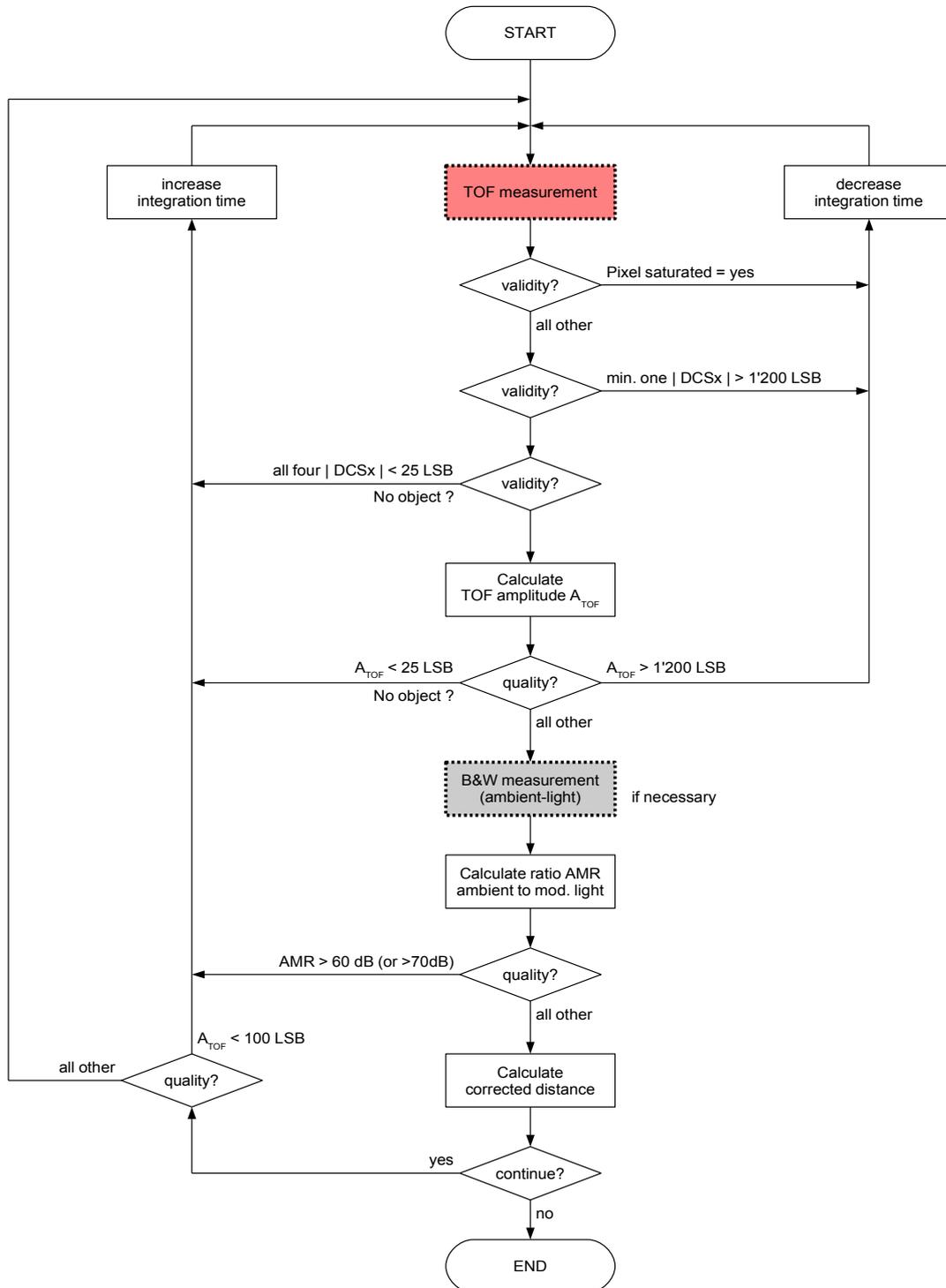


Figure 60: Generic validity and quality flow chart for a single pixel

Regarding possible correction and compensation algorithms refer to e.g. epc's application note AN10 or the Handbook epc600, which are available on the epc website.

#### 7.4. Operating and unambiguity range versus time base setting

The epc660 3D TOF imager uses the time-of-flight principle. It is implemented with a repeating, continuous-mode modulation signal (sine or PN) during the integration phase (refer to chapter 6., Measurement Modes). Consequently, only signals returning within the maximum time slots can be detected at all (PN mode) or unambiguously (sine or PN mode).

The operating range is the maximum distance which corresponds to the maximum time-of-flight inside of one period of the used modulation: for sine, it is one period of  $f_{LED}$  and for PN mode, it is the chip period  $t_c$ . Objects inside this area are detected unambiguously. For PN mode it means also, that objects above this distance and below the unambiguity distance are suppressed and cannot be detected (see Figure 56).

The unambiguity range defines the repetition distance, where objects outside of the targeted operating range can still be detected as far they are of very high reflectivity (remission). Strongly reflected signals outside of this range may therefore interfere with the measurement.

The operating range, the unambiguity distance, the time base for the integration time and the resolution of the distance signal are defined by the modulation clock  $mod\_clk$ . This corresponds for the epc660 to a maximum default operating range of 7.5m @  $mod\_clk = 80MHz$ . It may be necessary depending on the application to adapt this parameters to other values. It can be done by a change of the  $mod\_clk$ . Table 27 lists as an example some values of the modulation clock  $mod\_clk$  in function of the operating range, the unambiguity distance, of the distance resolution and of the multiplier of the integration time base.

TOF sine & PN					TOF sine		TOF PN	
Operating range	Int. time multiplied by	Distance resolution <sup>2</sup>	Modulator clock	$mod\_clk\_div$	LED/LD mod. freq.	Unambiguity range	Chip period	Unambiguity range
			$mod\_clk$	(0x85)	$f_{LED}$		$t_c$	e.g. LSFR 8
[m]	[#]	[cm]	[MHz]	[#]	[MHz]	[m]	[ns]	[m]
7.50 <sup>1</sup>	1	0.250	80.0	0 <sup>1</sup>	20.000	7.50	50.0	1'912
15.00	2	0.500	40.0	1	10.000	15.00	100.0	3'825
30.00	4	1.000	20.0	3	5.000	30.00	200.0	7'650
60.00	8	2.000	10.0	7	2.500	60.00	400.0	15'300
120.00	16	4.000	5.0	15	1.250	120.00	800.0	30'600
240.00	32	8.000	2.5	31	0.625	240.00	1'600.0	61'200

Table 27: Operating range versus  $mod\_clk$

Notes:

<sup>1</sup> Default values

<sup>2</sup> The distance resolution is given for an operating range corresponding to 3'000 LSB.

#### 7.5. Integration time setting

The integration time is the active frame acquisition period (see Figure 42). Specially for moving objects or cameras, this time should be very short to reduce motion blur effects as much as possible. The integration time together with the illumination intensity also defines the effective achievable distance, which the complete epc660 camera system can see.

The following Table 28 lists the possible and mostly common used integration times per measurement mode as well as the corresponding register settings.

Integration time <sup>5</sup>	Remarks <sup>1</sup>	Register values			
		INTM (0xA0/0xA1)		Int_len (0xA2/0xA3)	
		[DEC]	[HEX]	[DEC]	[HEX]
100 ns	Sine & B&W only	1d	0x0001	7d	0x0007
200 ns		1d	0x0001	15d	0x000F
400 ns		1d	0x0001	31d	0x001F
800 ns		1d	0x0001	63d	0x003F
1.60 μs		1d	0x0001	127d	0x007F
3.20 μs		1d	0x0001	255d	0x00FF
6.40 μs		1d	0x0001	511d	0x01FF
12.75 μs <sup>5</sup>	LSFR 8	1d	0x0001	1'019d	0x03FB
25.55 μs	LSFR 9	1d	0x0001	2'043d	0x07FB
51.15 μs	LSFR 10	1d	0x0001	4'091d	0x0FFB
102.35 μs	LSFR 11	1d	0x0001	8'187d	0x1FFB
204.75 μs	LSFR 12	1d	0x0001	16'379d	0x3FFB
409.55 μs	LSFR 13	1d	0x0001	32'763d	0x7FFB
819.15 μs	LSFR 14	1d	0x0001	65'531d	0xFFFB
1.6383 ms	Multiples of LSFR 14	2d	0x0002	65'531d	0xFFFB
3.2766 ms		4d	0x0004	65'531d	0xFFFB
6.5532 ms		8d	0x0008	65'531d	0xFFFB
13.1064 ms		16d	0x0010	65'531d	0xFFFB
26.2128 ms		32d	0x0020	65'531d	0xFFFB
52.4256 ms		64d	0x0040	65'531d	0xFFFB
104.8512 ms		128d	0x0080	65'531d	0xFFFB
209.7024 ms		256d	0x0100	65'531d	0xFFFB
419.4048 ms		512d	0x0200	65'531d	0xFFFB
838.8096 ms		1'024d	0x0400	65'531d	0xFFFB
1.6776192 s		2'048d	0x0800	65'531d	0xFFFB
3.3552384 s		4'096d	0x1000	65'531d	0xFFFB
6.7104768 s		8'192d	0x2000	65'531d	0xFFFB
13.4209536 s		16'384d	0x4000	65'531d	0xFFFB
26.8419072 s	32'768d	0x8000	65'531d	0xFFFB	

Table 28: Typical TOF and B&W integration time settings for mod\_clk = 80MHz

Notes:

- <sup>1</sup> Sine & B&W only: These integration times cannot be used with PN mode. Next higher value is the double.  
 LSFR 8 ... 14: These integration times are adjusted to the basic LSFR lengths (see Table 25).  
 They follow the LSFR rules and do not exactly double for next higher value.
- Multiples of LSFR 14: They are corresponding multiples of the integration time for LSFR 15.  
 They follow the LSFR rules and do not exactly double for next higher value.
- <sup>2</sup> Preferred integration time range for sine: 100 ns ... 52.4256 ms, see also note 1.
- <sup>3</sup> Preferred integration time range for PN mode: 12.75 μs ... 52.4256 ms, see also note 1.
- <sup>4</sup> Preferred integration time range for B&W mode: 100 ns ... 52.4256 ms, see also note 1.
- <sup>5</sup> Integration time default setting is 12.75μs.

## 7.6. Special mode setting

In this chapter, the user will find the register setting tables for using the special modes and will see its effects. Detailed descriptions are given in the corresponding chapters of these modes; see chapter 5.6., Pixel Field.

### 7.6.1. Binning, column/row reduction in basic measurement modes (Single MGX mode)

Ref.	Imager settings (Input)			Register value	Imager output		
Figure	Binning <sup>1</sup> hor. / ver.	Column reduction x-axis: 2	Row reduction y-axis: 2, 4, 8	Resolution_ reduction (0x94)	Resolution x-y <sup>2</sup> [imager pixel]	Frame rate [fps]	Frame size <sup>3</sup> [kbytes]
35	---	---	---	0x00	320 x 240	262	150
35	---	---	2	0x04	320 x 120	524	75
35	---	---	4	0x08	320 x 60	1'048	37.5
35	---	---	8	0x0C	320 x 30	2'096	18.75
---	---	2	---	0x01	160 x 240	524	75
---	---	2	2	0x05	160 x 120	1'048	37.5
---	---	2	4	0x09	160 x 60	2'096	18.75
---	---	2	8	0x0D	160 x 30	4'192	9.375
36	horizontal	2	---	0x11	160 x 240	524	75
36	horizontal	2	2	0x15	160 x 120	1'048	37.5
36	horizontal	2	4	0x19	160 x 60	2'096	18.75
36	horizontal	2	8	0x1D	160 x 30	4'192	9.375
37	vertical	---	2	0x24	320 x 120	524	75
37	vertical	---	4	0x28	320 x 60	1'048	37.5
37	vertical	---	8	0x2C	320 x 30	2'096	18.75
38	both	2	2	0x35	160 x 120	1'048	37.5
38	both	2	4	0x39	160 x 60	2'096	18.75
38	both	2	8	0x3D	160 x 30	4'192	9.375

Table 29: Binning, column/row reduction in basic measurement modes (Single MGX mode, default: QVGA)

Notes:

- <sup>1</sup> Horizontal or vertical binning correspond to a 2x increased sensitivity. Binning on both axis corresponds to a 4x increased sensitivity.
- <sup>2</sup> Readout has to follow the effective numbers and order of columns and rows.
- <sup>3</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the ext. frame buffer.

7.6.2. Binning, column/row reduction in enhanced measurement modes (Dual MGX mode)

Ref.	Imager settings (Input)			Register value	Imager output		
Figure	Binning <sup>1</sup> hor. / ver.	Column reduction x-axis: 2	Row reduction y-axis: 2, 4, 8	Resolution_ reduction (0x94)	Resolution x-y <sup>2</sup> [imager pixel]	Frame rate [fps]	Frame size <sup>3</sup> [kbytes]
39	---	---	---	0x80	2 x 320 x 120	262	150
39	---	---	2	0x84	2 x 320 x 60	524	75
39	---	---	4	0x88	2 x 320 x 30	1'048	37.5
---	---	2	---	0x81	2 x 160 x 120	524	75
---	---	2	2	0x85	2 x 160 x 60	1'048	37.5
---	---	2	4	0x89	2 x 160 x 30	2'096	18.75

Table 30: Binning, column/row reduction in enhanced measurement modes: Dual MGX mode, default: QVGA

Notes:

- <sup>1</sup> No binning available in this mode.
- <sup>2</sup> Readout has to follow the effective numbers and order of columns and rows.
- <sup>3</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the ext. frame buffer.

TOF dual DCS acquisition at same integration time (motion blur reduction)

Mode		Register setting				
Basic	Function	LSFR stages	MOD_Control (0x92)	MT_1_hi (0x25)	PN_POLY (0x8C/0x8D)	
TOF	Sine 4x DCS	---	---	---	---	
	Sine 2x DCS <sup>2</sup>	---	0x14	0x3E <sup>2</sup>	---	
	PN 4x DCS	---	---	---	---	
	PN 2x DCS <sup>2</sup>	8	8	0x57	0x3E <sup>2</sup>	Table 25
		9	9	0x56	0x3E <sup>2</sup>	Table 25
		10	10	0x55	0x3E <sup>2</sup>	Table 25
		11	11	0x54	0x3E <sup>2</sup>	Table 25
		12	12	0x53	0x3E <sup>2</sup>	Table 25
		13	13	0x52	0x3E <sup>2</sup>	Table 25
14		14	0x51	0x3E <sup>2</sup>	Table 25	
Black & white	---					

Table 31: Basic measurement mode setting

Notes:

- <sup>1</sup> Setting is not applicable for this application.
- <sup>2</sup> Output is effectively 4x DCS in 2 DCS-frames. MT\_1\_hi register default value: 0x31

**TOF and b&w single DCS acquisition with 2 different integration times (High dynamic range)**

- This mode needs the following basic setting of the MT registers:  
 MT\_0\_hi = 0x30, MT\_1\_hi = 0x35, MT\_2\_hi = 0x3A, MT\_3\_hi = 0x3F.
- Reset the MT registers to the default values after leaving this mode:  
 MT\_0\_hi = 0x34, MT\_1\_hi = 0x31, MT\_2\_hi = 0x3E, MT\_3\_hi = 0x3B.

Mode			Register setting				
Basic	Function <sup>5</sup>	LSFR stages	MOD_Control (0x92)	MT_0_hi (0x22)	MT_0_lo (0x24)	PN_POLY (0x8C/0x8D)	
TOF	Sine 4x DCS	--- <sup>1</sup>	0x3C <sup>1</sup>	0x30	0x00	--- <sup>1</sup>	
	Sine 2x DCS	--- <sup>1</sup>	0x1C	0x30	0x00	--- <sup>1</sup>	
	PN 4x DCS	8	8	0x7F	0x30	0x00	Table 25
		9	9	0x7E	0x30	0x00	Table 25
		10	10	0x7D	0x30	0x00	Table 25
		11	11	0x7C	0x30	0x00	Table 25
		12	12	0x7B	0x30	0x00	Table 25
		13	13	0x7A	0x30	0x00	Table 25
		14	14	0x79	0x30	0x00	Table 25
	PN 2x DCS	8	8	0x5F	0x30	0x00	Table 25
		9	9	0x5E	0x30	0x00	Table 25
		10	10	0x5D	0x30	0x00	Table 25
		11	11	0x5C	0x30	0x00	Table 25
		12	12	0x5B	0x30	0x00	Table 25
13		13	0x5A	0x30	0x00	Table 25	
14		14	0x59	0x30	0x00	Table 25	
Black & white	ambient only <sup>2</sup>	--- <sup>1</sup>	0x08	0x10	0x26	--- <sup>1</sup>	
	ambient & non modulated LED/LD <sup>3</sup>	--- <sup>1</sup>	0x08	0x10	0x16	--- <sup>1</sup>	
	ambient & modulated LED/LD <sup>4</sup>	--- <sup>1</sup>	0x08	0x10	0x06	--- <sup>1</sup>	

Table 32: Measurement mode setting for high dynamic range

Notes:

- <sup>1</sup> Setting is not applicable for this application.
- <sup>2</sup> Black & white image passively illuminated by ambient-light only.
- <sup>3</sup> Black & white image passively illuminated by ambient-light and actively illuminated by non modulated LED/LD.
- <sup>4</sup> Black & white image passively illuminated by ambient-light and actively illuminated by modulated LED/LD.  
 Note: LED driver is always turned on. Take care that the LED driver and the epc660 chip does not exceed the maximum operating limits.
- <sup>5</sup> Output is effectively 2 DCS frames with different integration times in each 1 readout frame.

### 7.6.3. ROI setting (region of interest)

Note: For the emulation of the epc635 refer to the application section: chapter 7.6.4., epc635 emulation.

Ref.	Imager		ROI setting	Register setting top left		Register setting bottom right	
Figure	Type	Resolution x-y	Resolution x-y	X (0x96/0x97)	Y (0x9A)	X (0x98/0x99)	Y (0x9B)
		[imager pixel]	[imager pixel]	[DEC]	[DEC]	[DEC]	[DEC]
41	QVGA (Default)	320 x 240	320 x 120	4	6	323	125
45	Half-QQVGA	160 x 60	160 x 30	84	96	243	125

Table 33: ROI setting for Half-QQVGA

Ref.	Imager settings (Input)			Register value	Imager output		
Figure	Binning <sup>1</sup> hor. / ver.	Column reduction x-axis: 2	Row reduction y-axis: 2, 4, 8	Resolution_ reduction (0x94)	Resolution x-y <sup>2</sup> [imager pixel]	Frame rate [fps]	Frame size <sup>3</sup> [kbytes]
<b>Single MGX mode</b>							
35	---	---	---	0x08	160 x 60	1'048	18.75
35	---	---	2	0x0C	160 x 30	2'096	9.375
---	---	2	---	0x09	80 x 60	2'096	9.375
---	---	2	2	0x0D	80 x 30	4'192	4.6875
36	horizontal	2	---	0x19	80 x 60	2'096	9.375
36	horizontal	2	2	0x1D	80 x 30	4'192	4.6875
37	vertical	---	2	0x2C	160 x 30	2'096	9.375
38	both	2	2	0x3D	80 x 30	4'192	4.6875
<b>Dual MGX mode</b>							
39	---	---	---	0x88	2 x 160 x 30	1'048	37.5
---	---	2	---	0x89	2 x 80 x 30	2'096	18.75

Table 34: Binning, column/row reduction for ROI setting for Half-QQVGA and MGX modes

Notes:

- <sup>1</sup> Horizontal or vertical binning correspond to a 2x increased sensitivity. Binning on both axis corresponds to a 4x increased sensitivity.
- <sup>2</sup> Readout has to follow the effective numbers and order of columns and rows.
- <sup>3</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the ext. frame buffer.

### 7.6.4. epc635 emulation

epc660 can 100% emulate the epc635 (160x60 pixel) in terms of frame rate, resolution and data transfer by reprogramming the chip. The reprogramming takes place by downloading the new program segments via I<sup>2</sup>C.

Figure 61 and Figure 62 show the mechanical and optical compatibilities between both chip types.

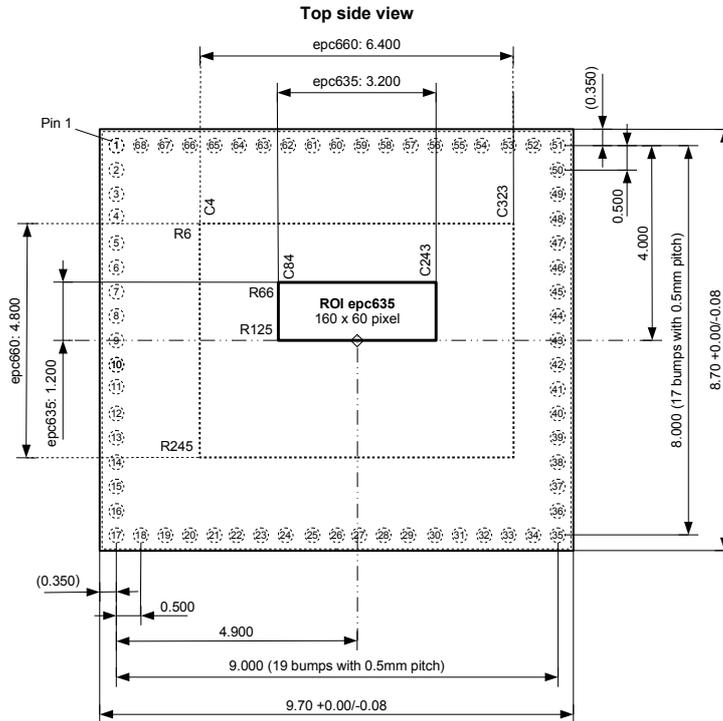


Figure 61: epc660: ROI setting for epc635 emulation

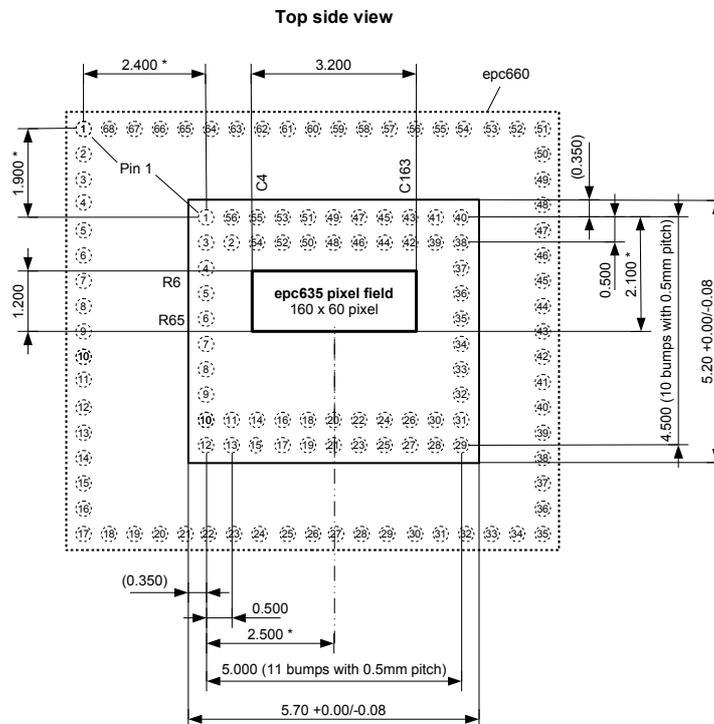


Figure 62: Mechanical dimensions epc635 versus epc660, pin 1

\* Note: This dimensions may slightly change in the final design of the epc635.

Change to epc635 mode:

1. Start up epc660 chip
2. Wait until the chip is in READY state.
3. Download the following program segments by I<sup>2</sup>C for reprogramming the epc660 to get into the epc635 emulation mode.
4. The chip is now ready to be used as epc635.  
The commands are the same as for the epc660, except the ROI is limited to the upper half pixel-field.
5. Exit epc635 mode: Power down or  $\overline{\text{RESET}}$  sets the chip back into the epc660 mode.

**IMPORTANT:**

epc635 mode is reading out the upper part of the pixel field only. It means, the data readout starts at the last row (125) and proceeds in a continuous way upwards until the first row (66) without any swaps between upper and lower pixel-field rows.

**Program segments for reprogramming the epc660 by I<sup>2</sup>C download**

Note: The actual download code for each chip version can be found in the document "Operating\_Instruction\_epc660-XXX-Vx.x"

After the program download, the chip will be operated by the regular instructions of the epc660. Special settings will deviate according to the Table 35 and Table 36.

Ref.	Imager		ROI setting	Register setting top left		Register setting bottom right	
Figure	Type	Resolution x-y	Resolution x-y	X (0x96/0x97)	Y (0x9A)	X (0x98/0x99)	Y (0x9B)
		[imager pixel]	[imager pixel]	[DEC]	[DEC]	[DEC]	[DEC]
41	epc660: QVGA	320 x 240	320 x 120	4	6	323	125
45	epc635: Half-QQVGA	160 x 60	160 x 60	84	66	243	125

Table 35: ROI setting for epc635 emulation

Ref.	Imager settings (Input)			Register value	Imager output		
Figure	Binning <sup>1</sup> hor. / ver.	Column reduction x-axis: 2	Row reduction y-axis: 2, 4, 8	Resolution_ reduction (0x94)	Resolution x-y <sup>2</sup> [imager pixel]	Frame rate <sup>4</sup> [fps]	Frame size <sup>3</sup> [kbytes]
<b>Single MGX mode</b>							
35	---	---	---	0x08	160 x 60	524	18.75
35	---	---	2	0x0C	160 x 30	1'048	9.375
---	---	2	---	0x09	80 x 60	1'048	9.375
---	---	2	2	0x0D	80 x 30	2'096	4.6875
36	horizontal	2	---	0x19	80 x 60	1'048	9.375
36	horizontal	2	2	0x1D	80 x 30	2'096	4.6875
37	vertical	---	2	0x2C	160 x 30	1'048	9.375
38	both	2	2	0x3D	80 x 30	2'096	4.6875
<b>Dual MGX mode</b>							
39	---	---	---	0x88	2 x 160 x 30	524	37.5
---	---	2	---	0x89	2 x 80 x 30	1'048	18.75

Table 36: Binning, column/row reduction for ROI setting: epc635 emulation

Notes:

- <sup>1</sup> Horizontal or vertical binning correspond to a 2x increased sensitivity. Binning on both axis corresponds to a 4x increased sensitivity.
- <sup>2</sup> Readout has to follow the effective numbers and order of columns and rows.
- <sup>3</sup> Frame size is based on 12 bit DATA[11:0] + 1 bit SAT flag per sample packed in 2 Bytes to store in the ext. frame buffer.
- <sup>4</sup> The frame rate is valid for 1µs integration time.

### 7.7. Power saving options

The epc660 has different power consumption depending on its activity level, see chapter 5.9., Power consumption levels. For power critical applications e.g. battery powered systems, it is possible to enforce the epc660 to go in so-called power saving states.

The different power saving modes and their description are listed in Table 37.

Operating mode	Power	Time		Description
		Shutdown	Recovery	
	[mW]	[ms]	[ms]	
INTEGRATION				Maximum average power consumption during regular 3D TOF operation
READY (Idle)				Minimum average power consumption during regular 3D TOF operation
SW POWER DOWN				Note: Only during regular READY mode possible. Power consumption during unnecessary functions where switched-off off by register commands.
HW POWER DOWN				Power consumption during Pin 55 $\overline{\text{RESET}} = 0$ .

Table 37: Power modes

Table 38 is a help for the electronic designer and list the current consumption versus the power saving level and per supply level.

Current	Description	Mode				Units
		INTEGRATION	READY	SW POWER DOWN	HW POWER DOWN	
I <sub>VDD</sub>	Digital supply current	30				mA
I <sub>VDDPLL</sub>	PLL supply current	6				mA
I <sub>VDDIO</sub>	IO supply current	40				mA
I <sub>VDDA</sub>	Analog supply current	250				mA
I <sub>VDDPXM</sub>	Pixel analog 1 supply current	1				mA
I <sub>VDDPXH</sub>	Pixel analog 2 supply current					mA
I <sub>VSEAL</sub>	Sealring supply current	2				mA
I <sub>VIR</sub>	Isolation supply current					mA
I <sub>VBS</sub>	Bias supply current					mA

Table 38: Current consumption during power modes

Is the epc660 during regular operation in the READY state, the SW power down mode can be activated by the following command sequence listed Table 39.

No.	Register			Description
	Name	Address	Value	
1	<b>Regular 3D TOF operation</b>			
2	Power_Control (analog)	0xA5	0x00	Switch off of unnecessary supplies
3	CLK_enables	0x80	0x00	Switch off of unnecessary clocks
4	CFG_Mode_Control	0x7D	0x14	Switch system clock to XTAL clock
5	CFG_Mode_Control	0x7D	0x10	Switch off PLL
6	<b>SW POWER DOWN</b>			
7	CFG_Mode_Control	0x7D	0x14	Switch on PLL
8	<b>Wait &gt; 32µs</b>			<b>Wait until PLL stable</b>
9	CFG_Mode_Control	0x7D	0x04	Switch system clock to PLL
10	CLK_enables	0x80	0x3F	Switch on the clocks again
11	Power_Control (analog)	0xA5	0x07	Switch on the supplies again
12	<b>Wait until supplies are stable</b>			
13	<b>Regular 3D TOF operation</b>			

Table 39: SW POWER DOWN sequence

### 7.8. Rolling DCS frames

In special applications, it is possible to use all the time the same integration time in continuous distance measurement mode without any black & white images for ambient-light compensation. Such a set-up allows enhancing the distance measurement rate by a factor of 4 by using rolling DCS frames.

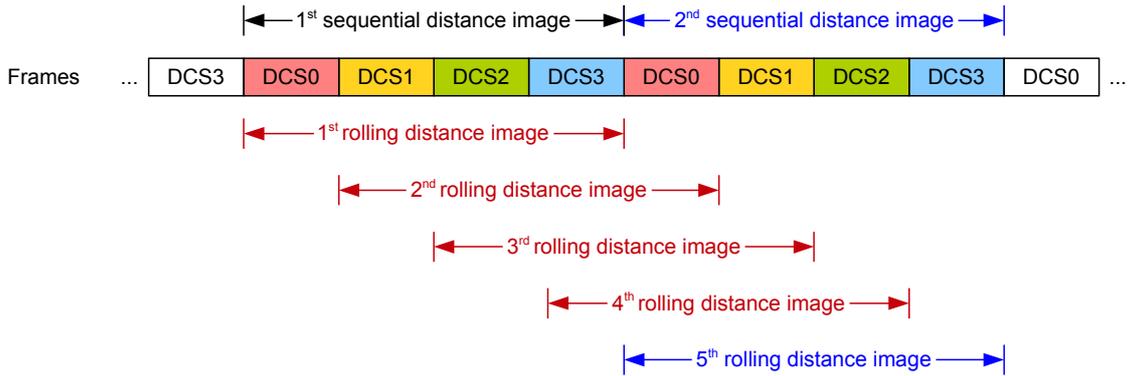


Figure 63: Rolling DCS frames

As shown in Figure 63, the algorithm performs with each new DCS frame a new distance calculation based on the new and last three DCS frames.

### 7.9. External modulation MODCLK

The epc660 has for enhanced user applications also the possibility to bring an external modulation clock to the chip. The optional MODCLK input can be used for this to inject in parallel a user controlled/modulated clock for both the LED driver and the pixel demodulator, see Figure 64.

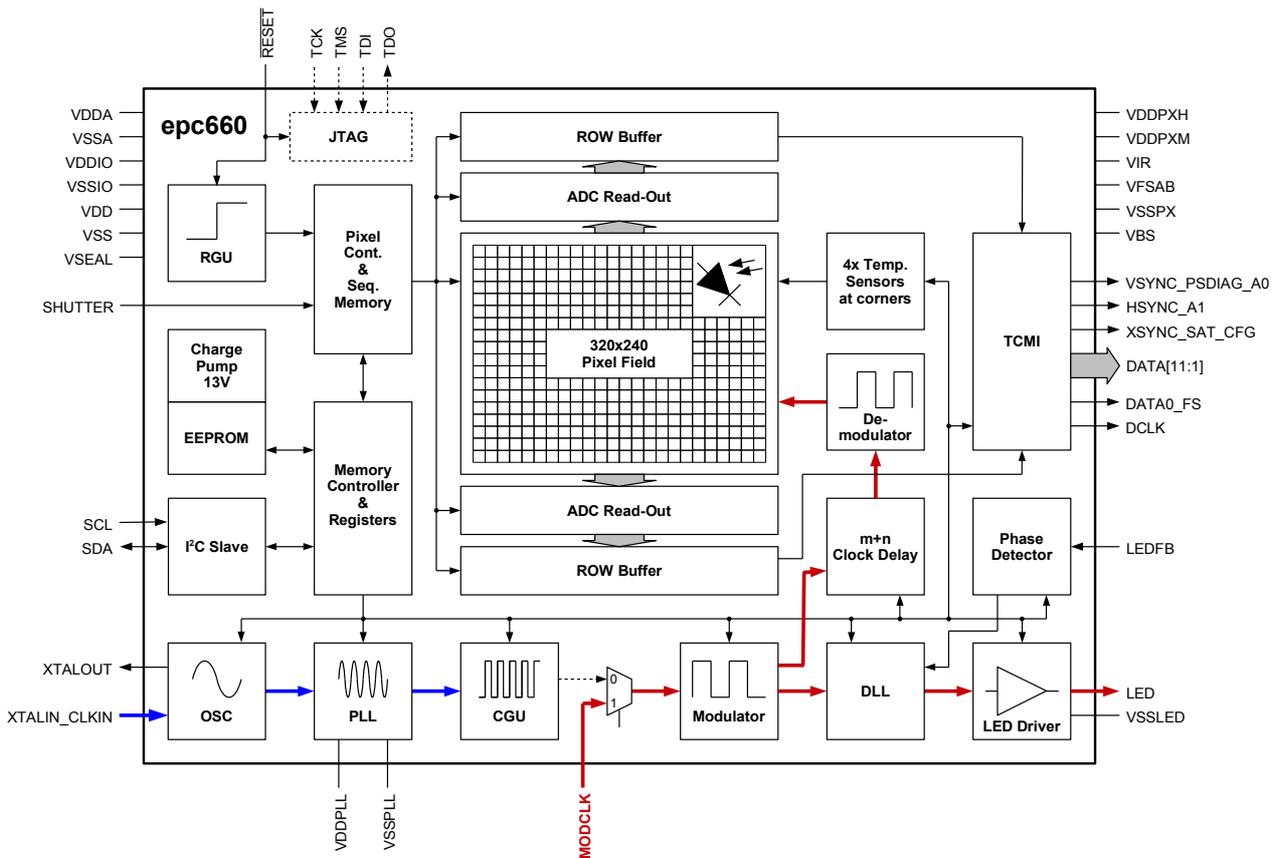


Figure 64: The MODCLK signal flow (red marked)

The external MODCLK can be used e.g. in concepts for reliable multi camera applications. It allows to use e.g. frequency-division multiple access (FDMA). In corresponding literature, the details of these concepts are explained in detail.

The user is free to apply any digital waveform up to 80MHz during frame acquisition as external MODCLK signal. Even more, he is also free to use modulations like pseudo-random edge jitter, dithering, etc.

The signal from the MODCLK pin is used as far in the register CLK\_enables is set to mod\_clk\_sel = 1, see section 8.7.1.

#### **IMPORTANT:**

- The external modulation clock replaces the internal generated modulation clock, refer also to Table 27. Based on this clock, the modulator generates the modulation sequence according chapter 6., Measurement Modes and the setting in the MOD\_Control register.
- Set DLL\_measurement\_rate = 0 for switching off the automatic DLL synchronization.

#### **7.9.1. Using the DLL with an external modulation clock**

Here, the modulator uses the ext\_mod\_clk signal from the MODCLK pin for both LED modulation and pixel demodulation functions when mod\_clk\_sel = 1. The user application is free to apply any digital waveform up to 80MHz during frame acquisition as ext\_mod\_clk signal. During the locking operation, this clock must be very stable, jitter-free, continuously running at least during the DLL pre-synchronization time and DLL lock time period. Is this period over, the user can switch back to his own modulation schemes: pseudo-random edge jitter, dithering, etc.

There are two possible ways to achieve this:

- Stop jitter/dithering and supply a clean clock on the MODCLK pin. The clock frequency for DLL synchronization needs to be the same as later on used during modulation period. Enable the DLL by setting dll\_bypass = 0. Set the DLL\_measurement\_rate = 1. Do a 1x DCS frame acquisition. After the frame data-out is completed, set DLL\_measurement\_rate = 0. This will freeze the last measured delay in the DLL. Enable jitter/dithering on the MODCLK pin and continue the normal frame acquisition.
- When a clean clock cannot be provided on the MODCLK pin, the application need to switch first to internal PLL source by setting mod\_clk\_sel = 0. It is followed by repeating the same procedure as above. Before starting the normal frame acquisition, set mod\_clk\_sel = 1 for switching back to the modulation clock provided on the MODCLK pin.

#### **7.9.2. DLL manual locking operation**

DLL can also be operated manually via I<sup>2</sup>C communication by assigning externally a delay value to the DLL control registers for bringing it into a locking condition. The procedure follows by single register access steps in a loop by software the mechanism of the automatic locking, see chapter 5.5.2., DLL (Delay Locked Loop).

The Figure 27 shows the two paths which must be brought in synchronization: The signal propagation time of the red coloured path depends, among others, on the registers Demodulation\_delays and Dist\_offset. The mgx\_del\_sel value of the Demodulation\_delays register will add a delay to this path if required. The purpose is, to make the propagation delay of this path longer than the blue path (see Figure 28). The Dist\_offset register is application dependent and will be neglected in this section. On the other side, the propagation time of the blue coloured path is mainly defined by the external LED/LD circuit until the LEDFB pin. The DLL compares the feedback signals from both paths and provides status information in the DLL\_status register. The delay lines of the DLL must now be adjusted by applying values to the registers DLL\_coarse\_ctrl\_ext and DLL\_fine\_ctrl\_ext\_\* until the DLL locks (see Table 41, DLL manual control registers).

Figure 65 provides a flowchart for manually DLL locking. The software has to determine the register settings for the DLL locking condition. Note, this is a straightforward control algorithm to explain the DLL manually locking behaviour. Different algorithms can be implemented depending on the applications.

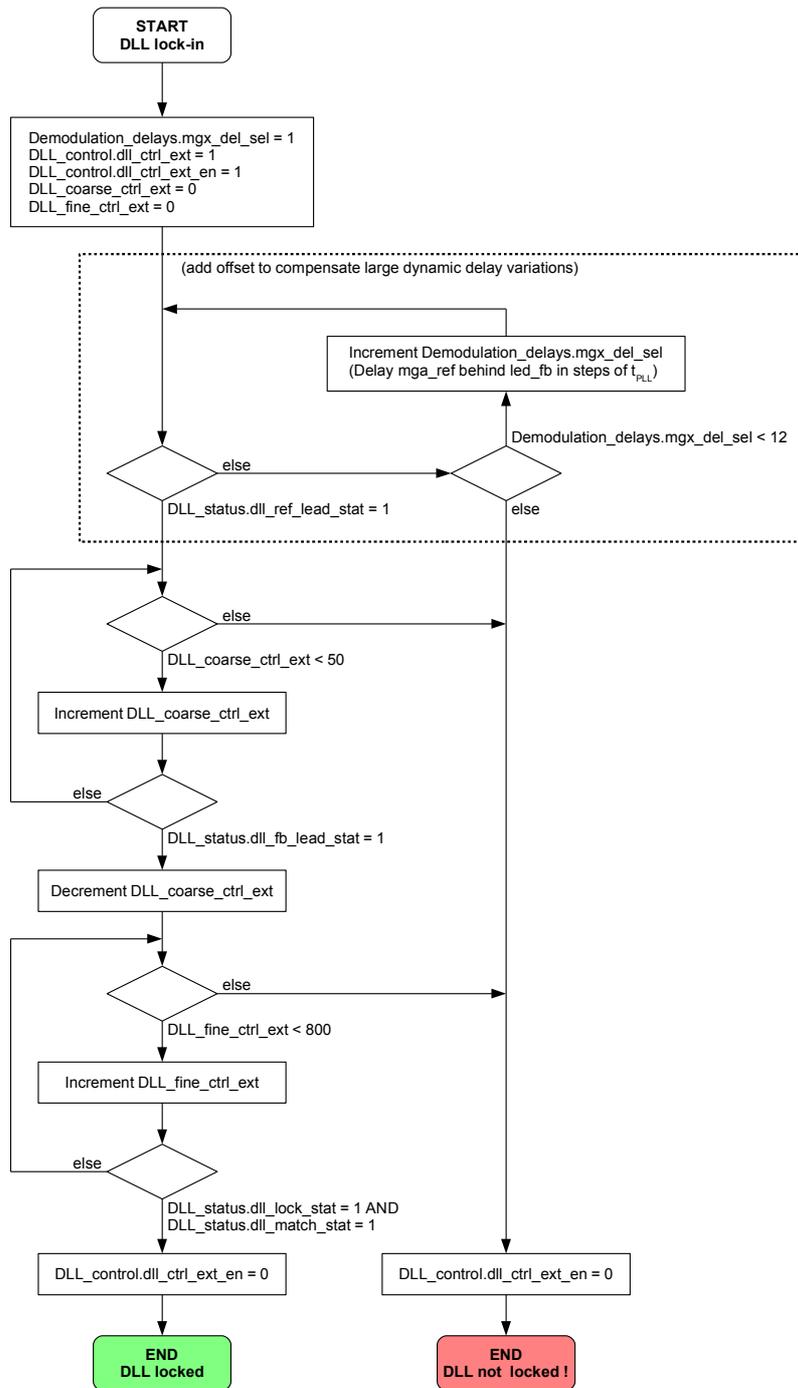


Figure 65: Flowchart for DLL manual locking

### 7.10. Calculation of PN mode polynomials (m-sequences)

The following Octave script can be used for calculating PN mode polynomials (m-sequences), which can be later on programmed into the PN\_POLY\_hi and PN\_POLY\_lo registers.

Following packages / toolboxes must be installed prior to run the Octave script:

Package Name	Version
communications *	1.1.1
control *	2.6.0
general *	1.3.2
miscellaneous *	1.0.9
optim *	1.0.12
signal *	1.2.2
specfun *	1.0.9

Table 40: Octave toolboxes

#### Octave script pn\_poly.m:

```
% Load all packages
pkg load all

% Calculating for LFSR stages from 8 to 15
for i = 8 : 15
    printf("\n\n\nLFSR stage: %d\n", i)

    % Calculating primitive polynoms. Remove 'nodisplay' if you want to see
    % polynomials in a different form.
    %primitive_poly = primpoly(i, 'all');
    primitive_poly = primpoly(i, 'all', 'nodisplay');

    % Getting number of primitive polynomials. Result was written in the form of
    % a matrix with 1 row. We need to get the row length.
    num_of_poly = size(primitive_poly, 2);
    printf("num_of_poly: %d\n", num_of_poly)

    % Length of the PN sequence
    pn_len = 2^i - 1;
    printf("pn_len: %d\n", pn_len)

    % Print polynomials as number
    printf("\nPolynomials in the number form:\n")
    for j = 1 : num_of_poly
        %printf("%d\n", primitive_poly(j)) % decimal
        printf("0x%0x\n", primitive_poly(j)) % hex
    end
    printf("\n\n")
end

printf("Done.\n\n")
```

## 7.11. epc660 Card Edge Connector Carrier

### 7.11.1. Schematics

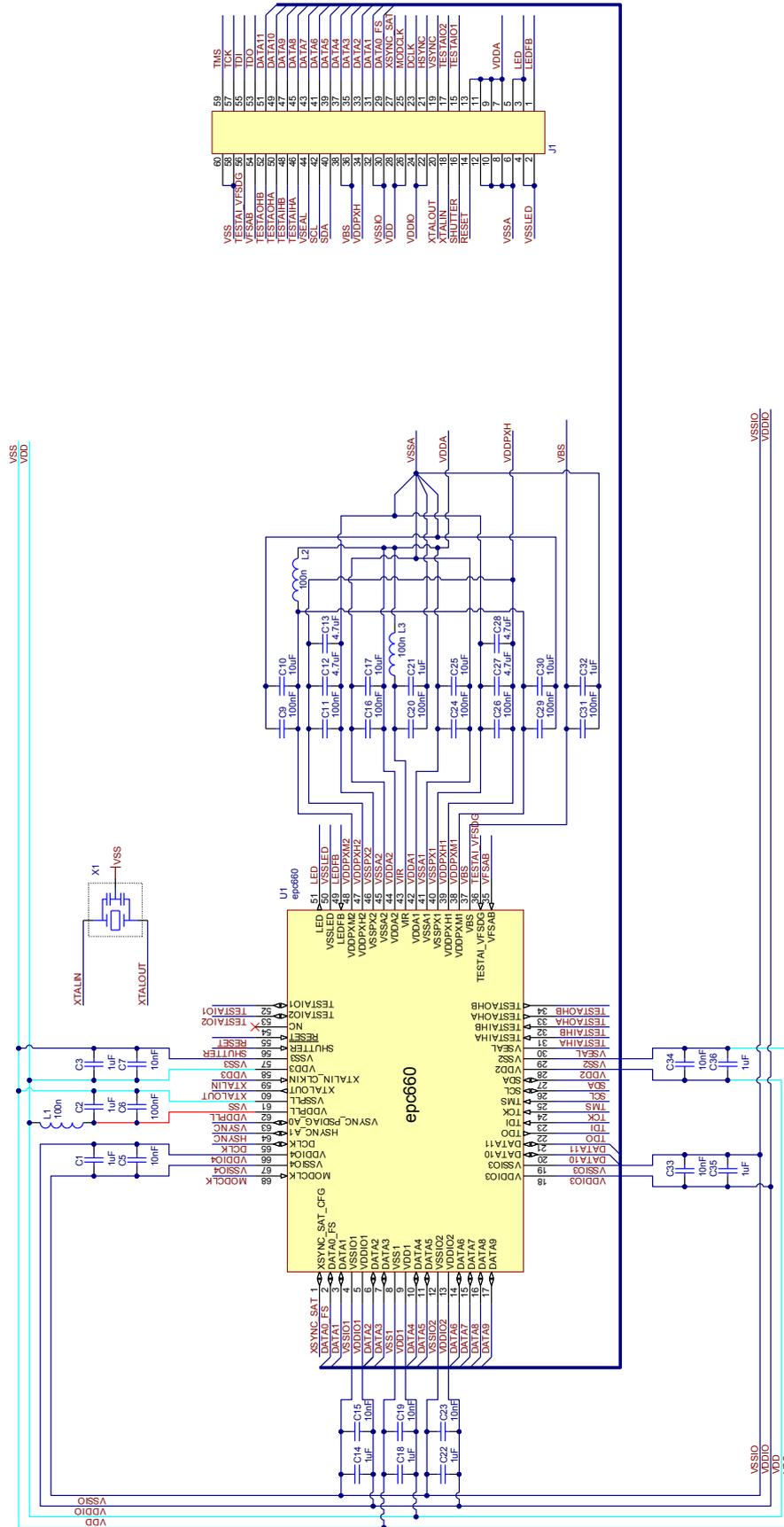


Figure 66: Schematic epc660 Card Edge Connector Carrier

7.11.2. Board layout and assembly

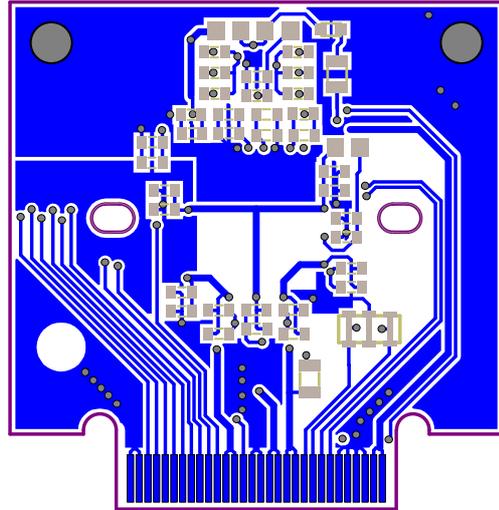
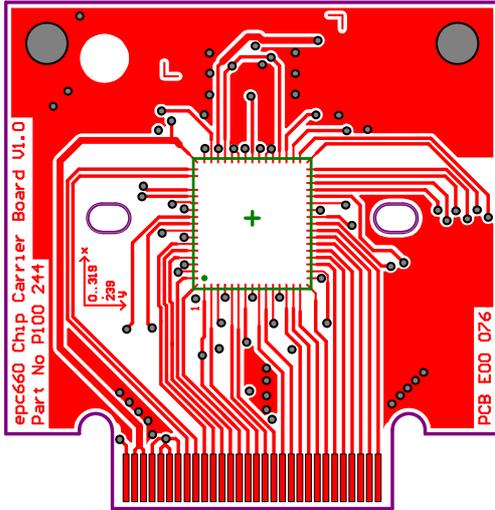


Figure 67: epc660 Card Edge Connector Carrier: Layout top and bottom

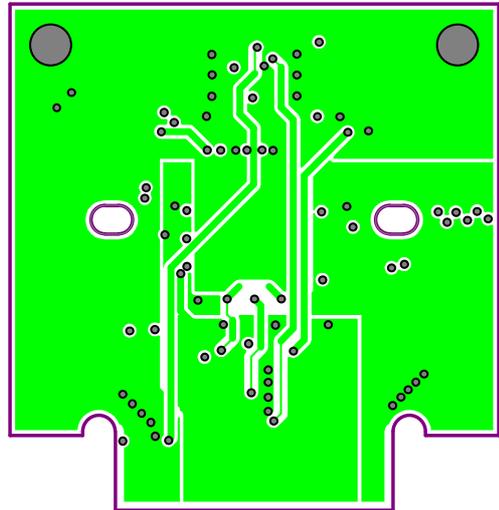
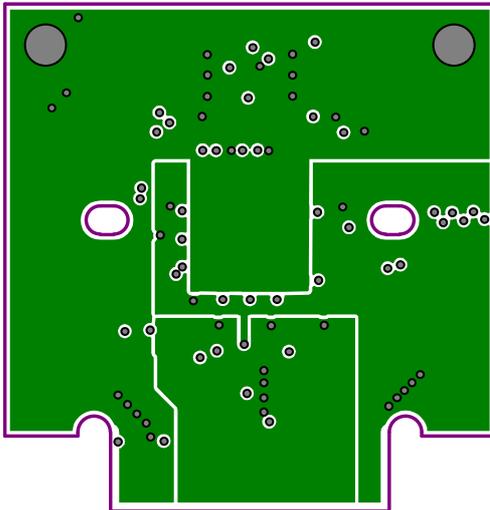


Figure 68: epc660 Card Edge Connector Carrier: Layout middle top and bottom

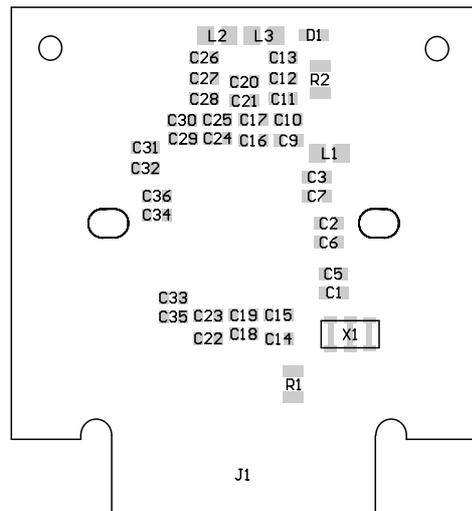
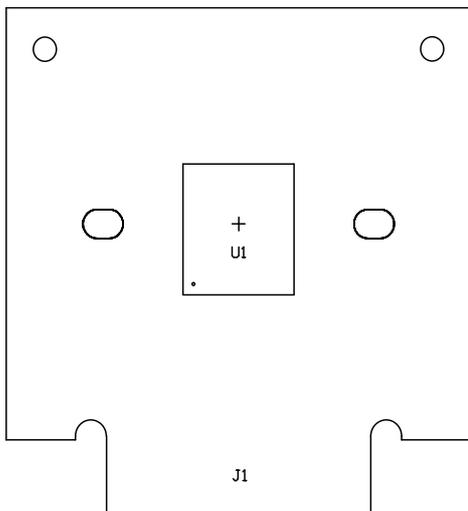


Figure 69: epc660 Card Edge Connector Carrier: Assembly top and bottom

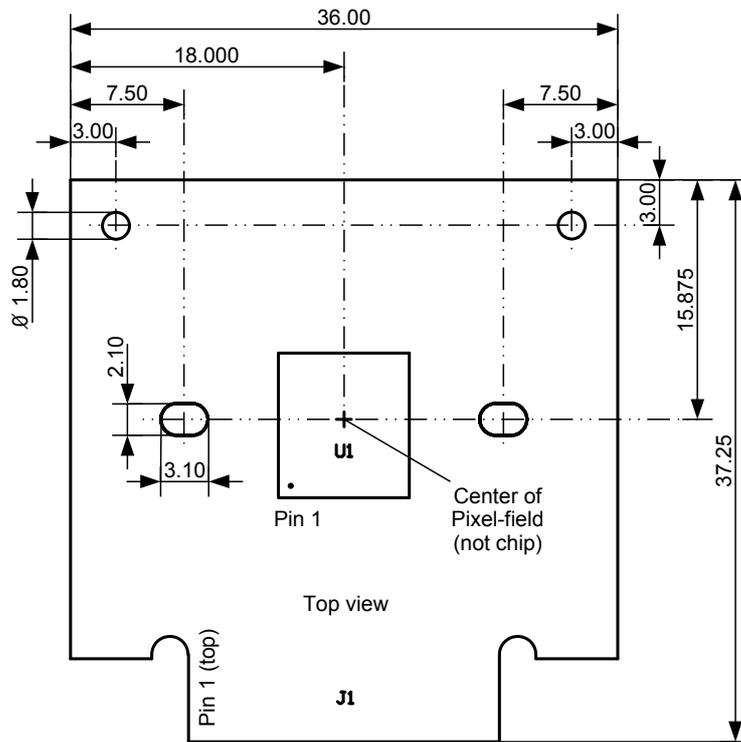


Figure 70: epc660 Card Edge Connector Carrier: Dimensions

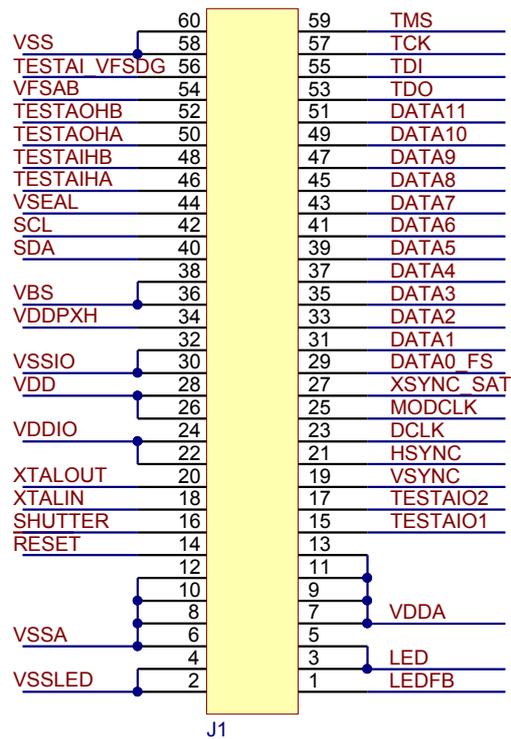


Figure 71: Pin table card connector

Figure 72 and Figure 73 show possible card connectors for interfacing the Card Edge Connector Carrier with the user's application board e.g. SAMTEC MEC6-130-02-L-DV-A / -RA1

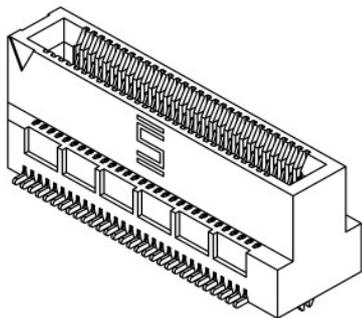


Figure 72: Vertical mount mini-edge card connector

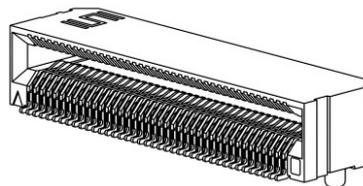


Figure 73: Right angle mini-card connector (Source: Samtec)

## 8. Control registers and EEPROM

### 8.1. Memory map

The epc660 control registers (RAM) are used for controlling all features of the chip. They are organized as 256x8 bit into 0x00 ... 0xFF address locations. The address space 0x80 ... 0xFF is EEPROM backed-up. Parameters in this section can be stored permanently between the power off/on cycles. All registers can be accessed through I<sup>2</sup>C interface by the application CPU (see chapter 5.4. I2C Slave). Multiple byte registers are stored as big-endian in the memory map.

It is further split into two pages as Control Page (0x00 ... 0x7F) and as EEPROM Page-0 (0x80 ... 0xFF).

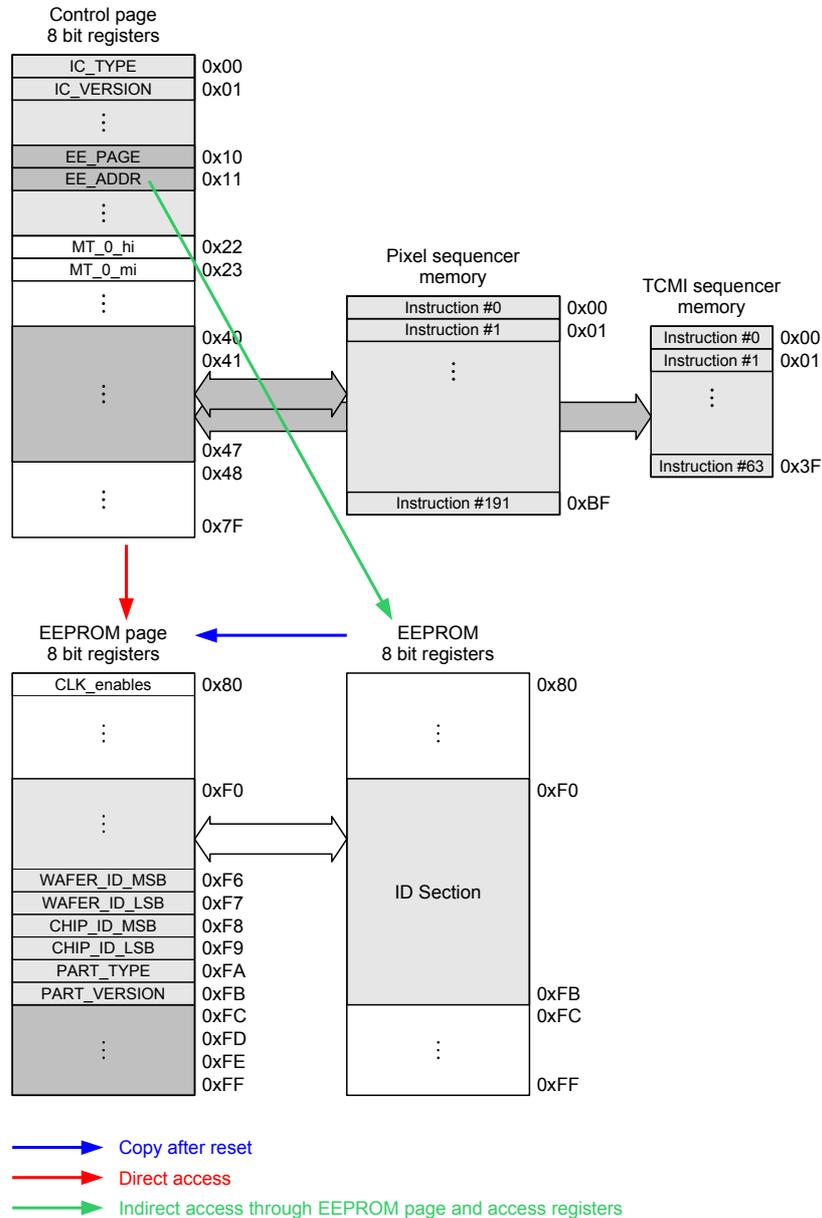


Figure 74: Memory Map

### 8.2. Control page

The control page contains only RW accessible configuration registers with default values during startup. The content can be changed via I<sup>2</sup>C interface. The changed values are preserved as long as the IC is powered. The registers reset back to their default values with a power-reset cycle or with a reset cycle alone.

### 8.3. EEPROM page, EEPROM and its charge pump

The epc660 has an 128x8-bit embedded EEPROM to store operation parameters, trimming and calibration values.

The EEPROM page address space (RAM) contains RW accessible configuration registers. Their content can be saved into the on-chip 128 x 8-bit EEPROM. It is mapped exactly one-to-one in the same RAM address space. There are various methods how the content of EEPROM can be saved or copied back and forth with the actual RW configuration registers (for details, refer to chapter 5.4.7., Control commands).

Each time a single or multiple I<sup>2</sup>C byte-write command sequence is applied to the EEPROM address space, a charge-pump for program and erase operations is automatically enabled before the EEPROM write access starts. It is disabled after the write access is finished.

The application software must respect a 20ms/byte write time (program/erase cycle) when altering the EEPROM content through I<sup>2</sup>C interface. When `i2c_clock_stretch_en = 1`, the I<sup>2</sup>C slave interface will stretch the SCK line while the EEPROM write continues. The application CPU can monitor the SCK line with its I<sup>2</sup>C master interface before sending the next byte-write command. If the application CPU does not support the I<sup>2</sup>C clock stretching feature, the application should first set `i2c_clock_stretch_en = 0` and keep a timer for waiting 20ms between every I<sup>2</sup>C byte-write command sequence.

**IMPORTANT:**

- The built-in charge-pump for the EEPROM is a noisy circuit which shall not be enabled during frame acquisition. It can degrade the performance of the measurements. Therefore, the application must not alter the content of the EEPROM while a frame acquisition is going on.
- The number of WRITE cycles into the EEPROM is limited. It should not exceed 100 WRITE operations.

#### 8.4. Register map

Address	Register name	Ref.	Description	Access standard	Access advanced
<b>Memory and EEPROM controller registers</b>					
0x00	IC_TYPE	8.6.1.	Unique IC Type for device family identification	R	R
0x01	IC_VERSION	8.6.1.	Unique IC Version for device mask identification	R	R
0x02 ... 0x10	reserved			---	---
0x11	EE_ADDR	8.6.2.	Address for indirect read/write access to EEPROM	RW	RW
0x12	EE_DATA	8.6.2.	Data for indirect read/write access to EEPROM	RW	RW
0x13	EE_MASK	8.6.2.	Mask bits for indirect write access to EEPROM	RW	RW
0x14	PROG_EE_REQ	8.6.3.	Requests programming of segments of the EEPROM	RW	RW
0x15 ... 0x1F	reserved			---	---
<b>Strap registers</b>					
0x20 0x21	Strap_hi Strap_lo	8.6.4.	Strap Scan Value Hold Register	R	R
<b>Modulation table registers</b>					
0x22 0x23 0x24	MT_0_hi reserved MT_0_lo	8.6.5.	MT-vector: Sine/PN mode DCS0	RW	RW
0x25 0x26 0x27	MT_1_hi reserved MT_1_lo	8.6.5.	MT-vector: Sine/PN mode DCS1	RW	RW
0x28 0x29 0x2A	MT_2_hi reserved MT_2_lo	8.6.5.	MT-vector: Sine/PN mode DCS2	RW	RW
0x2B 0x2C 0x2D	MT_3_hi reserved MT_3_lo	8.6.5.	MT-vector: Sine/PN mode DCS3	RW	RW
0x2E ... 0x5F	reserved			---	---
<b>Temperature sensor registers</b>					
0x60 0x61	Sum_Temp_tl_hi Sum_Temp_tl_lo	8.6.6.	Temperature sensor top-left	R	R
0x62 0x63	Sum_Temp_tr_hi Sum_Temp_tr_lo	8.6.6.	Temperature sensor top-right	R	R
0x64 0x65	Sum_Temp_bl_hi Sum_Temp_bl_lo	8.6.6.	Temperature sensor bottom-left	R	R
0x66 0x67	Sum_Temp_br_hi Sum_Temp_br_lo	8.6.6.	Temperature sensor bottom-right	R	R
0x68 ... 0x6F	reserved			---	---

Table 41: Address map of the control page (0x00 ~ 0x7F)

Address	Register name	Ref.	Description	Access standard	Access advanced
<b>DLL manual control registers</b>					
0x70	DLL_status	8.6.7.	DLL manual control: Status	---	R
0x71 0x72	DLL_fine_ctrl_ext_hi DLL_fine_ctrl_ext_lo	8.6.8.	DLL manual control: External fine control	---	RW
0x73	DLL_coarse_ctrl_ext	8.6.9.	DLL manual control: External coarse control	---	RW
0x74 0x75	DLL_fine_low_bank_rb_hi DLL_fine_low_bank_rb_lo	8.6.10.	DLL manual control: Fine lowest bank read back	---	R
0x76 0x77	DLL_fine_bank_rb_hi DLL_fine_bank_rb_lo	8.6.10.	DLL manual control: Fine bank read back	---	R
0x78	DLL_fine_page_rb	8.6.10.	DLL manual control: Fine section page read back	---	R
0x79	DLL_coarse_rb	8.6.11.	DLL manual control: Coarse control read back	---	R
0x7A 0x7C	reserved			---	---
<b>Configuration mode registers</b>					
0x7D	CFG_Mode_Control	8.6.12.	Configuration mode: Control register	---	RW
0x7E 0x7F	reserved			---	---

Table 41 cont.: Address map of the control page (0x00 ~ 0x7F)

Address	Register name	Ref.	Description	Access standard	Access advanced
<b>CGU registers, SEG0 *</b>					
0x80	CLK_enables	8.7.1.	CGU register, SEG0.*: Clock enable	RW	RW
0x81 ... 0x84	reserved			---	---
0x85	MOD_CLK_divider	8.7.2.	CGU register, SEG0.*: MOD clock divider	RW	RW
0x86 ... 0x88	reserved			---	---
0x89	TCMI_CLK_divider	8.7.3.	CGU register, SEG0.*: TCMI clock	RW	RW
0x8A	reserved			---	---
<b>Modulator/demodulator registers, SEG1 *</b>					
0x8B	Demodulation_delays	8.7.4.	Mod./demod. registers, SEG1 *: Delays	RW	RW
0x8C 0x8D	PN_POLY_hi PN_POLY_lo	8.7.5.	Mod./demod. registers, SEG1 *: PN polynomial	RW	RW
0x8E 0x8F	reserved			---	---
0x90	LED_driver	8.7.6.	Mod./demod. registers, SEG1 *: LED driver	RW	RW
0x92	MOD_Control **	8.7.7.	Mod./demod. registers, SEG1 *: Modulation select	RW	RW
0x93	Dist_offset **	8.7.8.	Mod. /demod. registers, SEG1 *: Distance offset	RW	RW
<b>Pixel operating and readout control registers</b>					
0x94	Resolution_reduction **	8.7.9.	Pixel operating and readout control	RW	RW
<b>Frame column / row mapping registers</b>					
0x95	Readout_dir **	8.7.10.	Frame column / row mapping: readout direction	RW	RW
0x96 0x97	ROI_tl_x_hi ** ROI_tl_x_lo **	8.7.11.	Frame column / row mapping: ROI top-left x	RW	RW
0x98 0x99	ROI_br_x_hi ** ROI_br_x_lo **	8.7.11.	Frame column / row mapping: ROI bottom-right x	RW	RW
0x9A	ROI_tl_y **	8.7.11.	Frame column / row mapping: ROI top-left y	RW	RW
0x9B	ROI_br_y **	8.7.11.	Frame column / row mapping: ROI bottom-right y	RW	RW
<b>Shutter control registers</b>					
0x9C 0x9D	reserved			---	---
0x9E 0x9F	Int_len_mgx1_hi ** Int_len_mgx1_lo **	8.7.12.	Shutter control: Integration time mgx1	RW	RW
0xA0 0xA1	INTM_hi ** INTM_lo **	8.7.13.	Shutter control: Integration time multiplier	RW	RW
0xA2 0xA3	Int_len_hi ** Int_len_lo **	8.7.14.	Shutter control: Integration time	RW	RW
0xA4	Shutter_Control	8.7.15.	Shutter control: Video mode / SW control	RW	RW
<b>Power control registers</b>					
0xA5	Power_Control (analog)	8.7.16.	Power control	RW	RW
<b>DLL synchronization registers</b>					
0xA6 0xA7	DLL_en_del_hi DLL_en_del_lo	8.7.17.	DLL synchronization: DLL pre-synchronization time	RW	RW
0xA8 0xA9	DLL_en_hi DLL_en_lo	8.7.17.	DLL synchronization: DLL synchronization time	RW	RW
0xAA 0xAB	DLL_measurement_rate_hi ** DLL_measurement_rate_lo **	8.7.18.	DLL synchronization: DLL measurement rate	RW	RW

Table 42: Address map of EEPROM page-0 (0x80 ~ 0xFF)

Address	Register name	Ref.	Description	Access standard	Access advanced
<b>DLL control registers</b>					
0xAC	reserved			---	---
0xAD	DLL_match_width	8.7.19.	DLL control: Match width	---	RW
0xAE	DLL_control	8.7.20.	DLL control	RW	RW
0xAF ... 0xC9	reserved			---	---
<b>I<sup>2</sup>C registers, SEG4 *</b>					
0xCA	I <sup>2</sup> C_address	8.7.21.	I <sup>2</sup> C register, SEG4 *: Address	R	R
0xCB	I <sup>2</sup> C_control	8.7.21.	I <sup>2</sup> C register, SEG4 *: Control	RW	RW
<b>TCMI registers</b>					
0xCC	TCMI_polarity	8.7.22.	TCMI register	RW	RW
0xCD ... 0xE7	reserved			---	---
<b>Temperature sensor calibration registers (factory settings)</b>					
0xE8	Temp_tl_cal1	8.7.23.	Temperature sensor top-left calibration point 1	R	RW
0xE9	Temp_tl_cal2	8.7.23.	Temperature sensor top-left calibration point 2	R	RW
0xEA	Temp_tr_cal1	8.7.23.	Temperature sensor top-right calibration point 1	R	RW
0xEB	Temp_tr_cal2	8.7.23.	Temperature sensor top-right calibration point 2	R	RW
0xEC	Temp_bl_cal1	8.7.23.	Temperature sensor bottom-left calibration point 1	R	RW
0xED	Temp_bl_cal2	8.7.23.	Temperature sensor bottom-left calibration point 2	R	RW
0xEE	Temp_br_cal1	8.7.23.	Temperature sensor bottom-right calibration point 1	R	RW
0xEF	Temp_br_cal2	8.7.23.	Temperature sensor bottom-right calibration point 2	R	RW
<b>Free EEPROM registers (for customer use), SEG6 *</b>					
0xF0	User_1	8.7.24.	User register 1 for user data	RW	RW
0xF1	User_2	8.7.24.	User register 2 for user data	RW	RW
<b>CHIP ID registers (factory settings), SEG7 *</b>					
0xF2 ... 0xF4	reserved			---	---
0xF5	ENGINEERING_ID	8.7.25.	Chip ID register SEG6 *: Engineering ID for MPWs	R	R
0xF6 0xF7	WAFER_ID_MSB WAFER_ID_LSB	8.7.26.	Chip ID register SEG6 *: Wafer ID	R	R
0xF8 0xF9	CHIP_ID_MSB CHIP_ID_LSB	8.7.27.	Chip ID register SEG6 *: Chip ID on wafer	R	R
0xFA	PART_TYPE	8.7.28.	Chip ID register SEG6 *: Part type	R	R
0xFB	PART_VERSION	8.7.28.	Chip ID register SEG6 *: Part version	R	R
0xFC ... 0xFF	reserved			---	---

Table 42 cont.: Address map of EEPROM page-0 (0x80 ~ 0xFF)

Notes:

\* EEPROM protected segments. Protection will be enabled during production testing.

\*\* Shadowed (double-buffered) registers which can be updated on-the-fly via I<sup>2</sup>C, while a frame acquisition is going on. The new values get copied and used at the start of the next frame. Shadow registers can be bypassed by setting Pixel\_test(0x7B).shadow\_regs\_bypass = 1. In this case, written values take effect immediately.

### 8.5. Register description: Explanation example

Register name: MOD_Control **				Description: Mod./demod. registers, SEG1 *: Modulation select				Address: 0x92
Bit No.	7	6	5	4	3	2	1	0
Bit name	mod_sel		dcs_sel		int_len _mgx1_en	lfsr_sel		
Operation	Access option for the register ■ R Read ■ W Write ■ RW Read or Write ■ (RW) Note: Needs epc support to access this function by user: Read or Write							
Default	Default factory setting of the register or register bits							

### 8.6. Register description: Control Page (0x00 ~ 0x7F)

#### 8.6.1. IC\_

IC_TYPE	Unique IC Type for device family identification	0x00
Operation	R	
Default	according to type	

IC_VERSION	Unique IC Version for device mask identification	0x01
Operation	R	
Default	according to mask	

#### 8.6.2. EE\_ (ADDR, DATA, MASK)

EE_ADDR	Address for indirect read/write access to EEPROM	0x11
Operation	RW	
Default	0x00 (note 1)	

Note1: Default (reset) value is internally modified during start-up sequence. Therefore, when this register is read via I<sup>2</sup>C, a different value may be observed.

EE_DATA	Data for indirect read/write access to EEPROM	0x12
Operation	RW	
Default	0x3F	

EE_MASK	Mask bits for indirect write access to EEPROM	0x13
Operation	RW	
Default	0x00	

#### 8.6.3. PROG\_EE\_REQ

PROG_EE_REQ	Requests programming of segments of the EEPROM	0x14
Operation	RW	
Default	0x00	

#### 8.6.4. Strap\_

Strap_hi				Strap Scan Value Hold Register (high)				0x20
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved	strap14	strap13	reserved				
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see below Strap\_lo register

Strap_lo				Strap Scan Value Hold Register (low)				0x21
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved							strap0
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Strap15: reserved, displays pin XYSNC\_SAT\_CFG

Strap14: I<sup>2</sup>C Device Address: A1, on HYSNC\_A1

Strap13: I<sup>2</sup>C Device Address: A0, on VYSNC\_PSDIAG\_A0

Strap12: reserved, displays pin DCLK

Strap11 ... Strap0: reserved, displays pins DATA[11:0]

Note 1: Default start-up values of these registers are only valid until end of reset phase. Values might be overwritten by external pull-up resistors during strap scan phase when reset is released.

Note 2: Read access on this register does not initiate a strap scan phase. This register simply holds the last scanned value when reset is released.

#### 8.6.5. MT\_

MT_0_hi				MT-vector: Sine/PN mode DCS 0 (high)				0x22
Bit No.	23	22	21	20	19	18	17	16
Bit name	reserved		readout_mode		mgx1_dcs_num		mgx0_dcs_num	
Operation	RW							
Default	0	0	1	1	0	1	0	0
	0x34							

Modulation Table Vector bit definitions:

readout\_mode: Readout mode of the vector  
 00: reserved  
 01: single-ended readout from MGA  
 10: single-ended readout from MGB  
 11: differential-ended readout from MGA and MGB

mgx1\_dcs\_num: DCS frame number of the vector for mgx1 modulator outputs (mga1, mgb1)  
 00: DCS 0  
 01: DCS 1  
 10: DCS 2  
 11: DCS 3

mgx0\_dcs\_num: DCS frame number of the vector for mgx0 modulator outputs (mga0, mgb0)  
 00: DCS 0  
 01: DCS 1  
 10: DCS 2  
 11: DCS 3

MT_0_lo				MT-vector: Sine/PN mode DCS 0 (low)				0x24
Bit No.	7	6	5	4	3	2	1	0
Bit name	override_led_modulated_B&W	reserved	override_led_off_integ/ override_led_on_mga_b&w	reserved	override_mgb_on_integ	override_mga_on_integ	override_mgb_off	override_mga_off
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

override\_led\_modulated\_B&W:

- Sine/PN/B&W: When LED\_driver.led\_on = 1 (torch function):
  - 0: LED/LD on (DC) during integration period
  - 1: LED/LD is modulated during integration period

override\_led\_off\_integ/override\_led\_on\_mga\_b&w:

- Sine/PN/B&W:
  - 0: LED/LD is modulated
  - 1: LED/LD stays off entire integration time

override\_mgb\_on\_integ:

MGB stays on (conducting) entire integration time

override\_mga\_on\_integ:

MGA stays on (conducting) entire integration time

override\_mgb\_off:

MGB stays off (non-conducting) all the time

override\_mga\_off:

MGA stays off (non-conducting) all the time

Note 1: Priorities: b0 over b2, b1 over b3.

Note 2: b5..b0 are ignored during DLL synchronization

MT_1_hi				MT-vector: Sine/PN mode DCS 1 (high)				0x25
Bit No.	23	22	21	20	19	18	17	16
Bit name	reserved		readout_mode		mgx1_dcs_num		mgx0_dcs_num	
Operation	RW							
Default	0	0	1	1	0	0	0	1
	0x31							

Note: Description see MT\_0\_hi

MT_1_lo				MT-vector: Sine/PN mode DCS 1 (low)				0x27
Bit No.	7	6	5	4	3	2	1	0
Bit name	override_led_modulated_B&W	reserved	override_led_off_integ/ override_led_on_mga_b&w	reserved	override_mgb_on_integ	override_mga_on_integ	override_mgb_off	override_mga_off
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see MT\_0\_lo

MT_2_hi				MT-vector: Sine/PN mode DCS 2 (high)				0x28
Bit No.	23	22	21	20	19	18	17	16
Bit name	reserved		readout_mode		mgx1_dcs_num		mgx0_dcs_num	
Operation	RW							
Default	0	0	1	1	1	1	1	0
	0x3E							

Note: Description see MT\_0\_hi

MT_2_lo				MT-vector: Sine/PN mode DCS 2 (low)				0x2A
Bit No.	7	6	5	4	3	2	1	0
Bit name	override_led_modulated_B&W	reserved	override_led_off_integ/override_led_on_mga_b&w	reserved	override_mgb_on_integ	override_mga_on_integ	override_mgb_off	override_mga_off
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see MT\_0\_lo

MT_3_hi				MT-vector: Sine/PN mode DCS 3 (high)				0x2B
Bit No.	23	22	21	20	19	18	17	16
Bit name	reserved		readout_mode		mgx1_dcs_num		mgx0_dcs_num	
Operation	RW							
Default	0	0	1	1	1	0	1	1
	0x3B							

Note: Description see MT\_0\_hi

MT_3_lo				MT-vector: Sine/PN mode DCS 3 (low)				0x2D
Bit No.	7	6	5	4	3	2	1	0
Bit name	override_led_modulated_B&W	reserved	override_led_off_integ/override_led_on_mga_b&w	reserved	override_mgb_on_integ	override_mga_on_integ	override_mgb_off	override_mga_off
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see MT\_0\_lo

### 8.6.6. Sum\_Temp\_

Sum_Temp_tl_hi				Temperature sensor top-left (high)				0x60
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved		Sum_Temp_tl[13:8]					
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see Sum\_Temp\_tl\_lo

Sum_Temp_tl_lo				Temperature sensor top-left (low)				0x61
Bit No.	7	6	5	4	3	2	1	0
Bit name	Sum_Temp_tl[7:0]							
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Sum\_Temp\_tl\_lo: Sum of 6 values (every 4th reading) of temperature sensor top-left

Sum_Temp_tr_hi			Temperature sensor top-right (high)					0x62
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved		Sum_Temp_tr[13:8]					
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see Sum\_Temp\_tr\_lo

Sum_Temp_tr_lo			Temperature sensor top-right (low)					0x63
Bit No.	7	6	5	4	3	2	1	0
Bit name	Sum_Temp_tr[7:0]							
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Sum\_Temp\_top-right: Sum of 6 values (every 4th reading) of temperature sensor top-right

Sum_Temp_bl_hi			Temperature sensor bottom-left (high)					0x64
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved		Sum_Temp_bl[13:8]					
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see Sum\_Temp\_bl\_lo

Sum_Temp_bl_lo			Temperature sensor bottom-left (low)					0x65
Bit No.	7	6	5	4	3	2	1	0
Bit name	Sum_Temp_bl[7:0]							
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Sum\_Temp\_bottom-left: Sum of 6 values (every 4th reading) of temperature sensor bottom-left

Sum_Temp_br_hi			Temperature sensor bottom-right (high)					0x66
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved		Sum_Temp_br[13:8]					
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see Sum\_Temp\_br\_lo

Sum_Temp_br_lo			Temperature sensor bottom-right (low)					0x67
Bit No.	7	6	5	4	3	2	1	0
Bit name	Sum_Temp_br[7:0]							
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

Sum\_Temp\_bottom-right: Sum of 6 values (every 4th reading) of temperature sensor bottom-right

### 8.6.7. DLL\_status

DLL_status				DLL manual control: Status				0x70
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved		dll_fb_lead_stat	dll_ref_lead_stat	dll_error_stat	dll_filter_stat	dll_match_stat	dll_lock_stat
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

dll\_fb\_lead\_stat: Live status signal indicating the feedback waveform is leading over the reference. Used to implement the delay control by SW.

dll\_ref\_lead\_stat: Live status signal indicating the reference waveform is leading over the feedback. Used to implement the delay control by SW.

dll\_error\_stat: Asserted when the delay to be compensated is out of reach for the delay line.

dll\_filter\_stat: Asserted when the DLL jitter filter is active.

dll\_match\_stat: Asserted when the residual delay between the reference and feedback is less than ~120ps.

dll\_lock\_stat: Asserted when the residual delay between the reference and feedback is less than ~2.4ns.

### 8.6.8. DLL\_fine\_ctrl\_ext

DLL_fine_ctrl_ext_hi				DLL manual control: External fine control (high)				0x71
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved						DLL_fine_ctrl_ext[9:8]	
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see DLL\_fine\_ctrl\_ext\_lo

DLL_fine_ctrl_ext_lo				DLL manual control: External fine control (low)				0x72
Bit No.	7	6	5	4	3	2	1	0
Bit name	DLL_fine_ctrl_ext[7:0]							
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

DLL\_fine\_ctrl\_ext: Fine control from user. Valid only when DLL\_control.dll\_ctrl\_ext = 1 (see section 8.7.20., DLL\_control)

### 8.6.9. DLL\_coarse\_ctrl\_ext

DLL_coarse_ctrl_ext				DLL manual control: External coarse control				0x73
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved		dll_coarse_ctrl_ext					
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

dll\_coarse\_ctrl\_ext: Coarse control from user. Valid only when DLL\_control.dll\_ctrl\_ext = 1 (see section 8.7.20., DLL\_control)

### 8.6.10. DLL\_fine\_

DLL_fine_low_bank_rb_hi				DLL manual control: Fine lowest bank read back (high)				0x74
Bit No.	15	14	13	12	11	10	9	8
Bit name	DLL_fine_low_bank_rb[15:8]							
Operation	R							
Default	0x00							

DLL_fine_low_bank_rb_lo				DLL manual control: Fine lowest bank read back (low)				0x75
Bit No.	7	6	5	4	3	2	1	0
Bit name	DLL_fine_low_bank_rb[7:0]							
Operation	R							
Default	0x00							

DLL_fine_bank_rb_hi				DLL manual control: Fine bank read back (high)				0x76
Bit No.	15	14	13	12	11	10	9	8
Bit name	DLL_fine_bank_rb[15:8]							
Operation	R							
Default	0x00							

DLL_fine_bank_rb_lo				DLL manual control: Fine bank read back (low)				0x77
Bit No.	7	6	5	4	3	2	1	0
Bit name	DLL_fine_bank_rb[7:0]							
Operation	R							
Default	0x00							

DLL_fine_page_rb				DLL manual control: Fine section page read back				0x78
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved						dll_fine_page_rb	
Operation	R							
Default	0	0	0	0	0	0	x	x
	0x00							

dll\_fine\_page\_rb: Fine section page read back

### 8.6.11. DLL\_coarse\_rb

DLL_coarse_rb				DLL manual control: Coarse control read back				0x79
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved			dll_coarse_rb[5:0]				
Operation	R							
Default	0	0	0	0	0	0	0	0
	0x00							

### 8.6.12. CFG\_Mode\_

CFG_Mode_Control				Configuration mode: Control register				0x7D
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved			sys_clk_bypass	pll_bypass	pll_en	reserved	
Operation	RW							
Default	0	0	0	0	0	1	0	0
	0x04 (Note 1)							

sys\_clk\_bypass: Bypass OSC clock directly to the sys\_clk output  
 0: normal  
 1: bypass (sys\_clk = osc\_clk)

pll\_bypass: Bypass OSC clock directly to the PLL output as clock source to the CGU  
 0: normal  
 1: bypass (pll\_clk = osc\_clk)

pll\_en: Enable PLL block  
 0: disable  
 1: enable

Note 1: Default (reset) value is internally modified during start-up sequence. Therefore, when this register is read via I<sup>2</sup>C, a different value will be observed.

### 8.7. Register description: EEPROM Page-0 (0x80 ~ 0xFF)

#### 8.7.1. CLK\_enables

CLK_enables			CGU register, SEG0.*: Clock enable					0x80
Bit No.	7	6	5	4	3	2	1	0
Bit name	all_clks_en	mod_clk_sel	reseved				mod_clk_en	dll_clk_en
Operation	RW							
Default	0	0	1	1	1	1	1	1
	0x3F							

CGU clock enable register:

all\_clks\_en: Force all clock enables  
 0: disable  
 1: enable

mod\_clk\_sel: Select modulator clock source  
 0: mod\_clk, from CGU  
 1: ext\_mod\_clk, from MODCLK input pin

Note: Note: sys\_clk is always running. It cannot be disabled.

#### 8.7.2. MOD\_CLK\_divider

MOD_CLK_divider			CGU register, SEG0.*: MOD clock divider					0x85
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved			mod_clk_div				
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

mod\_clk\_div: Provides the clock to the LED / pixel field modulator/demodulator circuits, respectively, by integer division of the PLL clock.  
 Default = 0:  $f_{\text{mod\_clk}} = 80\text{MHz} / (\text{mod\_clk\_div} + 1) = 80\text{MHz} / 1 = 80\text{MHz}$

### 8.7.3. TCMI\_CLK\_divider

TCMI_CLK_divider				CGU register, SEG0*: TCMI clock				0x89
Bit No.	7	6	5	4	3	2	1	0
Bit name	dclk_skew_en	tcmi_drv2_en	reserved	tcmi_clk_div				
Operation	RW							
Default	0	0	0	0	0	0	0	1
	0x01							

dclk\_skew\_en: DCLK skew enable  
0: disable  
1: enable

Note1: Use dclk\_skew\_en = 1 to delay DCLK edge (typ. 2ns) to compensate PCB delays. Might be particularly useful when tcmi\_clk\_div = 0 (divide by 1). When set normal, DCLK edge is centered with respect to other TCMI \*SYNC\*, DATA[11:0] outputs.

tcmi\_drv2\_en: TCMI pins driver-2 enable  
0: disable  
1: enable

Note2: Use tcmi\_drv2\_en = 1 to enable driver-2 of all TCMI output pins. This may require special VDDIO/VSSIO supply coupling to avoid spikes - use with caution!

tcmi\_clk\_div: Provides the clock to the TCMI by integer division of the PLL clock.  
Default = 1:  $f_{\text{tcmi\_clk}} = 80\text{MHz} / (\text{tcmi\_clk\_div} + 1) = 80\text{MHz} / 2 = 40\text{MHz}$

### 8.7.4. Demodulation\_delays

Demodulation_delays				Mod./demod. registers, SEG1 *: Delays				0x8B
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved				mgx_del_sel			
Operation	RW							
Default	0	0	0	0	0	0	0	1
	0x01							

mgx\_del\_sel: Number of pll\_clk period delays on the abd, abg, mga, mgb signals in order to compensate internal LED driver delay (all modulation modes)  
0: no delay  
1: 1 clock  
2: 2 clocks  
...

12: 12 clocks  
13 ... 15: reserved

Note 1: When DLL is enabled, mgx\_del\_sel must be initialized to a higher value with respect to the external LED/LD circuit's initial delay + max. delay deviation over the system's operating conditions. Minimum recommendation: 2.

Note 2: When mgx\_del\_sel set > 12 (i.e. 13, 14 or 15), delay is internally limited to 12 pll\_clk periods.

### 8.7.5. PN\_

PN_POLY_hi			Mod./demod. registers, SEG1 *: PN polynomial (high)					0x8C
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved	pn_poly[14:8]						
Operation	RW							
Default	0	0	0	0	1	0	0	0
	0x08							

Note: Description see PN\_POLY\_lo

PN_POLY_1o				Mod./demod. registers, SEG1 *: PN polynomial (low)				0x8D
Bit No.	7	6	5	4	3	2	1	0
Bit name	pn_poly[7:0]							
Operation	RW							
Default	0	0	0	0	0	1	0	1
	0x05							

pn\_poly: PN Polynomial configuration (default: 2'053)

### 8.7.6. LED\_driver

LED_driver			Mod./demod. registers, SEG1 *: LED driver					0x90
Bit No.	7	6	5	4	3	2	1	0
Bit name	led_drv_sel		reserved	led_on	reserved	led_drv_en	led_inv_en	led_ssr_en
Operation	RW							
Default	1	1	0	0	0	1	0	0
	0xC4							

led\_drv\_sel: LED driver output max. current select e.g. for LED current 200mA  $\cong$  100%  
00: 33%  
01: 46%  
10: 64%  
11: 100%

led\_on: LED/LD permanently on (DC) (torch function)  
0: off  
1: on

led\_drv\_en: LED driver internal power enable (independent of the modulator)  
0: disable  
1: enable

led\_inv\_en: LED signal inversion. Inversion of the output levels on pin LED.  
0: disable (when active: signal on pin LED = 0, VSSLED)  
1: enable (when active: active: signal on pin LED = 1, open-drain)

Note: When led\_inv\_en = 0: It can directly sink the LED turn-on current (up to 200mA peak) without additional external driver.  
When led\_inv\_en = 1: It needs an external pull-up resistor (open-drain) to drive the inverted value for the external LED drive circuitry.

led\_ssr\_en: LED slow slew rate enable.  
0: disable  
1: enable

### 8.7.7. MOD\_Control \*\*

MOD_Control **				Mod./demod. registers, SEG1 *: Modulation select				0x92
Bit No.	7	6	5	4	3	2	1	0
Bit name	mod_sel		dcs_sel		int_len_mgx1_en	lfsr_sel		
Operation	RW							
Default	0	0	1	1	0	1	0	0
	0x34							

- mod\_sel: Modulation select  
 00: Sinusoidal mode  
 01: PN mode  
 10: reserved  
 11: reserved
- dcs\_sel: Number of DCS read-outs select  
 00: 1x DCSx: DCS0  
 01: 2x DCSx: DCS0, DCS1  
 10: reserved  
 11: 4x DCSx: DCS0, DCS1, DCS2, DCS4
- int\_len\_mgx1\_en: Int\_Len\_mgx1\_hi/lo enable (refer to DUAL MGX mode – single DCS acquisition with different integration time)  
 0: disable  
 1: enable
- Note: int\_len\_mgx1\_en must be enabled only when dual\_mgx\_mode = 1, otherwise it is not effective (see Figure 33)
- lfsr\_sel: Number of LFSR stages select  
 000: reserved  
 001: 14  
 010: 13  
 011: 12  
 100: 11  
 101: 10  
 110: 9  
 111: 8

### 8.7.8. Dist\_offset \*\*

Dist_offset **				Mod./demod. registers, SEG1 *: Distance offset				0x93
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved	dist_offset						
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

- dist\_offset: Number of pll\_clk period delays on the abd, abg, mga, mgb signals in order to capture reflected LED/LD light from faraway objects with PN mode
- Note: It is effective in all modulation modes.  
 Therefore, it is recommended to set it to 0 for all modulation modes other than PN mode.

### 8.7.9. Resolution\_reduction \*\*

Resolution_reduction **			Pixel operating and readout control					0x94
Bit No.	7	6	5	4	3	2	1	0
Bit name	dual_mgx_mode	reserved	pixel_bin_mode		res_red_row		res_red_col	
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

dual\_mgx\_mode: Dual MGX mode (refer to chapter Fehler: Referenz nicht gefunden, Fehler: Referenz nicht gefunden)  
 0: single  
 1: dual

pixel\_bin\_mode: Pixel binning mode  
 00: no binning  
 01: horizontal binning (x-axis) (only when res\_red\_col <> 00)  
 10: vertical binning (y-axis) (only when res\_red\_row <> 00)  
 11: horizontal + vertical binning (only when res\_red\_col <> 00 AND res\_red\_row <> 00)

Note 1: Pixel binning cannot be used with dual MGX modes.

res\_red\_row: Row reduction: Selects resolution on y-axis  
 00: full (0, 1, 2, ...)  
 01: half (0, 2, 4, ...)  
 10: quarter (0, 4, 8, ...)  
 11: one eight (0, 8, 16, ...)

res\_red\_col: Column reduction: Selects resolution on x-axis  
 00: full (0, 1, 2, ...)  
 01: half (0, 2, 4, ...)  
 10: reserved  
 11: reserved

Note 2: If binning is selected, then the corresponding reduction mode should also be chosen (res\_red\_row, res\_red\_col).

### 8.7.10. Readout\_dir \*\*

Readout_dir **			Frame column / row mapping: readout direction					0x95
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved						col_dir_sel	reserved
Operation	RW							
Default	0	0	0	0	0	0	1	1
	0x03							

col\_dir\_sel: Column readout direction  
 0: decrement  
 1: increment

### 8.7.11. ROI\_

ROI_tl_x_hi **			Frame column / row mapping: ROI top-left x (high)					0x96
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved							ROI_tl_x[8]
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see ROI\_tl\_x\_lo \*\*

ROI_tl_x_lo **				Frame column / row mapping: ROI top-left x (low)				0x97
Bit No.	7	6	5	4	3	2	1	0
Bit name	ROI_tl_x[7:0]							
Operation	RW							
Default	0	0	0	0	0	1	0	0
	0x04 (default: 4)							

ROI\_tl\_x: Refer to chapter 5.6.3., section ROI (Region of Interest)

ROI_br_x_hi **				Frame column / row mapping: ROI bottom-right x (high)				0x98
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved							ROI_br_x[8]
Operation	RW							
Default	0	0	0	0	0	0	0	1
	0x01							

Note: Description see ROI\_br\_x\_lo \*\*

ROI_br_x_lo **				Frame column / row mapping: ROI bottom-right x (low)				0x99
Bit No.	7	6	5	4	3	2	1	0
Bit name	ROI_br_x[7:0]							
Operation	RW							
Default	0	1	0	0	0	0	1	1
	0x43 (default: 323)							

ROI\_br\_x: Refer to chapter 5.6.3., section ROI (Region of Interest)

ROI_tl_y **				Frame column / row mapping: ROI top-left y				0x9A
Bit No.	7	6	5	4	3	2	1	0
Bit name	ROI_tl_y							
Operation	RW							
Default	0	0	0	0	0	1	1	0
	0x06 (default: 6)							

ROI\_tl\_y: Refer to chapter 5.6.3., section ROI (Region of Interest)

ROI_br_y **				Frame column / row mapping: ROI bottom-right y				0x9B
Bit No.	7	6	5	4	3	2	1	0
Bit name	ROI_br_y							
Operation	RW							
Default	0	1	1	1	1	1	0	1
	0x7D (default: 125)							

ROI\_br\_y: Refer to chapter 5.6.3., section ROI (Region of Interest)

### 8.7.12. Int\_len\_mgx1\_

Int_len_mgx1_hi **				Shutter control: Integration time mgx1 (high)				0x9E
Bit No.	15	14	13	12	11	10	9	8
Operation	RW							
Default	0	0	0	0	0	1	1	1
	0x07							

Note: Description see Int\_len\_mgx1\_lo \*\*

Int_len_mgx1_lo **				Shutter control: Integration time mgx1 (low)				0x9F
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	1	1	1	1	1	1	1	1
	0xFF							

Int\_len\_mgx1: Number of mod\_clk periods for the integration time of mgx1 (Default: 2'047).  
See Int\_len\_hi/lo registers (0xA2/0xA3) for functional definition details.

Note: int\_len\_mgx1\_en = 0: These registers are updated simultaneously to the same value every time the Int\_len\_hi/lo (0xA2/0xA3) registers are written by I<sup>2</sup>C.

int\_len\_mgx1\_en = 1: Int\_len\_mgx1\_hi/lo can be updated independent of Int\_len\_1\_hi/lo. This enables asymmetric integration times for upper and lower pixels rows

### 8.7.13. INTM\_

INTM_hi **				Shutter control: Integration time multiplier (high)				0xA0
Bit No.	15	14	13	12	11	10	9	8
Bit name	reserved						INTM[9:8]	
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see INTM\_lo \*\*

INTM_lo **				Shutter control: Integration time multiplier (low)				0xA1
Bit No.	7	6	5	4	3	2	1	0
Bit name	INTM[7:0]							
Operation	RW							
Default	0	0	0	0	0	0	0	1
	0x01							

INTM: Multiplier of the basic integration length set in Int\_len

Note: Minimum INTM value = 1

### 8.7.14. Int\_len\_

Int_len_hi **				Shutter control: Integration time (high)				0xA2
Bit No.	15	14	13	12	11	10	9	8
Operation	RW							
Default	0	0	0	0	0	1	1	1
	0x07							

Note: Description see Int\_len\_lo \*\*

Int_len_lo **				Shutter control: Integration time(low)				0xA3
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	1	1	1	1	1	1	1	
	0xFF							

Int\_len: Number of mod\_clk periods for the PN integration time.  
Default = 2'047: Integration time = INTM \* (Int\_len + 1) \* t<sub>mod\_clk</sub> = 25.6us

Note: Sine mode: (Int\_len + 1) should be evenly divisible by 4.  
Min Int\_len = 7 (100ns).  
PN mode (Int\_len + 1) should be evenly divisible by 4 and correspond to the LSFR setting.  
Min Int\_len = 1'019 (12.75µs).

### 8.7.15. Shutter\_Control

Shutter_Control				Shutter control: Video mode / SW control				0xA4
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved						multi_frame_en	shutter_en
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

multi\_frame\_en: Multiple frames (video mode). Refer to chapter Fehler: Referenz nicht gefunden, Fehler: Referenz nicht gefunden.  
0: disable  
1: enable

shutter\_en: Shutter release (SW control)  
0: disable  
1: enable: starts acquisition (auto cleared)

Note: shutter\_en is not auto-cleared when multi\_frame\_en = 1

### 8.7.16. Power\_Control (analog)

Power_Control (analog)				Power control				0xA5
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved				reserved	See note below		
Operation	RW							
Default	0	0	0	0	0	1	1	1
	0x07							

Note: Refer to chapter 7.7., Power saving options, Table 39

### 8.7.17. DLL\_en\_

DLL_en_del_hi				DLL synchronization: DLL pre-synchronization (high)				0xA6
Bit No.	15	14	13	12	11	10	9	8
Operation	RW							
Default	0	0	0	0	0	0	1	1
	0x03							

Note: Description see DLL\_en\_del\_lo

DLL_en_del_lo				DLL synchronization: DLL pre-synchronization (low)				0xA7
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	0	0	0	1	1	1	1	1
	0x1F							

DLL\_en\_del: Number of mod\_clk periods before the DLL enable (DLL pre-synchronization time).  
 Default = 799: delay = (DLL\_en\_del + 1) \* t<sub>mod\_clk</sub> = 10us

DLL_en_hi				DLL synchronization: DLL synchronization time (high)				0xA8
Bit No.	15	14	13	12	11	10	9	8
Operation	RW							
Default	0	0	0	0	1	0	0	1
	0x09							

Note: Description see DLL\_en\_lo

DLL_en_lo				DLL synchronization: DLL synchronization time (low)				0xA9
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	0	1	0	1	1	1	1	1
	0x5F							

DLL\_en: Number mod\_clk periods for the DLL synchronization time.  
 Default = 2'399: delay = (DLL\_en + 1) \* t<sub>mod\_clk</sub> = 30us

#### 8.7.18. DLL\_measurement\_rate\_

DLL_measurement_rate_hi **				DLL synchronization: DLL measurement rate (high)				0xAA
Bit No.	15	14	13	12	11	10	9	8
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

Note: Description see DLL\_measurement\_rate\_lo \*\*

DLL_measurement_rate_lo **				DLL synchronization: DLL measurement rate (low)				0xAB
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	0	0	0	0	0	1	0	0
	0x04							

DLL\_measurement\_rate: Number of DCS acquisitions for the DLL measurement to compensate for the phase shift of the LED driver path. When equal to 0, the modulator does not trigger the DLL to re-measure, it simply keeps the previously measured/programmed delay value during the following frame acquisition.

Note: The DLL measurement rate should be set to a multiple of the dcs frame number e.g. 4x DCS: DLL\_measurement\_rate = 4.

### 8.7.19. DLL\_match\_width

DLL_match_width				DLL control: Match width				0xAD
Bit No.	7	6	5	4	3	2	1	0
Operation	RW							
Default	1	1	1	1	1	1	1	1
	0xFF							

### 8.7.20. DLL\_control

DLL_control				DLL control				0xAE
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved			dll_ctrl_ext_en	dll_rate_cnt_rst	dll_ctrl_ext	dll_fb_pol	dll_bypass
Operation	RW							
Default	0	0	0	0	0	0	0	0
	0x00							

DLL Control:

**dll\_ctrl\_ext\_en:** DLL, LED driver, feedback amplifier enable during manual control for delay locking operation (i.e. Modulator control is completely bypassed)  
0: disable  
1: enable

**dll\_rate\_cnt\_rst:** DLL measurement rate counter reset  
0: normal  
1: reset (auto cleared)

**dll\_ctrl\_ext:** Manual control of the delay line using DLL\_\*ctrl\_ext\* registers  
0: normal  
1: manual

**dll\_fb\_pol:** Inverts the polarity of signal at LEDFB pin  
0: normal  
1: inverted

Note 1: **dll\_fb\_pol** must be set with respect to **LED\_driver.led\_inv\_en** value and the external LED/LD circuit feedback point connected to the LEDFB input (external LED/LD circuit can be inverting or non-inverting depending on the application).

**dll\_bypass:** Bypass control of DLL for system delay compensation  
0: normal  
1: bypass

Note 2: When DLL is operated manually, application SW must set **dll\_ctrl\_ext\_en** = 0 while keeping **dll\_ctrl\_ext** = 1 to freeze the locked value before starting frame acquisition.

### 8.7.21. I<sup>2</sup>C\_

I <sup>2</sup> C_address				I <sup>2</sup> C register, SEG4 *: Address				0xCA
Bit No.	7	6	5	4	3	2	1	0
Bit name	reserved	i2c_dev_adr(A6..A2)					reserved i2c_dev_adr(A1..A0)	
Operation	RW							
Default	0	0	1	0	0	0	0	0
	0x20							

**i2c\_dev\_adr(A6..A2):** I<sup>2</sup>C device address A6 ... A2 of 7-bit I<sup>2</sup>C device address.

**i2c\_dev\_adr(A1..A0):** I<sup>2</sup>C device address A1, A0 of 7-bit I<sup>2</sup>C device address.  
Programmable only during reset via strap pins using external pull-up resistors.

I <sup>2</sup> C_control			I <sup>2</sup> C register, SEG4 *: Control					0xCB	
Bit No.	7	6	5	4	3	2	1	0	
Bit name	reserved						i2c_spike_filter_en	i2c_clock_stretch_en	
Operation	RW								
Default	0	0	0	0	0	0	1	1	
	0x03								

i2c\_spike\_filter\_en: I<sup>2</sup>C pins input spike filter  
0: disabled (> 1MHz)  
1: enabled (≤ 1MHz, FM+)

i2c\_clock\_stretch\_en: I<sup>2</sup>C clock stretching  
0: disabled  
1: enabled

Note 1: When i2c\_spike\_filter\_en = 0, SDA and SCL pins can be used up to 10MHz as inputs (driven rail-to-rail by a real CMOS driver, no pull-up). They can be used up to 2MHz as outputs.

### 8.7.22. TCMI\_polarity

TCMI_polarity			TCMI register					0xCC
Bit No.	7	6	5	4	3	2	1	0
Bit name	tcmi_data_sat_en	tcmi_xsync_sat_sel	reserved	tcmi_data_pol	tcmi_xsync_pol	tcmi_vsync_pol	tcmi_hsync_pol	tcmi_edge_sel
Operation	RW							
Default	0	1	0	0	0	0	0	1
	0x41							

tcmi\_data\_sat\_en: Force DATA[11:0] = 0xFFFF (unsigned) / 0x7FF (signed) during data-out operation when corresponding pixel is saturated  
0: disabled  
1: enabled

tcmi\_xsync\_sat\_sel: Select XSYNC / SAT output pin function (SAT function is always active high)  
0: XSYNC  
1: SAT

tcmi\_data\_pol: DATA[11:0] unsigned/signed control (for signed output, MSB bit is inverted)  
0: unsigned (0 ... 4'095)  
1: signed (-2'048 ... 2'047)

tcmi\_xsync\_pol: XSYNC polarity  
0: XSYNC active low  
1: XSYNC active high

Note: tcmi\_xsync\_pol is only effective when tcmi\_xsync\_sat\_sel = 0

tcmi\_vsync\_pol: VSYNC polarity  
0: VSYNC active low  
1: VSYNC active high

tcmi\_hsync\_pol: HSYNC polarity  
0: HSYNC active low  
1: HSYNC active high

tcmi\_edge\_sel: DCLK edge select to align all other TCMI outputs  
0: falling edge  
1: rising edge

### 8.7.23. Temp\_

<b>Temp_tl_cal1</b>		<b>Temperature sensor top-left calibration point 1</b>	<b>0xE8</b>
Operation	RW		
Default	0xFF		

<b>Temp_tl_cal2</b>		<b>Temperature sensor top-left calibration point 2</b>	<b>0xE9</b>
Operation	RW		
Default	0xFF		

<b>Temp_tr_cal1</b>		<b>Temperature sensor top-right calibration point 1</b>	<b>0xEA</b>
Operation	RW		
Default	0xFF		

<b>Temp_tr_cal2</b>		<b>Temperature sensor top-right calibration point 2</b>	<b>0xEB</b>
Operation	RW		
Default	0xFF		

<b>Temp_bl_cal1</b>		<b>Temperature sensor bottom-left calibration point 1</b>	<b>0xEC</b>
Operation	RW		
Default	0xFF		

<b>Temp_bl_cal2</b>		<b>Temperature sensor bottom-left calibration point 2</b>	<b>0xED</b>
Operation	RW		
Default	0xFF		

<b>Temp_br_cal1</b>		<b>Temperature sensor bottom-right calibration point 1</b>	<b>0xEE</b>
Operation	RW		
Default	0xFF		

<b>Temp_br_cal2</b>		<b>Temperature sensor bottom-right calibration point 2</b>	<b>0xEF</b>
Operation	RW		
Default	0xFF		

### 8.7.24. User\_

<b>User_1</b>		<b>User register 1 for user data</b>	<b>0xF0</b>
Operation	RW		
Default	0x00		

<b>User_2</b>		<b>User register 2 for user data</b>	<b>0xF1</b>
Operation	RW		
Default	0x00		

#### 8.7.25. ENGINEERING\_ID

<b>ENGINEERING_ID</b>	<b>Chip ID register SEG6 *: Engineering ID for MPWs</b>	<b>0xF5</b>
Operation	R	
Default	according engineering ID	

#### 8.7.26. WAFER\_ID\_

<b>WAFER_ID_MSB</b>	<b>Chip ID register SEG6 *: MSB of wafer ID</b>	<b>0xF6</b>
Operation	R	
Default	according wafer ID	

<b>WAFER_ID_LSB</b>	<b>Chip ID register SEG6 *: LSB of wafer ID</b>	<b>0xF7</b>
Operation	R	
Default	according wafer ID	

#### 8.7.27. CHIP\_ID\_

<b>CHIP_ID_MSB</b>	<b>Chip ID register SEG6 *: MSB of chip ID on wafer</b>	<b>0xF8</b>
Operation	R	
Default	according chip ID	

<b>CHIP_ID_LSB</b>	<b>Chip ID register SEG6 *: LSB of chip ID on wafer</b>	<b>0xF9</b>
Operation	R	
Default	according chip ID	

#### 8.7.28. PART\_

<b>PART_TYPE</b>	<b>Chip ID register SEG6 *: Part type</b>	<b>0xFA</b>
Operation	R	
Default	according part ID	

<b>PART_VERSION</b>	<b>Chip ID register SEG6 *: Part version</b>	<b>0xFB</b>
Operation	R	
Default	according part version	

## 9. Addendum

### 9.1. Terms, Definitions and Abbreviations

Abbreviation	Term, Definition	Explanation
ABS	Automatic Backlight Suppression	
ADC	Analog Digital Converter	
AMR	Ratio of ambient-light / modulated light	
Big-endian		The MSB of a multi-byte register is stored in the memory location with the lowest address first. The next byte value in significance is stored at the following memory location and so on
CGU	Clock Generation Unit	
CSP	Chip Scale Package	
DCS	Differential Correlation Sample	
DLL	Delay Locked Loop	A digital circuit similar to PLL, with the main difference being the absence of an internal VCO, replaced by a delay line
HDR	High Dynamic Range	
IC	Integrated Circuit	
JTAG	Joint Test Action Group	
LED/LD	Light Emitting Diode / Laser Diode	
LSB	Least Significant Bit	
LSFR	Linear Feedback Shift Register	
MGA	Modulation Gate A	
MGB	Modulation Gate B	
MGX	Modulation Gate A, B	
mga	MGA control signal	
mgb	MGB control signal	
mgx	MGX control signal	
MSB	Most Significant Bit	
OSC	Oscillator	
PLL	Phase Locked Loop	
PN	Pseudo-random Noise	
ROI	Region of Interest	
QVGA	Quarter VGA	320x240 pixel resolution
SGA	Storage Gate A	
SGB	Storage Gate B	
SGX	Storage Gate A, B	
TCMI	TOF Camera Module Interface	
TOF	Time of Flight	
VCO	Voltage Controlled OSC	
VGA	Video Graphics Array	640x480 pixel resolution
XTAL	Crystal	

Table 43: Definitions and Abbreviations

### 9.2. Related documents

- NXP I2C-bus specification: I2C Bus Specification and User Manual, NPX corp., Rev.5 - 9 October 2012
- Application note AN10 epc600/epc610 temperature and BG light compensation, ESPROS Photonics corp., 2014
- Handbook – epc 600 Time-of-flight range finder chip, ESPROS Photonics corp., 2014

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